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## Remote Data Acquisition and Error Analysis of the Scattering Parameters of Quartz Crystal Devices

Sallie Layton Douglas  
*University of Central Florida*

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REMOTE DATA ACQUISITION  
AND ERROR ANALYSIS OF  
THE SCATTERING PARAMETERS  
OF QUARTZ  
CRYSTAL DEVICES

BY

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THESIS

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## ABSTRACT

A two-port device can be described by the incident and reflected voltages at each port. The parameters used in this description are known as scattering parameters. Accurate measurement of the values are thus important in device evaluation and network design.

Limitations arise with the measurement capability of the equipment. In order to reduce these limitations, the data acquisition is controlled remotely by a computer program. The program also offers an error correction analysis of the measurement results.

The measurement setup and basic approach are discussed as well as the techniques of normalization and calibration of each scattering parameter. The computer program offers three methods of data acquisition which are presented in detail. Results of device testing and error analysis are presented.



#### ACKNOWLEDGMENTS

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## INTRODUCTION

The importance of quartz crystal resonators in electronics results from their extremely high quality factor, relatively small size, and excellent temperature stability [1]. Surface acoustic wave filters offer the advantages of inherent linear phase, superior shape factors, excellent rejection, small size, and high repeatability [2].

The use of quartz crystal units in frequency control, filter and timing applications require accurate determination of the value of their equivalent electrical parameters. For the measurement of these parameters, the single-port reflection method characterizes the crystal device as a two-terminal unit and provides very accurate determination of resonance frequency and resistance as well as motional-arm parameters [3].

While the measurement of the scattering parameters, with their normalization and calibration, follows the standard reference method of measurement of the parameters of crystal devices, the actual data acquisition is performed remotely by computer. A program was written that offers the user much greater freedom in specification of acquisition characteristics than utilization of the network analyzer and S-Parameter test set only. With this freedom, the user may

define the desired number of data acquisition points or the desired delta frequency, may make an error analysis, and may obtain permanent records of the device measurement in printed and plot form and by transfer of the data to hard disc for future manipulation.

The objective of the project was to write a computer program for testing of quartz crystal devices. As stated, the program provides a remote acquisition of all scattering parameters and a means of error analysis.



## PROPOSED STRATEGY

### Data Acquisition

The operation of the HP 3577A Network Analyzer and the HP 35677A S-Parameter Test Set from the front panel limits the user in several ways. First of all, the maximum number of sample frequencies available across the screen is 401. This is due to the sweep resolution of the network analyzer. The user may select 51, 101, 201, or 401 points per sweep, compromising fewer trace points for a shorter sweep time [4]. The second limiting factor of operation from the front panel is the exact measurement values can only be found by moving the marker across the trace and noting the magnitude, phase, and frequency values printed at the top of the screen. This procedure becomes tedious if more than a few values are needed. Thirdly, the only permanent record of device measurement available is by use of the HP 7475A Plotter. By making a plot, the user has a record of the value of the single magnitude and single phase for the marker frequency. All other values must be approximated by noting the scaling factors. Fourthly, the method of error analysis is obtained by taking two sets of measurements and noting the difference in the printed marker values for one particular frequency.



A method of data acquisition was needed that would allow the user the option of choosing the desired sweep resolution; that is, of choosing from any number of data points. This method should also offer, in a concise manner, exact values of magnitude and phase for each of the measured frequencies with the option of a permanent record. Also a method of error analysis should be incorporated in the device measurements.

The method of data acquisition chosen was a computer program which would remotely control the Network Analyzer to take measurements from the device under test using user input specifications.

Since the network analyzer has a limitation of points per sweep, the computer program should be able to measure any number of points per sweep. The program should be able to perform the necessary mathematical calculations to normalize or calibrate each of the scattering parameters.

The equipment to be used is the HP 3577A Automatic Network Analyzer, the HP 35677A S-Parameter Test Set, the HP 9845B Computer, the HP 9133 Disc Drive, and the HP 7475A plotter. These are interconnected via the HP Interface Bus.

Data messages are sent from one machine to another on the bus in an 8-bit parallel, byte serial manner using standard ASCII codes. Only one machine at a time can place information on the data lines of the bus and that machine is

known as the active talker. Another machine, known as the active listener, senses the information on these data lines and acts on that information. The computer program must instruct the network analyzer to be a listener so that it can be set up for measurements and told when to take readings. It then must be made a talker so that it can put the results of that reading on the data bus to be sent back to the computer for calculations. Plotting will be done by defining either the plotter or the computer screen as the plotting device and then sending the data and instructions to the plotting device directly from the computer. Complete specifications of the destination for messages and data transfer will be accomplished by machine addresses [5].

The computer program should be fairly general in order to control the network analyzer to test a wide range of devices. Interest will focus, however, on quartz crystal resonators and acoustic filters.

### Sensitivity Analysis

Inherent in the HP Network Analyzer are accuracy and frequency response errors which must be compensated. In the S-Parameter test set are frequency response, port match, and test port reciprocity errors which also must be compensated. Specifications are found in Appendix A [4].



The computer program should offer the option of making two measurement sweeps for each scattering parameter. The errors will be found by subtracting the polar values of the second sweep from the first. Perfectly accurate results would then yield errors of 0 dB and 0 degrees. Deviation falling outside the range of the network analyzer specifications should then be treated as extrinsic errors. Possible causes for these extrinsic errors will be discussed later.



## METHODS, PROCEDURES, AND EXPERIMENTS

### Basic System Setup

The 3 1/2 inch disc labelled "Scat" is inserted into the disc drive. The command MASS STORAGE IS ":A6" is executed. This specifies the mass storage operations be directed to the disc drive. The user then executes the command GET "SCAT:A6,2" to load the program into the computer [6].

The program is executed by the RUN or CONTINUE key. The measurement setup begins with the OPTION BASE 1 command which specifies that the lower bound for array dimension be one rather than zero. This assures that the array dimensions will be matched to the measurement FOR/NEXT loops. The screen prompts the user to press the SPECIAL FUNCTION hardkey and then the TALK ONLY OFF softkey on the network analyzer. This enables the network analyzer to be a listener on the bus [6].

The next command is REMOTE 711 which switches device number eleven (network analyzer) on port seven (HP IB) from local to remote control [6]. Sixteen arrays are initially dimensioned to hold 1024 data points. A maximum of eleven arrays are utilized with the scattering parameters  $S_{21}$ ,  $S_{12}$ , and  $S_{22}$  depending upon error sweeps and plots. The scattering parameter  $S_{11}$  utilizes all sixteen arrays. The

INSTRUMENT PRESET command is executed next. Default conditions utilized and unchanged by the program's measurement setup are included in Table 1.

TABLE 1

NETWORK ANALYZER INSTRUMENT CONDITIONS UTILIZED  
IN THE DATA ACQUISITION AND ERROR ANALYSIS PROGRAM

FUNCTION	CONDITION	SET BY
1. Display Function	Trace 1: log magnitude (linear magnitude, V, for $S_{11}$ )	Default
2. Amplitude	Trace 2: Phase, degrees	Program
3. Start Frequency	-49 dBm to +15 dBm	User
4. Stop Frequency	0 Hz minimum	User
5. Sweep Type	200 MHz maximum	User
	Linear Frequency Sweep for "Dump the Screen" Data Acquisition,	Default
	Continuous Wave for "Define N" and "Define Df" Data Acquisition	Program
6. Sweep Time	1 second for Linear Frequency Sweep, 0.05 ms Sample Time for Continuous Wave Sweep	Default
7. Sweep Mode	Single Sweep for "Dump the Screen" Data Acquisition,	Program
	Continuous Sweep for "Define N" and "Define Df" Data Acquisition	Default
8. Sweep Resolution	401 points/span for "Dump the Screen" Data Acquisition,	Default
	2-1024 points/span for "Define N" and "Define Df" Data Acquisition	User
9. Trigger Mode	Free Run	Default
10. Resolution Bandwidth	1 kHz	Default
11. Averaging	Off	Default
12. Attenuation (input)	20 dB	Default
13. Impedance (input)	50 Ohms	Default

The user is prompted to enter the start frequency and stop frequency in MHz. The frequency range for the network analyzer is from 5 Hz to 200 MHz. However the frequency range for the S-Parameter test set is from 100 kHz to 200 MHz. Regardless, the program is designed to accept a start frequency of 0 Hz in order to prepare for  $S_{21}$  data acquisition from a surface acoustic wave device with data storage for future fast Fourier transform. This is



accomplished by loading the first value of the data acquisition arrays with -100 dB and 0 degrees and the first value of the normalizing arrays with 0 dB and 0 degrees. The Array Start Variable is set at 2 so that subsequent data acquisition will begin at the incremented frequency and storage will begin at the second value of the arrays. If the start frequency had been other than 0 Hz the Array Start Variable will be set at 1 so that subsequent data acquisition will begin at the start frequency. Storage will begin in the first value of the arrays.

The user is prompted to enter a value for the signal level of the source output. Trace 2 is defined as phase in degrees. By default, Trace 1 is log magnitude.

The program then goes to the Data Acquisition Method Subroutine where the user is prompted to choose one of three methods of data acquisition. These methods are discussed in detail later in this chapter. The program returns to the Measurement Setup Section and the sixteen arrays are redimensioned to hold N number of data points, where N was defined in the Data Acquisition Method Subroutine.

The user is asked if dual sweeps for system error checks are desired. If so, the Error Run Flag is set. At this point the measurement setup is complete and the program progresses to the first scattering parameter.

### Basic Approach and Block Diagram

The flow of the program after the Measurement Setup Section follows similar lines for each of the scattering parameters.

The user is asked if measurement of a particular scattering parameter is desired. If it is not, the program skips to the next parameter to ask the same question. When measurement is desired, a flag is set. This flag indicates throughout the generic normalization, printing, and plotting sections which scattering parameters the program is measuring. The program then goes to the Calibration Subroutine. If the scattering parameter is  $S_{21}$ ,  $S_{12}$ , or  $S_{22}$ , the program goes to the Normalization Section of the subroutine. If the scattering parameter is  $S_{11}$  the program goes to the One Port Full Calibration Section of the subroutine. These normalizations and calibrations are discussed in detail later in this chapter. Measurements are taken using the calibration devices and stored in magnitude and phase arrays. The program returns to its scattering parameter section but then immediately goes to the Data Acquisition Subroutine. Measurements are taken from the device under test and stored in magnitude and phase arrays. The values are then normalized/calibrated. The program then goes to the 360 Degree Phase Shift Subroutine to compensate



for phase shifts. The program returns to the Data Acquisition Subroutine and the Error Run Flag is checked.

If the flag is set, new measurements are taken from the device and are then normalized/calibrated using the same normalization/calibration measurements used previously. Systematic errors will thus be detected on test device measurements and not normalization/calibration device measurements. The phase array is compensated for any 360 degree shifts as before.

The values of the magnitude array and phase array are printed on the HP 9845B screen in decibels and degrees, respectively. If the Error Run Flag has been set the printed values are from the second sweep. The user is offered the option of having a hard print made of these values. If the Delta Frequency Method of Data Acquisition has been selected, the program goes to the Save Results Subroutine where the results, if the user desires, are saved on the disc drive for possible future Fast Fourier Transform.

The user is next asked if a normalized plot is desired. If so, the program goes to the Max\_min Subroutine to find the maximum and minimum values for the vertical axis of the plot thereby "normalizing" it. The program then goes to the Plot Subroutine where plots of magnitude and phase can be made on the HP 9845B screen, the HP 7475A Plotter, or both.

The vertical axis gives the magnitude in decibels or the phase in degrees. The horizontal axis is the frequency span divided into ten sections with the center frequency labeled as "0.0" in the middle of the axis. The actual center of the frequency span is printed below the axis.

If dual sweeps for errors have been made, the second sweep is subtracted from the first. Data is in decibels and degrees. The magnitude and phase errors are printed on the HP 9845B screen and, as before, the user is offered the option of a hard print, saving the results (if the Delta Frequency Method of Data Acquisition has been selected), and making plots.

The program returns the particular scattering parameter section and the user is asked if the next scattering parameter measurements are desired. Progression is made through (or around)  $S_{21}$ ,  $S_{12}$ ,  $S_{11}$ , and finally,  $S_{22}$  before ending. The basic block diagram of the program is given in Figure 1.



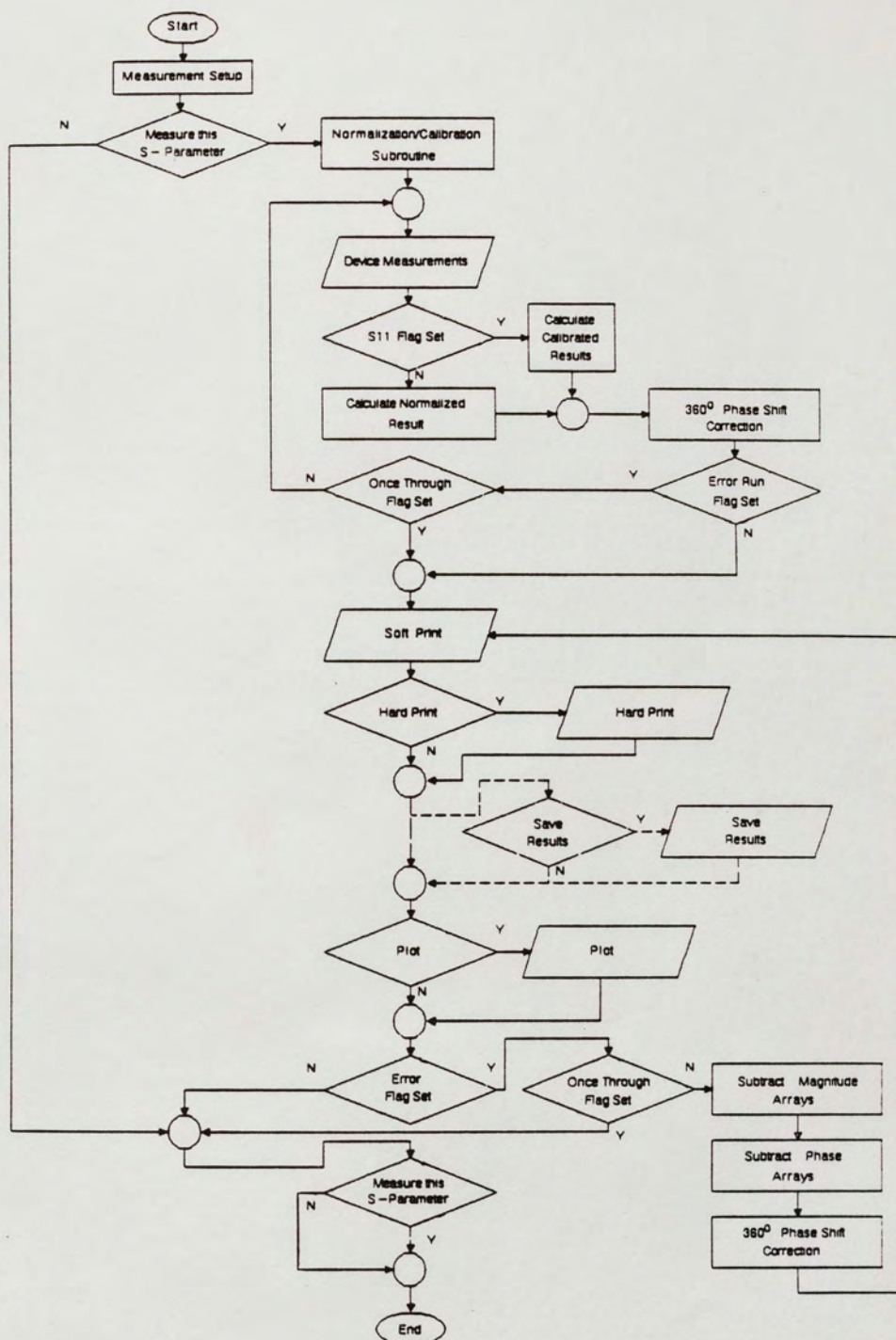


Figure 1. Basic Block Diagram of the Data Acquisition and Error Analysis Program

### Measurements and Calibration

The measurement of the input reflection scattering parameter,  $S_{11}$ , is the most complex of the four parameters due to the mathematics of the calibration. In the  $S_{11}$  section of the program the magnitude function is changed from logarithmic to linear. The program then goes to the One Port Full Calibration Subroutine and the user is asked to insert an "Open" in the test fixture. The magnitude and phase measurements are taken, changed from polar to rectangular format, and stored in two arrays,  $r_{or}$  and  $r_{oi}$ . The user is then asked to replace the "Open" with a "Short." Again, measurements are made, changed to rectangular format and stored in arrays  $r_{sr}$  and  $r_{si}$ . The user replaces the "Short" with the reference load (fifty Ohms for the HP 35677A S-Parameter Test Set fixture) and, as before, the results are stored, this time in arrays  $r_{tr}$  and  $r_{ti}$ . The program then performs the first calculations necessary for calibration. Additional subroutines are called to change between polar and rectangular formats depending upon the actual mathematical operations. Polar format is utilized with multiplication and division so that the data can be added or subtracted in logarithmic form. The rectangular format is utilized with straightforward addition and subtraction of data. The correction factor for transmission,  $T_f$ , and the factor for source match,  $S_f$ , are



calculated. The correction factor for directivity,  $D$ , is given by  $\Gamma_t$ . Directivity is the ratio of the reflected signal to the incident signal with the load in place. The user is asked to replace the "Load" with the device under test. The program then returns to the  $S_{11}$  section and is immediately sent to the Data Acquisition Subroutine. Device measurements,  $M_{meas}$ , are taken and the program goes to the end of the One Port Full Calibration Subroutine where they are first changed to rectangular format. Calculations continue, using the previously described Polar/Rectangular Subroutines, and the actual calibrated value for  $S_{11}$  is found using the equation [4]

$$S_{11} = \frac{M_{meas} - D}{S_f \cdot M_{meas} + T_f} .$$

An additional subroutine is called for plotting purposes, to correct for any 360 degree phase shifts. The final magnitude values are in decibels while phase is in degrees. A detailed derivation of the above equation can be found in Appendix B.

The remaining scattering parameters are not calibrated by the computer program but merely normalized. This fact needs to be taken into consideration by the user if true calibrated results are desired.

The forward gain and phase scattering parameter,  $S_{21}$ , is normalized by the use of a "Thru." The program leaves the  $S_{21}$  section and goes to the Normalizing Subroutine. The user is asked to insert a "Thru" into the test fixture and measurements are taken in polar format. The magnitude and phase values are stored in two arrays,  $D_n$  and  $E_n$ , respectively. The user is then asked to replace the "Thru" with the device under test. The program returns to the  $S_{21}$  section and immediately goes to the Data Acquisition Subroutine. Device measurements are made and the values are stored in arrays D and E. The polar format normalizing arrays are subtracted (linear division) from these arrays so that the final results are normalized against any variation from a transmission coefficient of unity. The phase is checked for a 360 degree shift before the results are printed on the HP 9845B screen.

The reverse loss scattering parameter,  $S_{12}$ , exactly follows the above procedure utilizing a "Thru."

The output reflection coefficient,  $S_{22}$ , varies from the above procedure only in that an "Open" is utilized to normalize against any variations from a reflection coefficient of unity.



### Data Acquisition Methods

Near the completion of the Measurement Setup Section the program goes to the Data Acquisition Method Subroutine. The user is told the results of the measurements can be saved on the disc drive only by defining the delta frequency. The user is then prompted to choose one of the three methods of data acquisition. These methods are Dump the Screen, Define the Delta Frequency, and Define the Number of Data Points. The method of choice is then utilized in all subsequent normalizations/calibrations and measurements for each of the scattering parameters.

If the user chooses to dump the screen the "Dump the Screen" flag is set and the data point variable, N, which is used for array redimensioning, is given the value of 401. The program then returns to the end of the Measurement Setup Section. This method of data acquisition is limited by the fact that the maximum number of points available for measurement across the sweep is 401 due to the sweep resolution within the internal structure of the HP 3577A. For data acquisition, the default Sweep Type of Linear Frequency Sweep is utilized but the Sweep Mode is changed from the default selection of Continuous to Single Sweep. Thus a single sweep is made over the default Sweep Time of 1.0 second [4].

The next command is Take Measurement. The HP 3577A settles (by default, this settling time is 22ms [4]) and takes the measurement before processing the Dump Trace command thereby guaranteeing that the measurement will be completed before data transfer begins. Dump Trace 1 dumps the magnitude trace in logarithmic form for the scattering parameters  $S_{21}$ ,  $S_{12}$ , and  $S_{22}$  and linear form for the scattering parameter  $S_{11}$ . Dump Trace 2 dumps the phase trace in degrees for all the scattering parameters. The data is then loaded into two separate arrays using formatting commands.

If the "Define the Delta Frequency" method of data acquisition is chosen, that particular flag is set and the user is prompted to define the frequency bandwidth of interest. This bandwidth must be within the previously defined start and stop frequencies and if it is not, the user is asked to redefine the bandwidth. Next the user is prompted to input the desired delta frequency and this value must be less than the defined bandwidth. Again, if it is not the user is asked to redefine the delta frequency. An intermediate value for the data point variable,  $N$ , is calculated and checked as to whether it is less than the maximum allowable value of 1024. If it is, a new value for  $N$  is calculated which satisfies the requirement for a  $2^n$  point file necessary for fast Fourier transform. This



value for N will be greater than the intermediate value and the process will yield a somewhat smaller delta frequency. The user is given the new values for the number of data points and the delta frequency. The program then returns to the end of the Measurement Setup Section. This method of data acquisition uses the default Sweep Mode of Continuous Sweep but the Sweep Type is changed from the default selection of Linear Frequency Sweep to Continuous Wave. This puts the HP 3577A in a single frequency measurement state. The display shows a single line from the bottom of the graticule to the height of the signal level at the specified frequency. The default Sample Time of 0.05 seconds is utilized [4]. Before measurement, the value of the minimum frequency is first stored for later plotting purposes. Measurement is taken via a FOR/NEXT loop and begins filling the arrays in either the first or second space depending upon the value of the Array Start Variable which depends upon the start frequency. The reason for this was previously explained in the Basic System Setup Section of this thesis. In the loop, the frequency of measurement is determined by an equation that will increment the frequency only after the first pass through the loop. The source frequency for the marker is set at this particular frequency and the number of digits are set to be accurate to one hertz. The Take Measurement and Dump Marker commands

are executed and, as before, measurement is completed prior to data transfer. Dump Marker 1 dumps the value of the magnitude marker of Trace 1 in logarithmic form for the scattering parameters  $S_{21}$ ,  $S_{12}$ , and  $S_{22}$ , and in linear form for the scattering parameter  $S_{11}$ . Dump Marker 2 dumps the value of the phase marker of Trace 2 in degrees for all the scattering parameters. These values are entered into two separate arrays and the program passes to the beginning of the loop. The frequency is incremented by the amount of the delta frequency to set a new source frequency for the marker and the measurements begin again. The number of passes through the loop is equal to the calculated number of data points,  $N$ , or to  $(N-1)$  depending on the Array Start Variable as previously described.

If the user chooses the data acquisition method by which the number of data points,  $N$ , is defined, that particular flag is set and the user is prompted to enter a value between, but not including, 1 and 1025. This value is given to the data point variable,  $N$ . The delta frequency is calculated and the program returns to the Measurement Setup Section. This method of data acquisition is identical to the previously described "Define the Delta Frequency" method except there is no option to save the results of measurement for future fast Fourier transform and arrays begin filling



with data from the minimum frequency. The frequency is incremented at the end of the FOR/NEXT loop by simply adding the value for the delta frequency.

### Device Testing

The quartz crystal devices tested were an intermediate frequency resonator, a high frequency resonator, and a surface acoustic wave filter. The resonators were obtained from the Electronics Industry Association of Olathe, Kansas, and are referred to as device J69 for the IF resonator and device F83 for the HF resonator. The SAW filter was built at the University of Central Florida, and is referred to as the SAW filter.

All measurements for device J69 were made with a start frequency of 3.5782215 MHz and stop frequency of 3.5792215 MHz, thus giving a frequency span of 1 kHz with the center frequency at resonance, 3.5787215 MHz. All measurements for device F83 were made with a start frequency of 40.67869 MHz and a stop frequency of 40.68869 MHz, thus giving a frequency span of 10 kHz with the center frequency at resonance, 40.683690 MHz. The drive level for each of the three devices was 0 dBm.

The scattering parameter  $S_{21}$  was measured from device F83 three times using each of the data acquisition methods for comparison purposes. Figures 2 and 3 show the magnitude

and phase plots made using the "Dump the Screen" method. Here, 401 data points were measured over the bandwidth of 10 kHz and the delta frequency between points was 25 Hz. Figures 4 and 5 show the magnitude and phase plots made using the "Define the Number of Data Points" method. This number,  $N$ , was chosen to be 401 in order to compare the plots more closely with the "Dump the Screen" method. As before, the delta frequency between points was 25 Hz. Figures 6 and 7 show the magnitude and phase plots made using the "Define the Delta Frequency" method. Since the number of data points will be in the form  $N=2^n$ , a delta frequency was chosen which would prompt the program to calculate a value of  $N$  closest to 401 for comparison purposes. This value was  $N=512$  with a delta frequency of 19.53125 Hz. Error runs were also made with the above three data acquisition methods. Plots of the magnitude and phase errors are to follow. The device F83 was then normalized for  $S_{21}$  from the front panel of the network analyzer without the use of the computer program. The number of data points is 401 and the delta frequency between these points is 25 Hz. The plot of magnitude and phase is shown in Figure 8. Good correlation between all methods is observed.



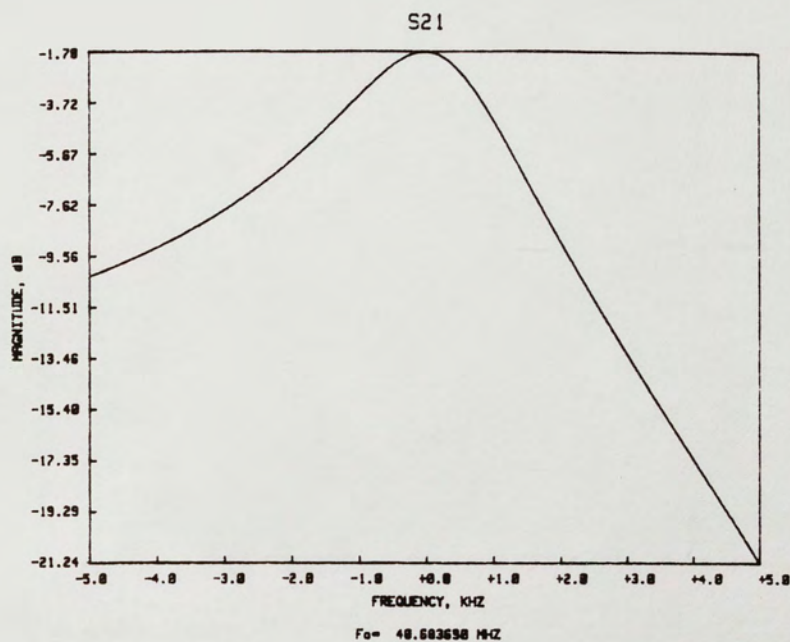


Figure 2. S<sub>21</sub> Magnitude Plot of Device F83 Using the "Dump the Screen" Data Acquisition Method

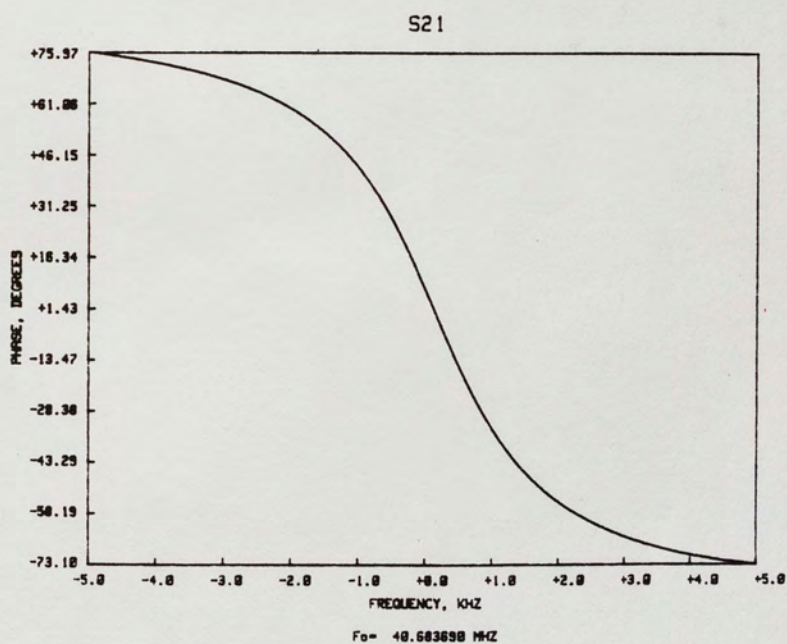


Figure 3. S<sub>21</sub> Phase Plot of Device F83 Using the "Dump the Screen" Data Acquisition Method

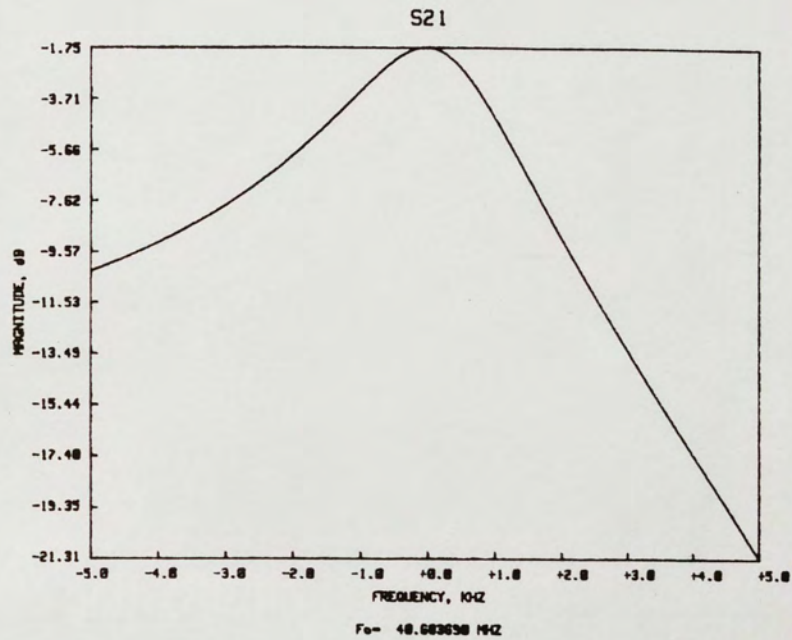


Figure 4. S<sub>21</sub> Magnitude Plot of Device F83 Using the "Define the Number of Data Points" Data Acquisition Method

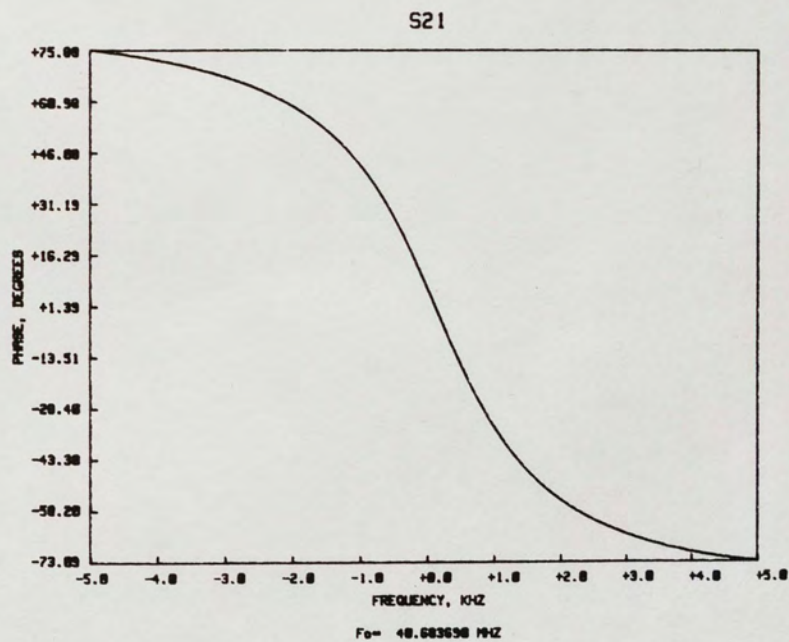


Figure 5. S<sub>21</sub> Phase Plot of Device F83 Using the "Define the Number of Data Points" Data Acquisition Method



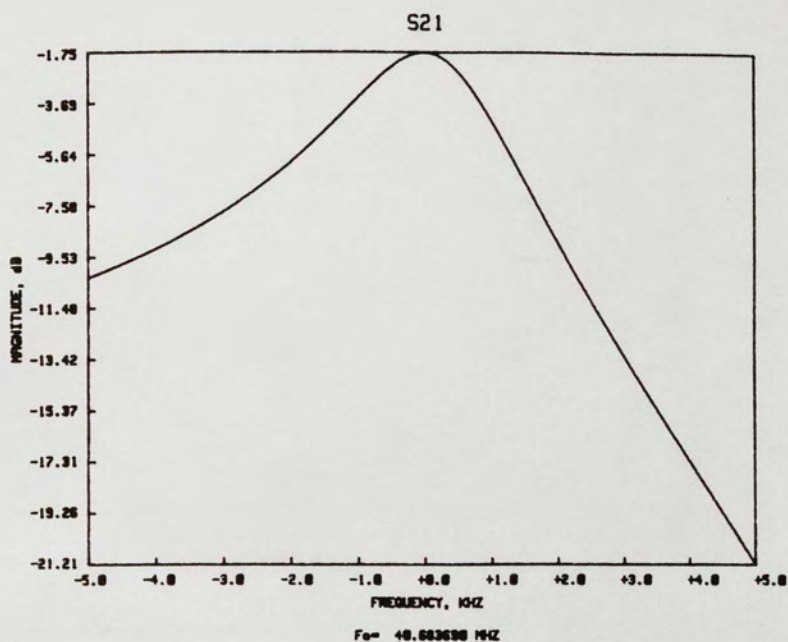


Figure 6. S<sub>21</sub> Magnitude Plot of Deice F83 Using the "Define the Delta Frequency" Data Acquisition Method

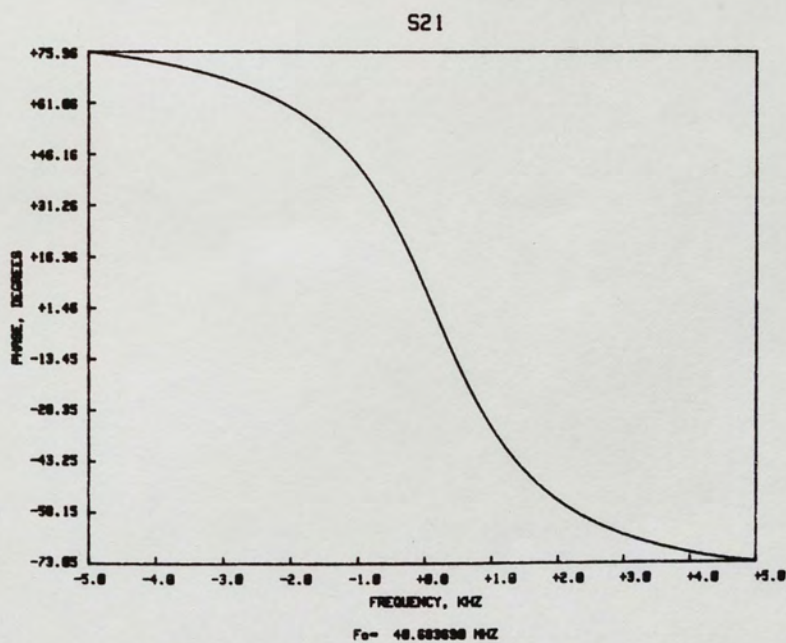


Figure 7. S<sub>21</sub> Phase Plot of Device F83 Using the "Define the Delta Frequency" Data Acquisition Method

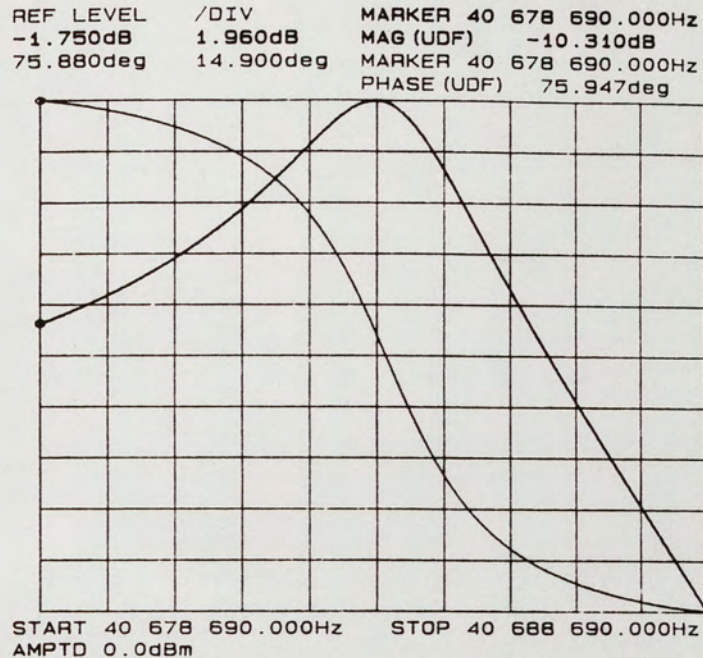


Figure 8.  $S_{21}$  Magnitude and Phase Plot of Device F83 Made Directly from the HP 3577A Network Analyzer

If the "Dump the Screen" method is used as a standard for comparison, then the percent difference in the plots can be calculated using the equation

$$\frac{(\text{Expected Value} - \text{Measured Value})}{\text{Expected Value}} \times 100\%$$

Adjusting for logarithmic form, the percent difference in magnitude at resonance is

$$\frac{\left(10^{\frac{-1.78}{20}} - 10^{\frac{-1.75}{20}}\right)}{10^{\frac{-1.78}{20}}} \times 100\% = -0.35\%$$



for both the "Define the Number of Data Points" and the "Define the Delta Frequency" methods. The percent difference in the amplitude range can be calculated between the "Dump the Screen" and "Define the Number of Data Points" methods by

$$\frac{\left(10^{\frac{-1.78}{20}} - 10^{\frac{-21.24}{20}}\right) - \left(10^{\frac{-1.75}{20}} - 10^{\frac{-21.31}{20}}\right)}{\left(10^{\frac{-1.78}{20}} - 10^{\frac{-21.24}{20}}\right)} \times 100\% = -0.48\%$$

where, as before, adjustment is made for logarithmic form.

By similar calculations, the percent difference in the amplitude range between the "Dump the Screen" and "Define the Delta Frequency" methods is -0.35%. The percent difference in the phase at resonance between the "Dump the Screen" and "Define the Number of Data Points" methods is found to be

$$\frac{(1.43 - 1.39)}{1.43} \times 100\% = 2.8\%$$

The percent difference in the phase at resonance between the "Dump the Screen" and "Define the Delta Frequency" methods is 2.1%. Between the "Dump the Screen" and "Define the Number of Data Points" methods, the percent difference in phase range is

$$\frac{((75.97 - (-73.1)) - (75.88 - (-73.09)))}{(75.97 - (-73.1))} \times 100\% = 0.067\%$$

similarly, the percent difference in phase range between the "Dump the Screen" and "Define the Delta Frequency" is 0.04%. These values of percent differences can be found in Table 2. The plot of magnitude and phase of  $S_{21}$  made from the front panel is seen to have similar characteristics as the six plots using the computer program's data acquisition.

The scattering parameter  $S_{12}$  was measured for devices F83 and J69, twice each, for the purpose of comparing two error runs. The "Define the Delta Frequency" method of data acquisition was chosen. The delta frequency for device F83 was 19.53125 Hz with  $N=512$  points. Figures 9 through 12 show the magnitude and phase plots of the first and second run. Figure 13 shows the normalized magnitude and phase plot made from the front panel of the network analyzer without the use of the computer program. The delta frequency is 25 Hz and  $N=401$  points as before. If a comparison of runs is made using the first run as the standard, the percent difference in magnitude at resonance is 0.12% and the percent difference in amplitude range is 0.15%. Calculations were similar to those used previously. The percent difference in phase at resonance is -4.2% and the percent difference in the phase range is 0.13%. These values are repeated in Table 2. The plot of magnitude and phase made from the front panel of the network analyzer is seen to have similar characteristics as the four plots using



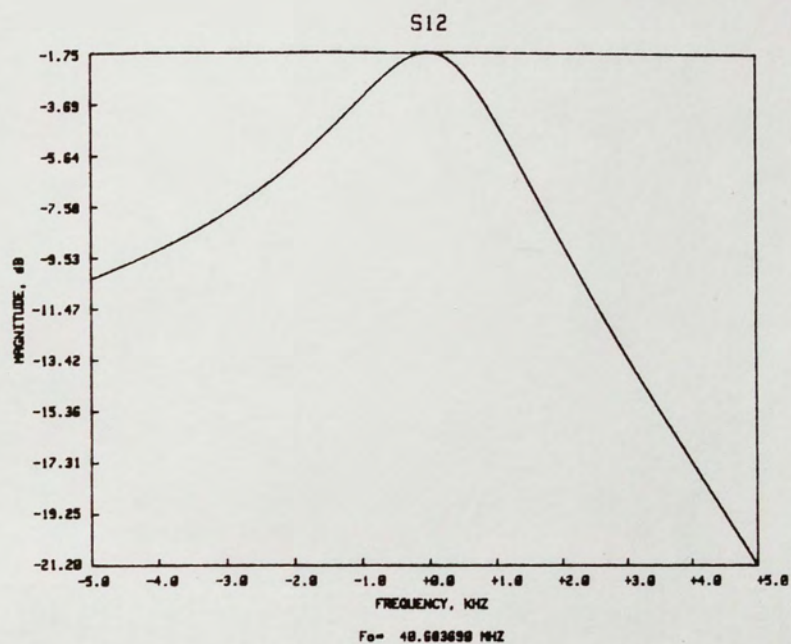


Figure 9.  $S_{12}$  Magnitude Plot of Device F83; First Run

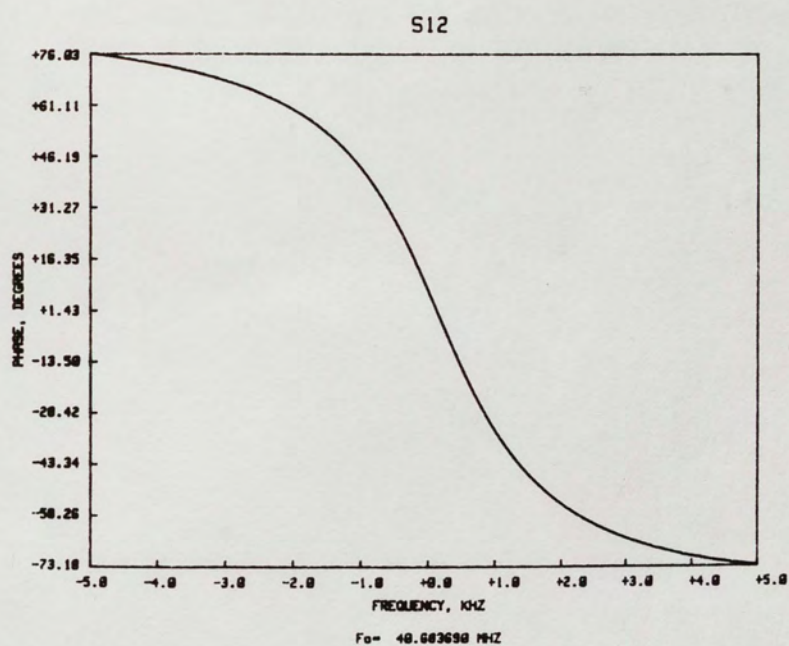


Figure 10.  $S_{12}$  Phase Plot of Device F83; First Run

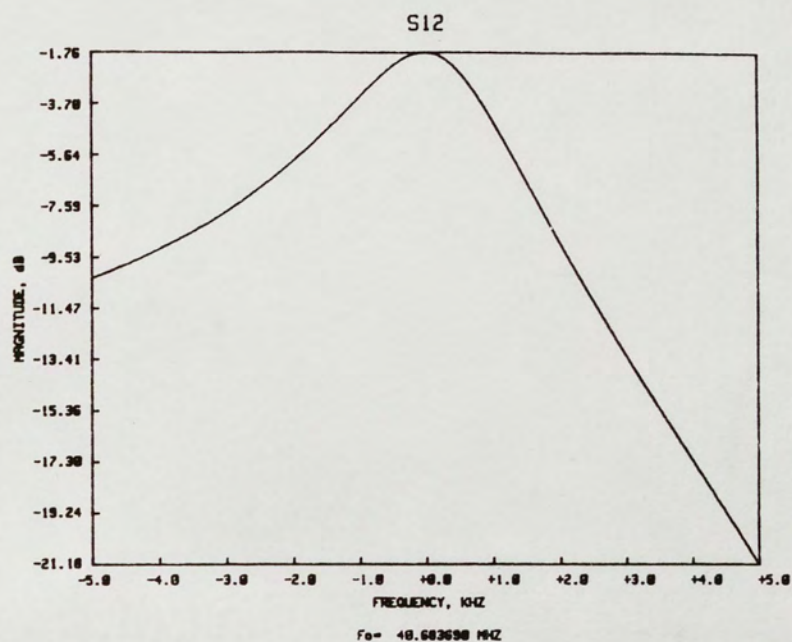


Figure 11.  $S_{12}$  Magnitude Plot of Device F83; Second Run

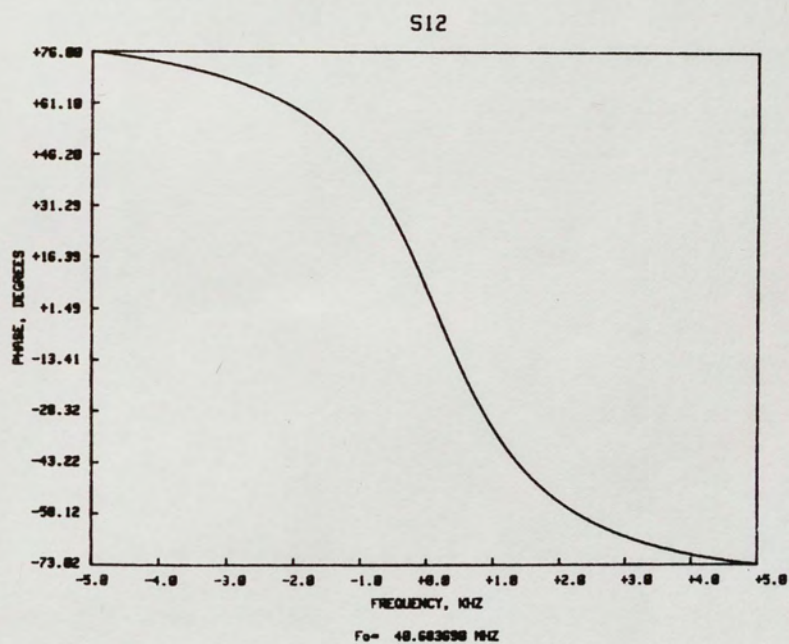


Figure 12.  $S_{12}$  Phase Plot of Device F83; Second Run



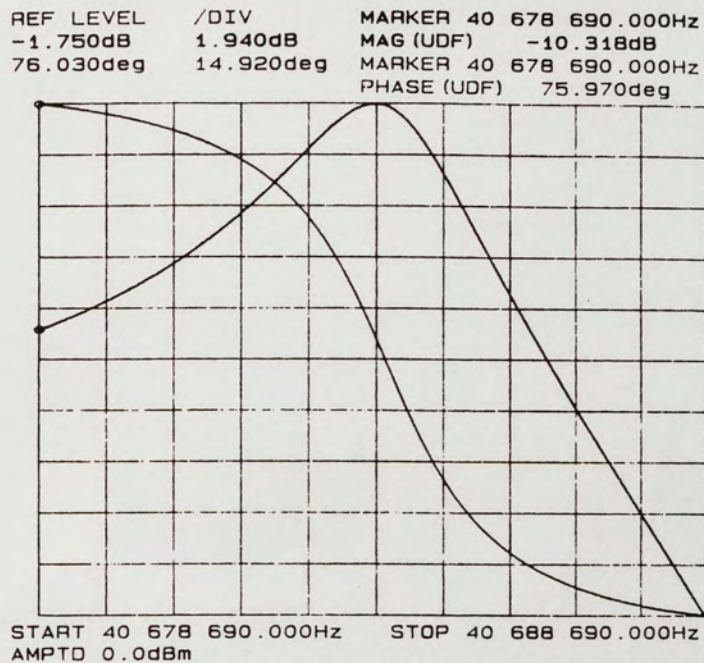


Figure 13.  $S_{12}$  Magnitude and Phase Plot of Device F83 Made Directly from the HP 3577A Network Analyzer

the computer program's data acquisition. Figures 14 through 17 show the magnitude and phase plots of the first and second run from device J69. The delta frequency was 1.953125 Hz with  $N=512$  points. Figure 18 shows the normalized magnitude and phase plot for the device made from the front panel of the network analyzer. The delta frequency is 2.5 Hz with  $N=401$  points. If a comparison of runs is made using the first run as the standard, the percent difference in magnitude at resonance is -0.12% and the percent difference in amplitude range is -0.12%.

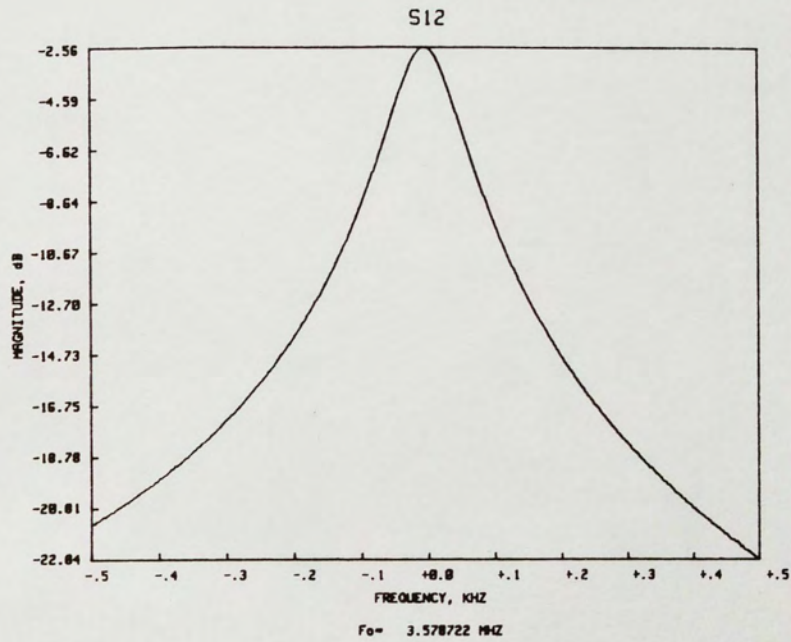


Figure 14. S<sub>12</sub> Magnitude Plot of Device J69; First Run

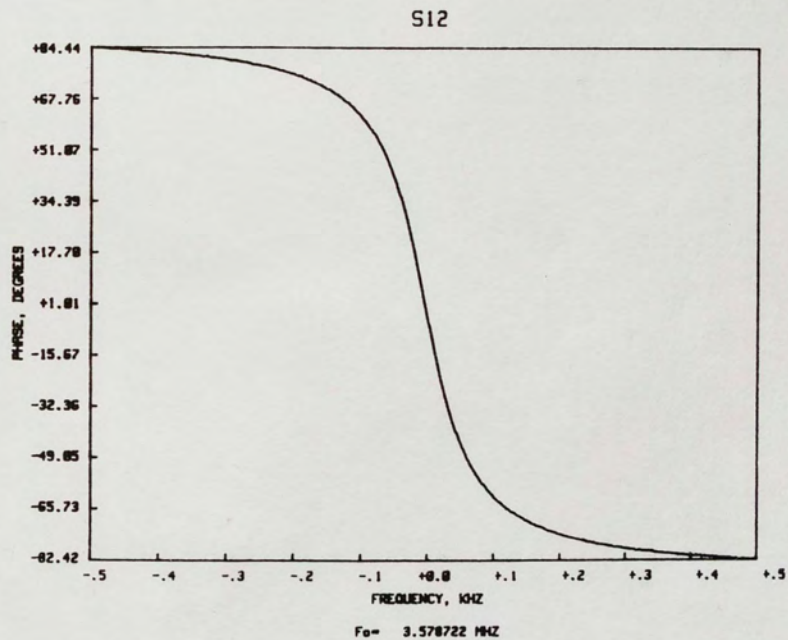


Figure 15. S<sub>12</sub> Phase Plot of Device J69; First Run



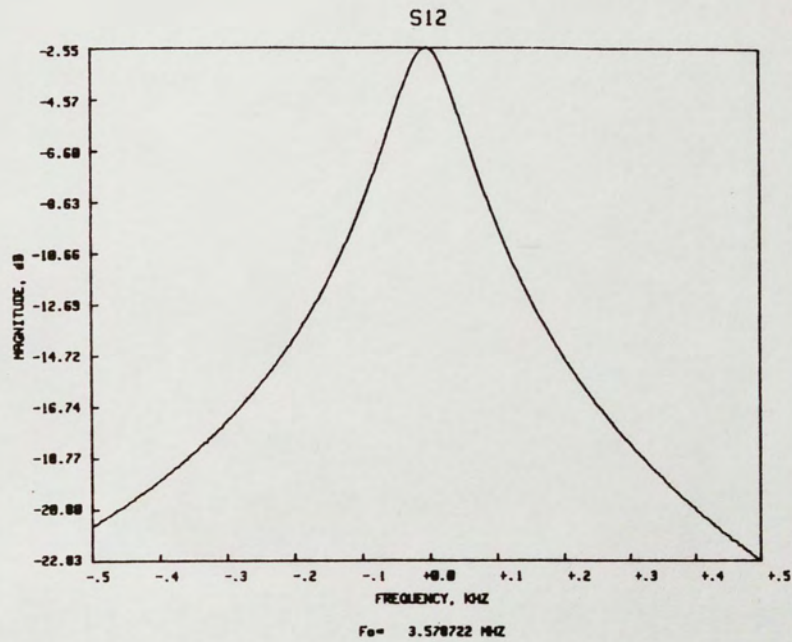


Figure 16.  $S_{12}$  Magnitude Plot of Device J69; Second Run

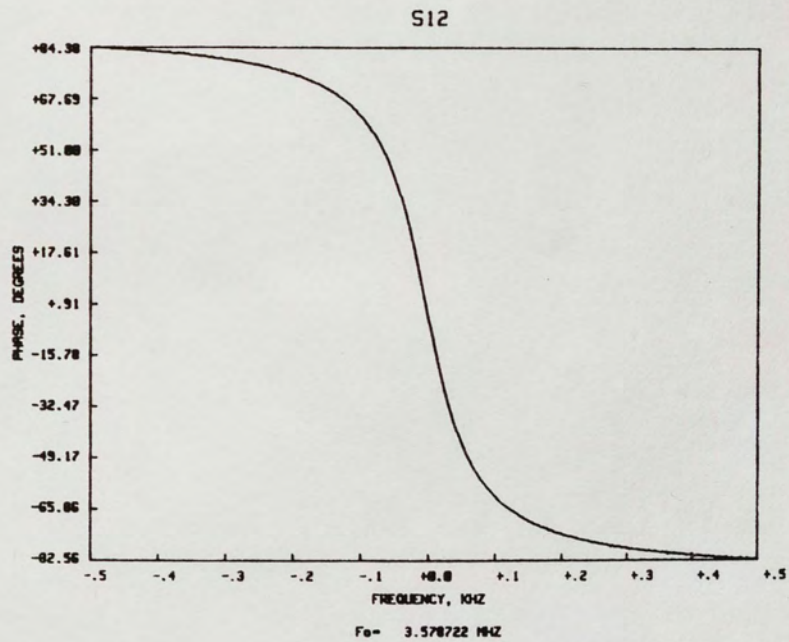


Figure 17.  $S_{12}$  Phase Plot of Device J69; Second Run

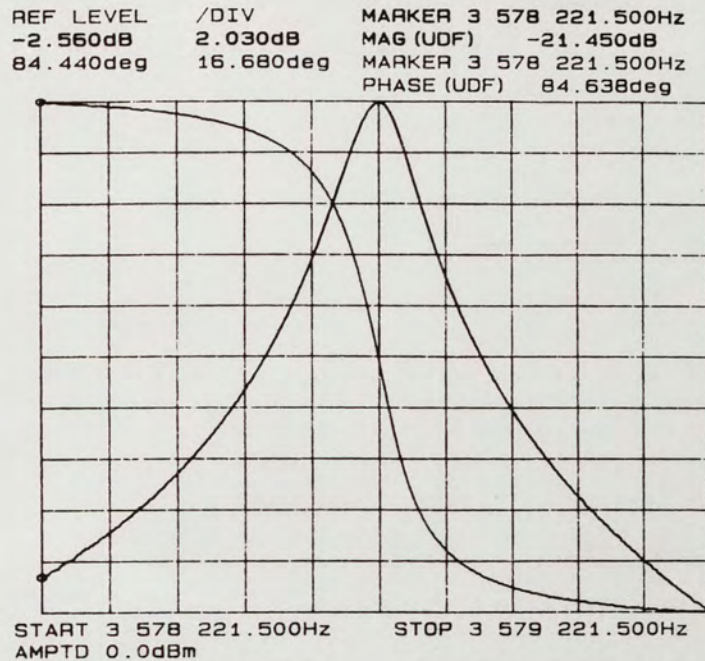


Figure 18.  $S_{12}$  Magnitude and Phase Plot of Device J69 Made Directly from the HP 3577A Network Analyzer

The percent difference in phase at resonance is 9.9% and the percent difference in phase range is -0.048%. Again, these results can be found in Table 2. The error run plots for both of these devices are to follow.

The scattering parameter  $S_{11}$  was measured from devices F83 and J69 twice each also for the purpose of comparing two error runs. The "Define the Delta Frequency" method of data acquisition was again chosen and the values for the delta frequency and number of data points are as before. Figures 19 through 22 show the magnitude and phase plots of the first and second run from device F83.



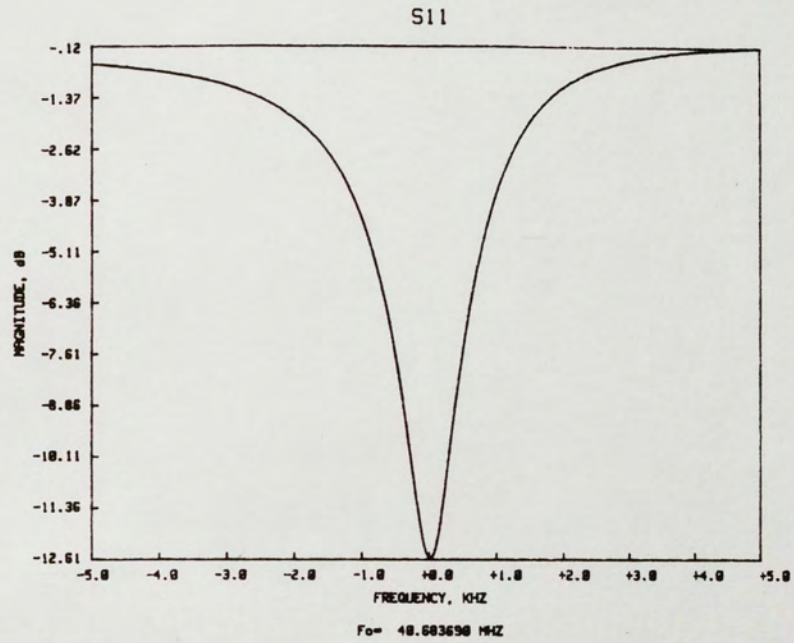


Figure 19.  $S_{11}$  Magnitude Plot of Device F83; First Run

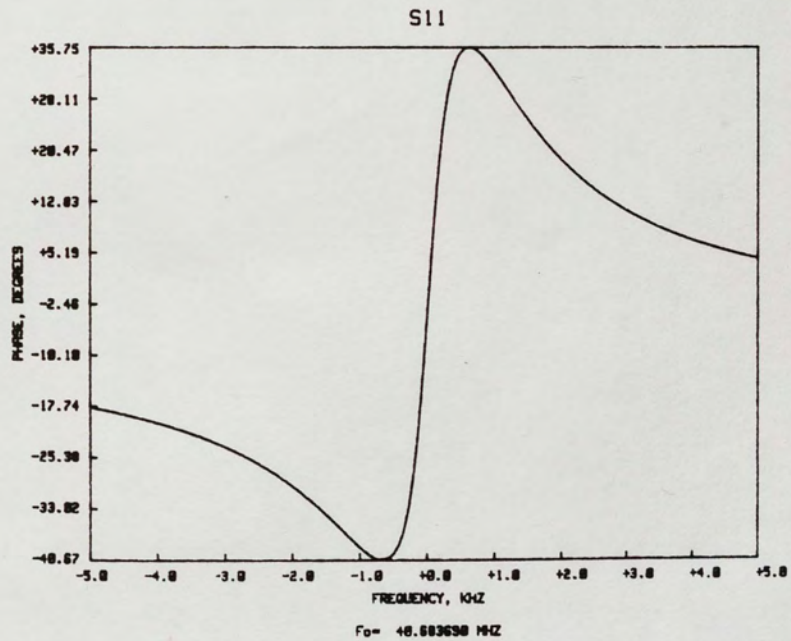


Figure 20.  $S_{11}$  Phase Plot of Device F83; First Run

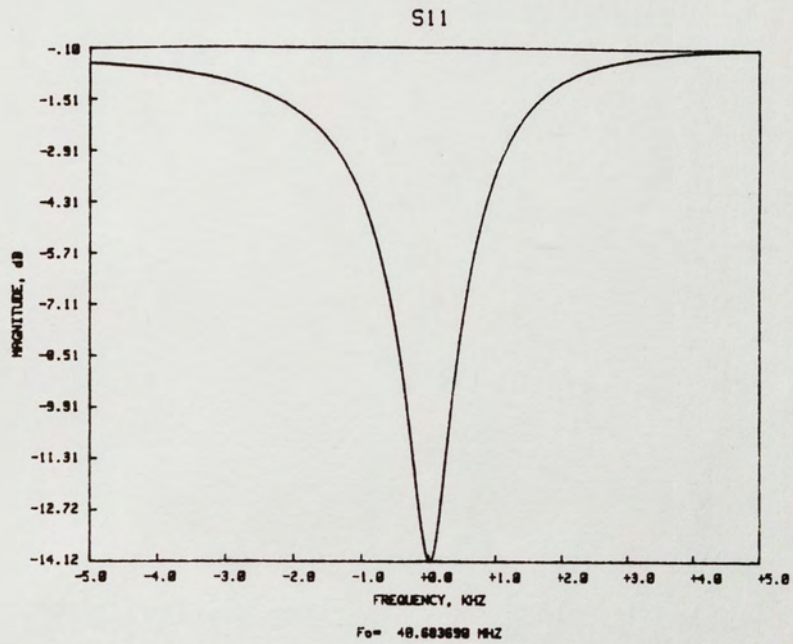


Figure 21. S<sub>11</sub> Magnitude Plot of Device F83; Second Run

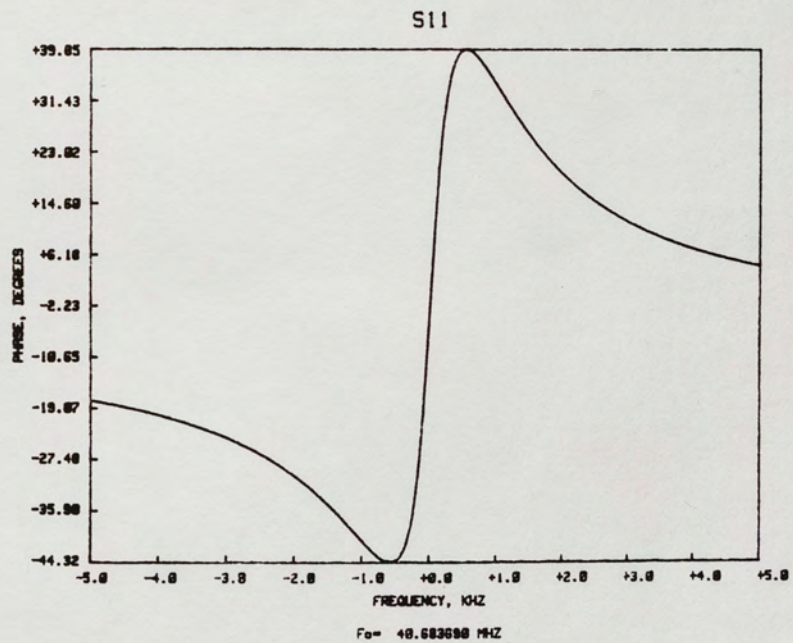


Figure 22. S<sub>11</sub> Phase Plot of Device F83; Second Run



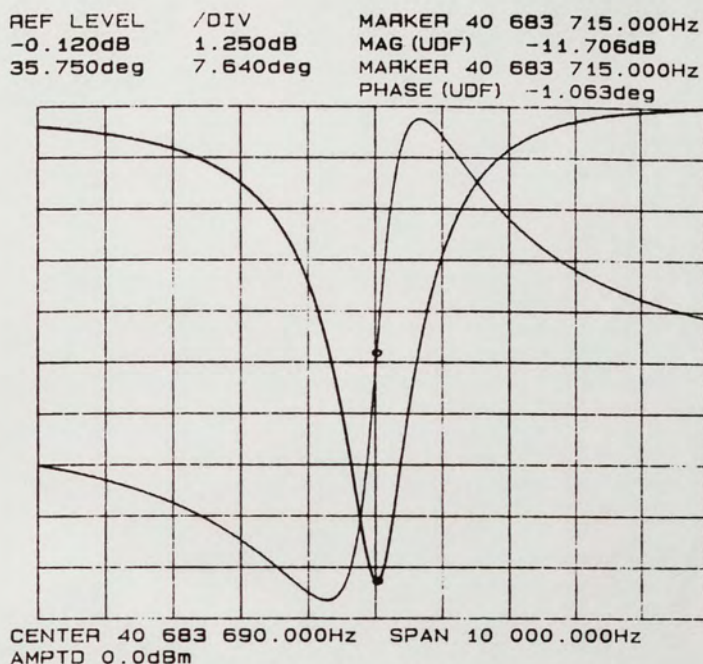


Figure 23.  $S_{11}$  Magnitude and Phase Plot of Device F83 Made Directly from the HP 3577A Network Analyzer

Figure 23 shows the calibrated magnitude and phase plot made from the front panel of the network analyzer. Comparison of runs show a percent difference in magnitude at resonance of 15.96%, a percent difference in amplitude range of -5.28%, a percent difference in phase at resonance of 9.35%, and a percent difference in phase range of -10.1%. Figures 24 through 27 show the magnitude and phase plots of the first and second run from device J69. Figure 28 shows the calibrated magnitude and phase plot made from the front panel of the network analyzer.

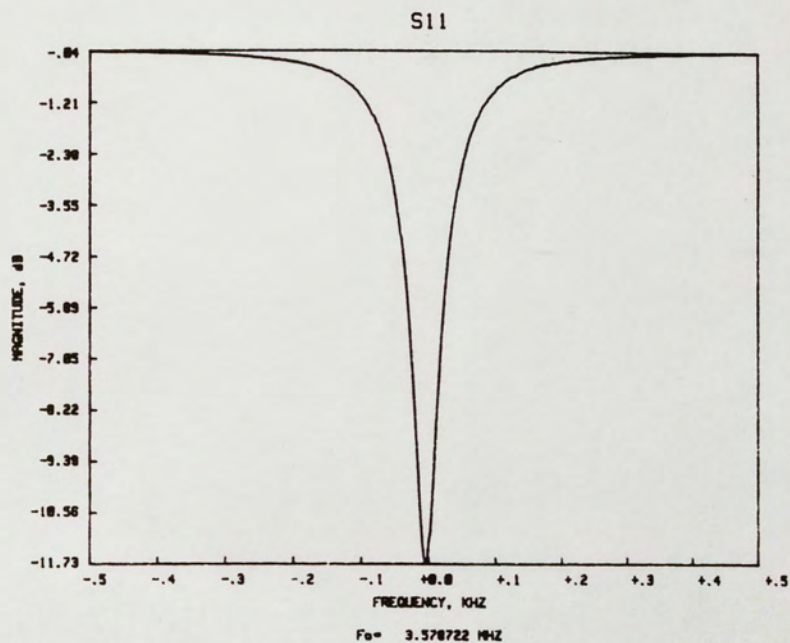


Figure 24.  $S_{11}$  Magnitude Plot of Device J69; First Run

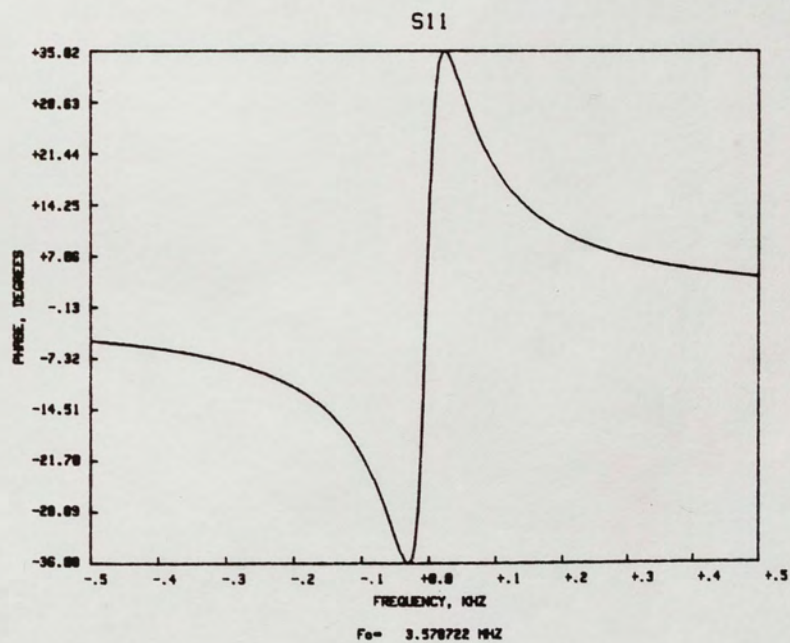


Figure 25.  $S_{11}$  Phase Plot of Device J69; First Run



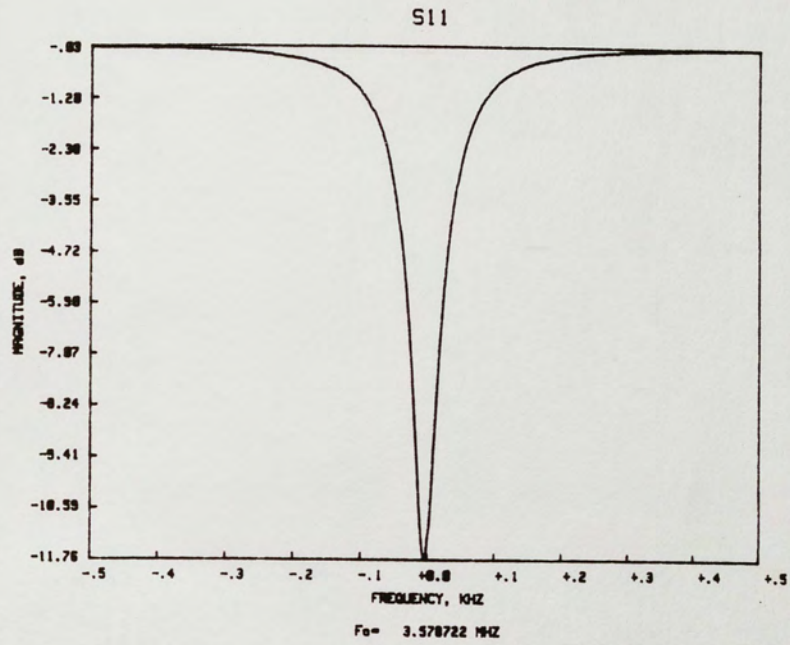


Figure 26.  $S_{11}$  Magnitude Plot of Device J69; Second Run

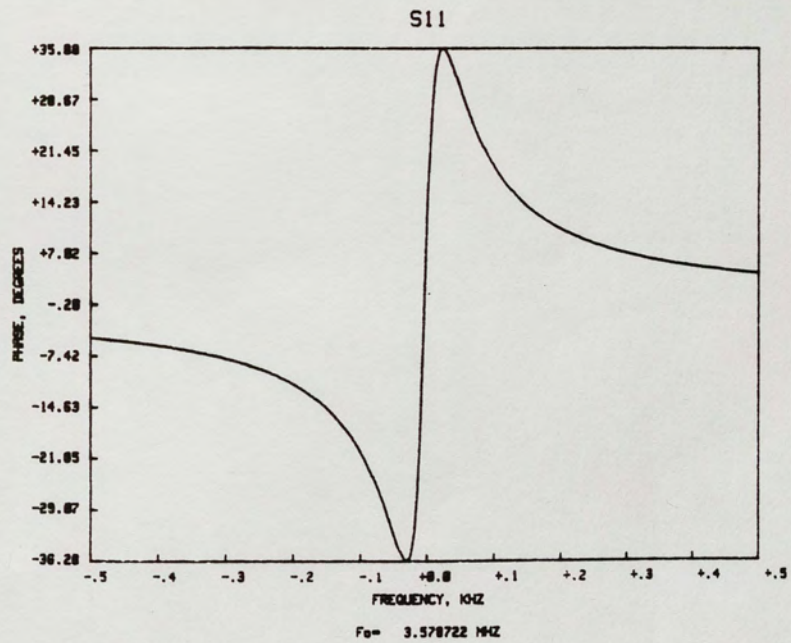


Figure 27.  $S_{11}$  Phase Plot of Device J69; Second Run

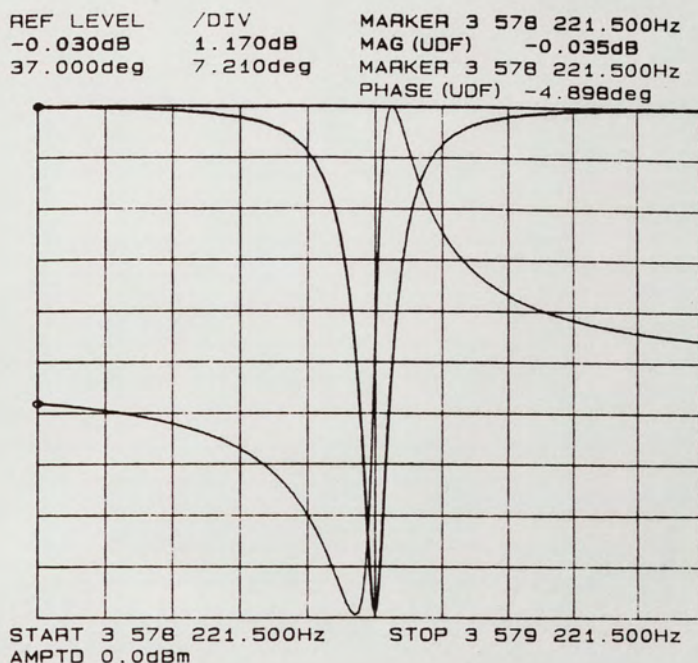


Figure 28.  $S_{11}$  Magnitude and Phase Plot of Device J69 Made Directly from the HP 3577A Network Analyzer

A comparison of runs show a percent difference in magnitude at resonance of 0.34%, a percent difference in amplitude range of -0.27%, a percent difference in phase at resonance of -53.8%, and a percent difference in phase range of 0.36%. The error run plots for both of these devices are to follow.

The scattering parameter  $S_{22}$  was measured twice from device J69. The "Define the Number of Data Points" method of data acquisition was chosen. Figures 29 and 30 show the magnitude and phase plots of the measurements using  $N=401$  and figures 31 and 32 show the plots of the measurements using  $N=1024$ .



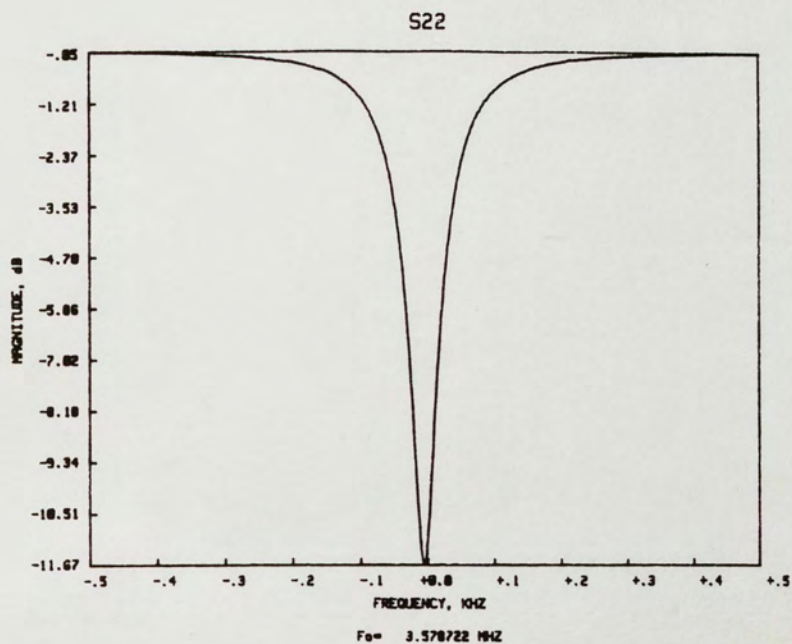


Figure 29.  $S_{22}$  Magnitude Plot of Device J69 with N=401

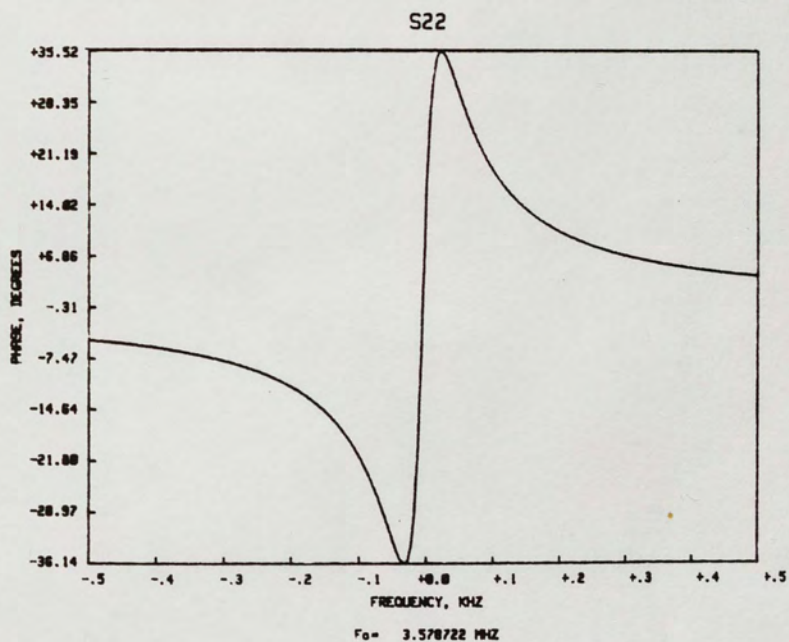


Figure 30.  $S_{22}$  Phase Plot of Device J69 with N=401

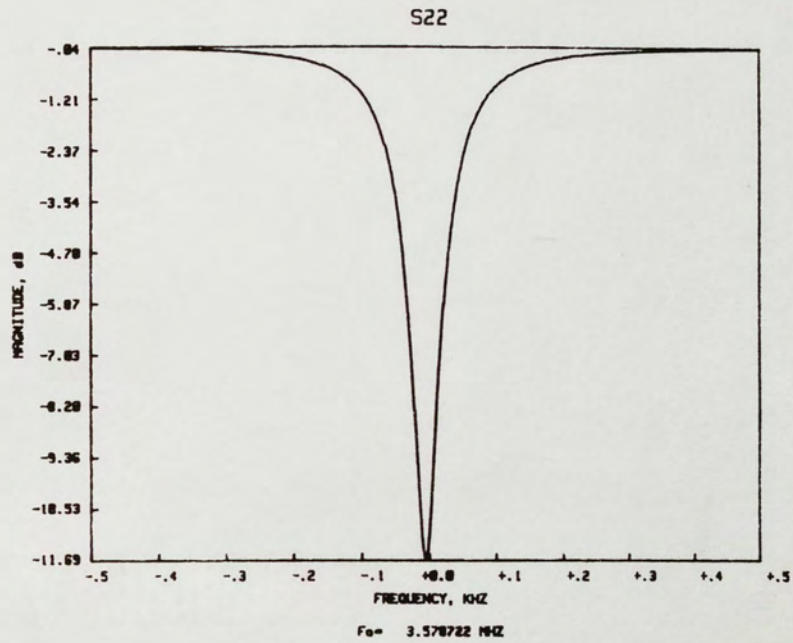


Figure 31. S<sub>22</sub> Magnitude Plot of Device J69 with N=1024

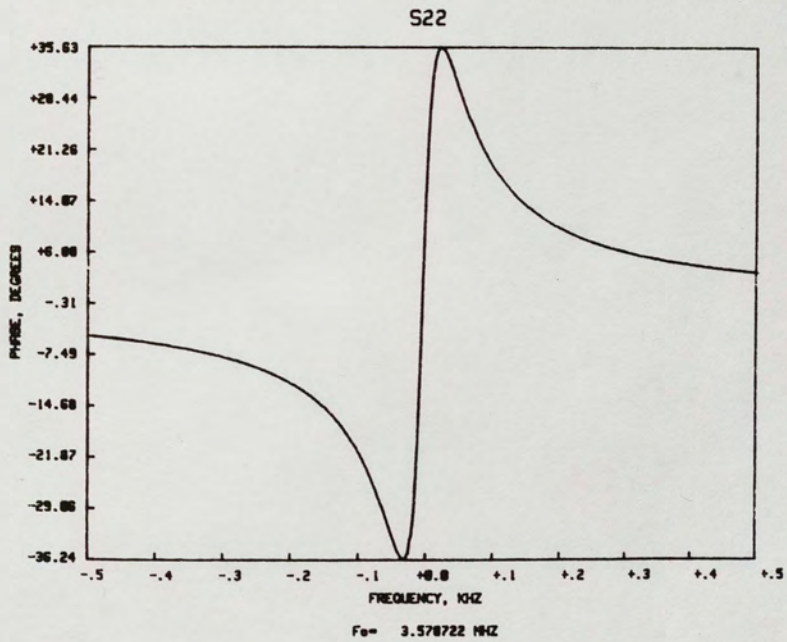


Figure 32. S<sub>22</sub> Phase Plot of Device J69 with N=1024



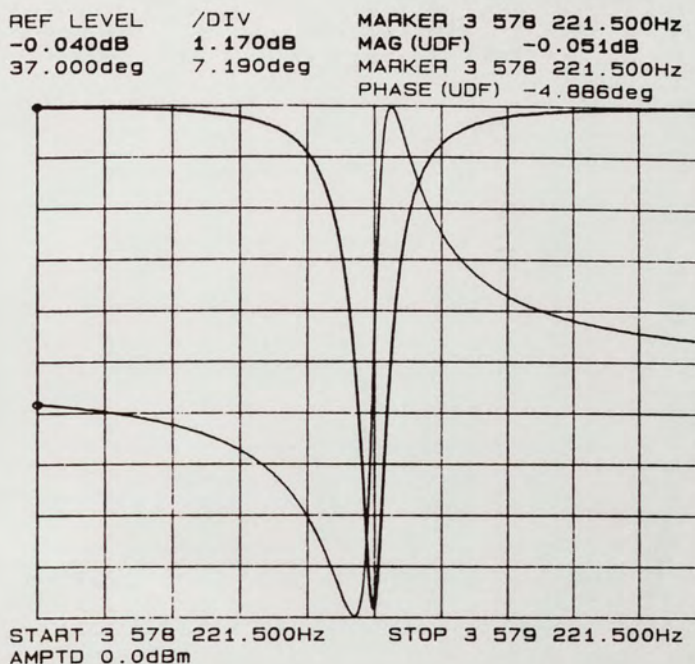
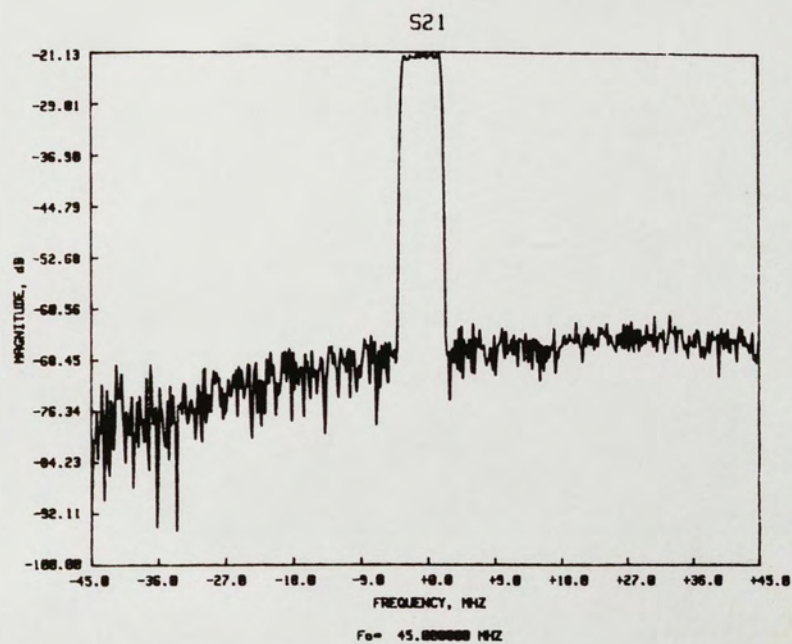
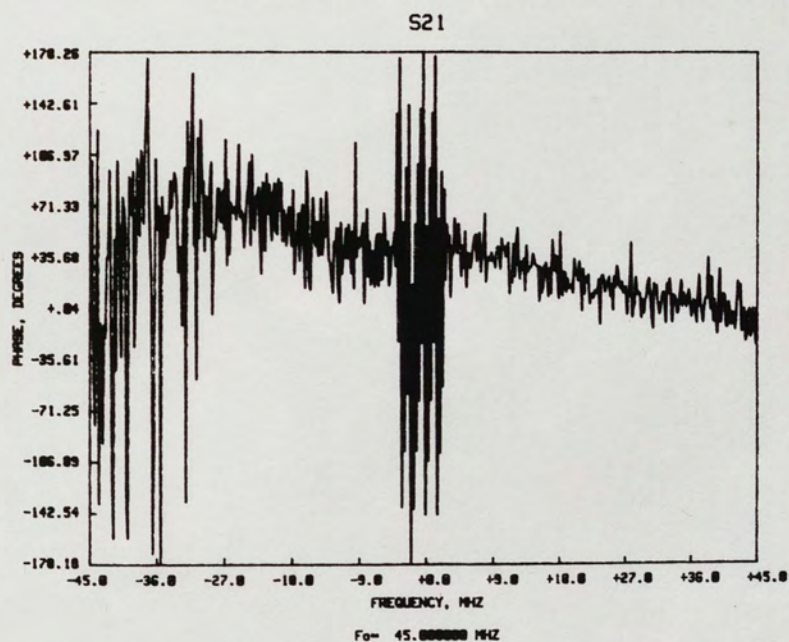


Figure 33.  $S_{22}$  Magnitude and Phase Plot of Device J69 Made Directly from the HP 3577A Network Analyzer

Figure 33 shows the normalized magnitude and phase plot made from the front panel of the network analyzer. A comparison of measurements taken with different number of data points show a percent difference in magnitude at resonance of 0.23%, a percent difference in amplitude range of -0.25%, a percent difference in phase at resonance of 0.0%, and a percent difference in phase range of -0.29%. These values, as before, are repeated in Table 2. The purpose for making these measurements is to compare the error runs. Plots of those runs are to follow.

The scattering parameter  $S_{21}$  was also measured from the SAW device. The start frequency was 0 Hz and the stop frequency was 90 MHz. The "Define the Delta Frequency" method of data acquisition was used with  $Df=0.17578125$  and  $N=512$ . Actual data acquisition began at 0.17578125 MHz for reasons previously explained in the Data Acquisition Methods section of this thesis. Figures 34 and 35 show the magnitude and phase plots. Figures 36 and 37 show the normalized magnitude and phase plots made from the front panel of the network analyzer. As before,  $N=401$  and so the delta frequency between data points was 0.225 MHz. This set of plots can be seen to have similar characteristics as the set of plots made using the computer program. The results of the magnitude measurements were saved on the hard disc and another computer program was utilized to find the fast Fourier transform of the data. Figure 38 shows the plot of the transform. Note that the plot now shows magnitude versus time.



Figure 34. S<sub>21</sub> Magnitude Plot of SAW DeviceFigure 35. S<sub>21</sub> Phase Plot of SAW Device

REF LEVEL /DIV MARKER 45 000 000.000Hz  
 -21.130dB 7.880dB MAG (UDF) -22.689dB

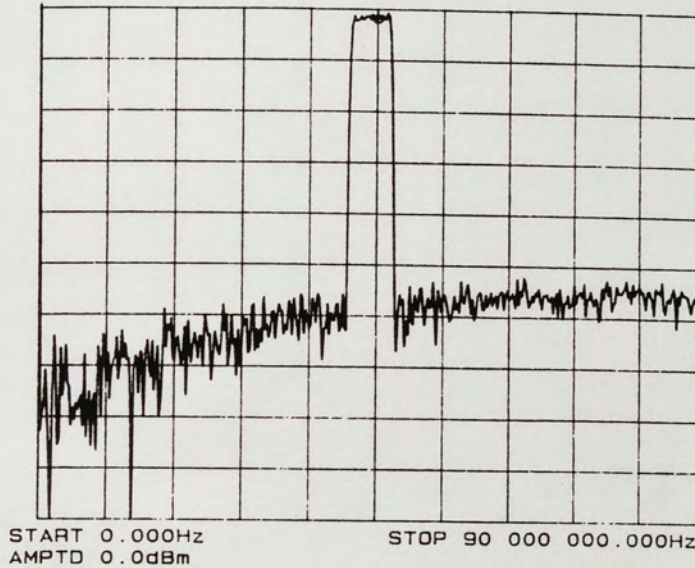


Figure 36. S<sub>21</sub> Magnitude Plot of SAW Device Made Directly from the HP 3577A Network Analyzer

REF LEVEL /DIV MARKER 45 000 000.000Hz  
 0.040deg 35.650deg PHASE (UDF) 152.161deg

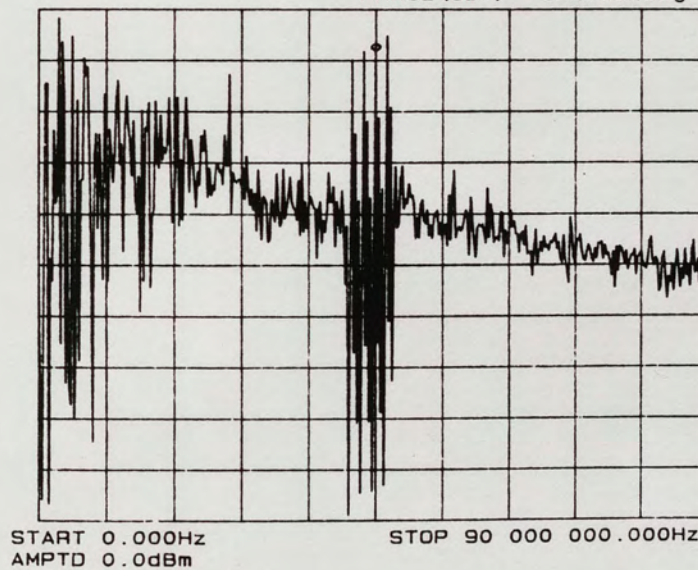


Figure 37. S<sub>21</sub> Phase Plot of SAW Device Made Directly from the HP 3577A Network Analyzer



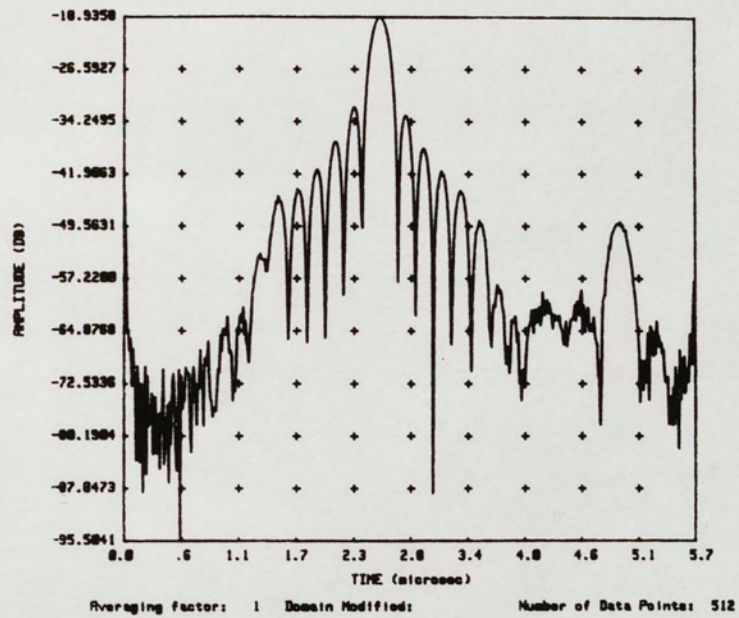


Figure 38. Fast Fourier Transform of the  $S_{21}$  Measurement from the SAW Device

TABLE 2  
MEASUREMENT COMPARISONS

Device	Methods Compared	Measurement Compared	Percent Difference
1. F83	Dump the Screen Define N	Magnitude at Resonance	-0.35%
2. F83	Dump the Screen Define Df	Magnitude at Resonance	-0.35%
3. F83	Dump the Screen Define N	Magnitude Range	-0.48%
4. F83	Dump the Screen Define Df	Magnitude Range	-0.35%
5. F83	Dump the Screen Define N	Phase at Resonance	2.8%
6. F83	Dump the Screen Define Df	Phase at Resonance	2.1%
7. F83	Dump the Screen Define N	Phase Range	0.067%
8. F83	Dump the Screen Define Df	Phase Range	0.04%
9. F83	Define Df; First Run Define Df; Second Run	Magnitude at Resonance	0.12%
10. F83	Define Df; First Run Define Df; Second Run	Magnitude Range	0.15%
11. F83	Define Df; First Run Define Df; Second Run	Phase at Resonance	-4.2%
12. F83	Define Df; First Run Define Df; Second Run	Phase Range	0.13%
13. J69	Define Df; First Run Define Df; Second Run	Magnitude at Resonance	-0.12%
14. J69	Define Df; First Run Define Df; Second Run	Magnitude Range	-0.12%
15. J69	Define Df; First Run Define Df; Second Run	Phase at Resonance	9.9%
16. J69	Define Df; First Run Define Df; Second Run	Phase Range	-0.048%
17. F83	Define Df; First Run Define Df; Second Run	Magnitude at Resonance	15.96%
18. F83	Define Df; First Run Define Df; Second Run	Magnitude Range	-5.28%
19. F83	Define Df; First Run Define Df; Second Run	Phase at Resonance	9.35%
20. F83	Define Df; First Run Define Df; Second Run	Phase Range	-10.1%
21. J69	Define Df; First Run Define Df; Second Run	Magnitude at Resonance	0.34%
22. J69	Define Df; First Run Define Df; Second Run	Magnitude Range	-0.27%
23. J69	Define Df; First Run Define Df; Second Run	Phase at Resonance	-53.8%
24. J69	Define Df; First Run Define Df; Second Run	Phase Range	0.36%
25. J69	Define N=401 Define N=1024	Magnitude at Resonance	0.23%
26. J69	Define N=401 Define N=1024	Magnitude Range	-0.25%
27. J69	Define N=401 Define N=1024	Phase at Resonance	0.0%
28. J69	Define N=401 Define N=1024	Phase Range	-0.29%



### Error Analysis

Figure 39 shows the plot of the  $S_{21}$  magnitude error of device F83 using the "Dump the Screen" method. The error range is approximately  $\pm 0.03$  dB. Figure 40 shows the plot of the  $S_{21}$  phase error of device F83 using the "Dump the Screen" method. The error ranges from  $-0.11$  degrees to  $+0.19$  degrees with the increases noted slightly above resonant frequency where the phase change is great over a small frequency range, and at higher frequencies where the phase just begins to approach  $-90$  degrees (see Figure 3). Figure 41 shows the plot of the  $S_{21}$  magnitude error of device F83 using the "Define the Number of Data Points" method. The error range is approximately  $\pm 0.02$  dB across the majority of the frequency span. At higher frequencies when the magnitude decreases (see Figure 4), the error ranges from  $-0.02$  dB to  $+0.03$  dB. Figure 42 shows the plot of the  $S_{21}$  phase error of device F83 using the "Define the Number of Data Points" method. The error ranges from  $-0.09$  degrees to  $+0.3$  degrees with the increase noted at higher frequencies where the phase just begins to approach  $-90$  degrees (see Figure 5). Figure 43 shows the plot of the  $S_{21}$  magnitude error of device F83 using the "Define the Delta Frequency" method. The error ranges from  $-0.05$  dB to  $+0.03$  dB with the increase noted at higher frequencies when the magnitude decreases (see Figure 6).

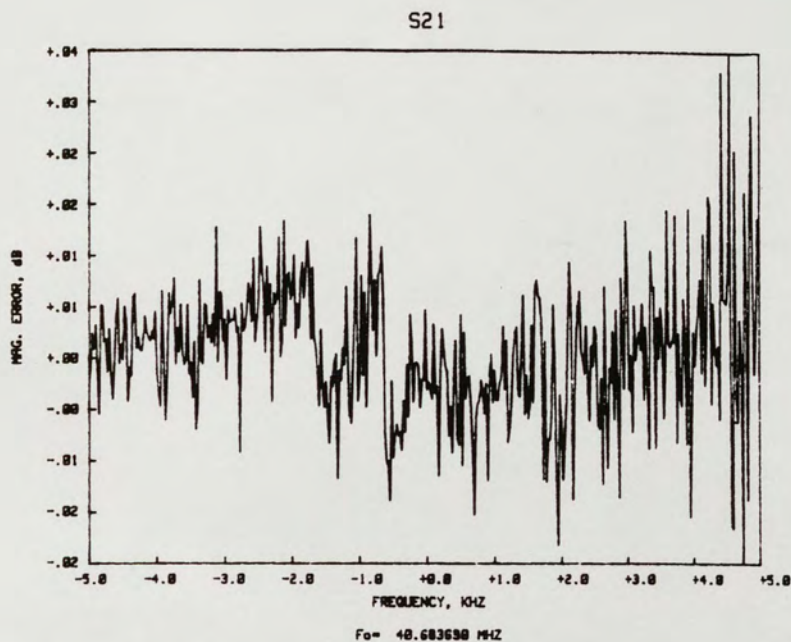


Figure 39. S<sub>21</sub> Magnitude Error Plot of Device F83 Using the "Dump the Screen" Data Acquisition Method

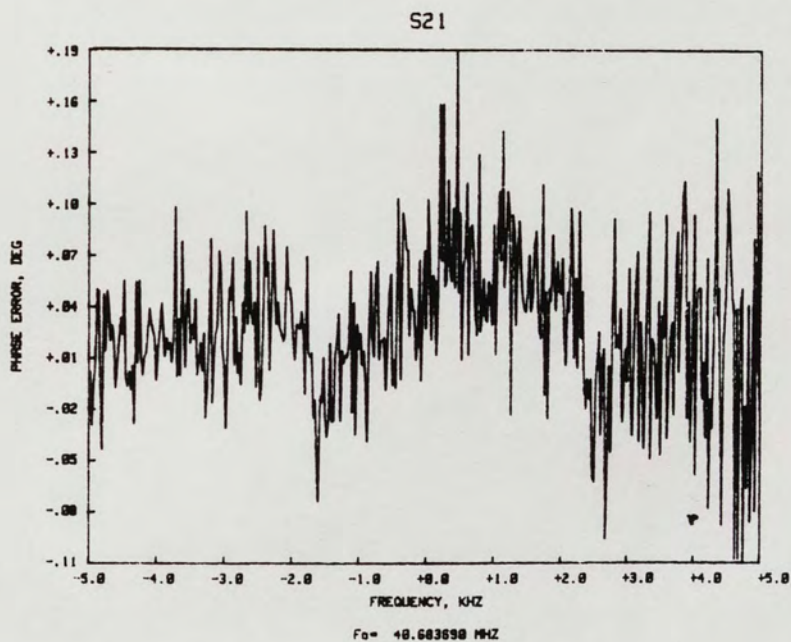


Figure 40. S<sub>21</sub> Phase Error Plot of Device F83 Using the "Dump the Screen" Data Acquisition Method



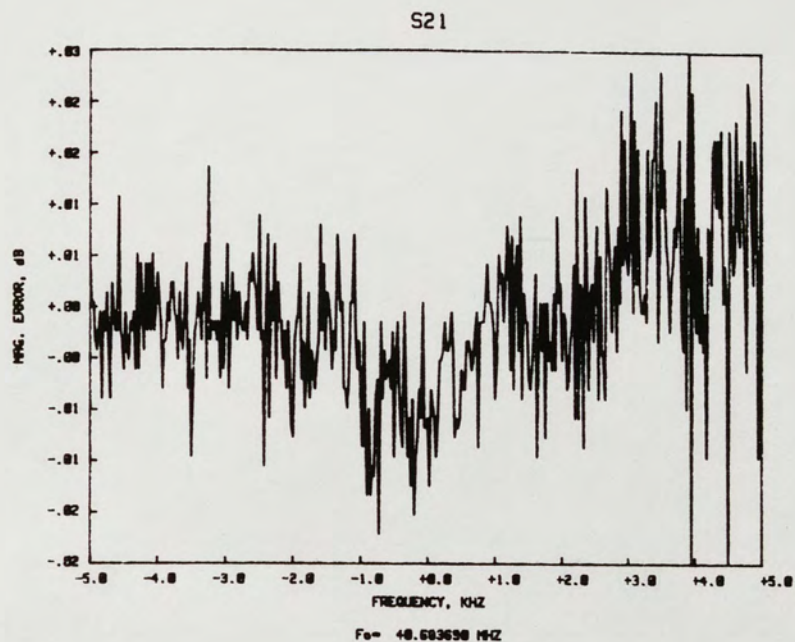


Figure 41. S<sub>21</sub> Magnitude Error Plot of Device F83 Using the "Define the Number of Data Points" Data Acquisition Method

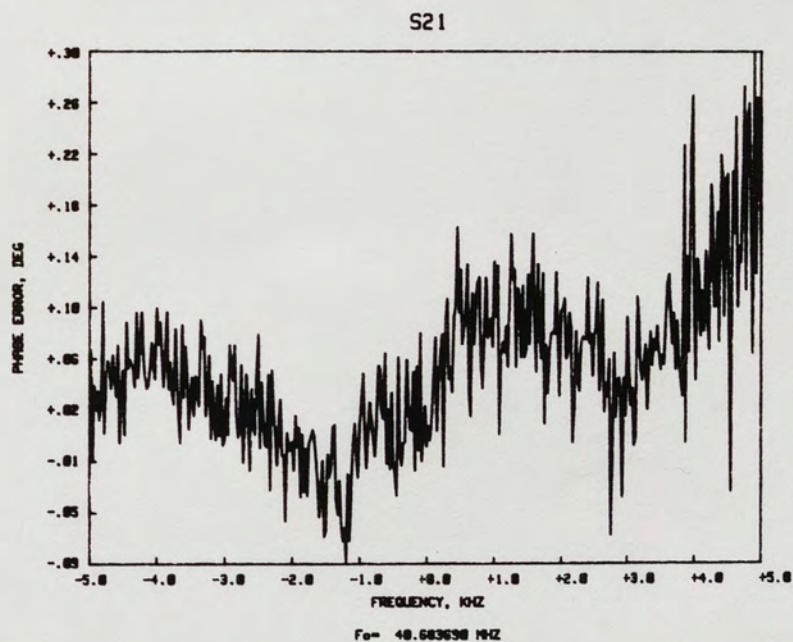


Figure 42. S<sub>21</sub> Phase Error Plot of Device F83 Using the "Define the Number of Data Points" Data Acquisition Method

Figure 44 shows the  $S_{21}$  phase error plot of device F83 using the "Define the Delta Frequency" method. The error ranges from -0.10 degrees to +0.20 degrees with the increase noted at higher frequencies where the phase just begins to approach -90 degrees (see Figure 7). Table 3 shows the maximum errors for each measurement.

Figures 45 and 46 show the  $S_{12}$  magnitude error plots of device F83 for the first and second run. The first run error ranges from -0.03 dB to +0.02 dB and the second run error ranges from -0.02 dB to +0.03 dB. The increased errors are noted at higher frequencies where the  $S_{12}$  magnitude decreases (see figures 9 and 11). Figures 47 and 48 show the  $S_{12}$  phase error plots of device F83 for the first and second run. The first run error ranges from -0.15 degrees to +0.18 degrees with the maximum error occurring slightly beyond the resonant frequency where the change in phase is great over a small frequency span (see Figure 10). The second run error ranges from -0.20 degrees to +0.23 degrees with the increase noted at higher frequencies where the phase just begins to approach -90 degrees (see Figure 12).

Figures 49 and 50 show the  $S_{12}$  magnitude error plots of device J69 for the first and second run. The first run error ranges from -0.08 dB to +0.08 dB and the second run error ranges from -0.07 dB to +0.09 dB.



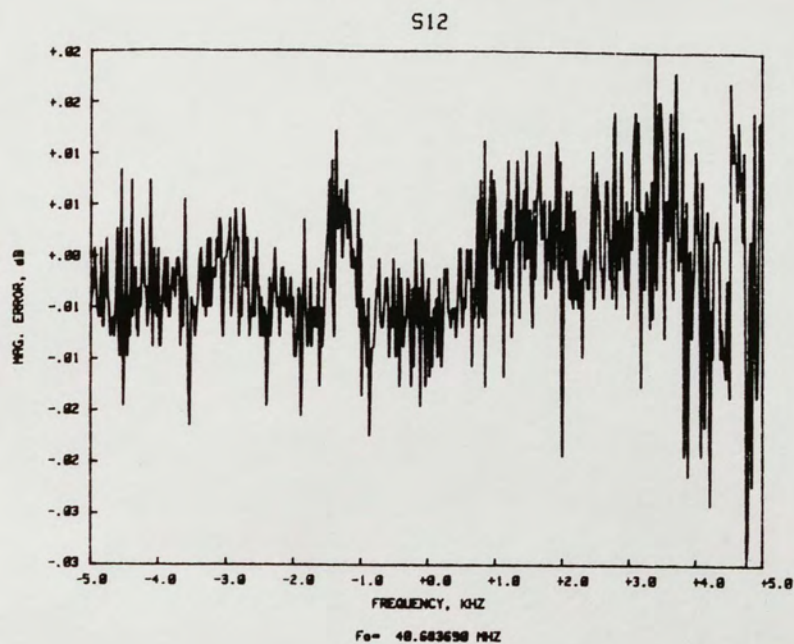


Figure 45.  $S_{12}$  Magnitude Error Plot of Device F83;  
First Run

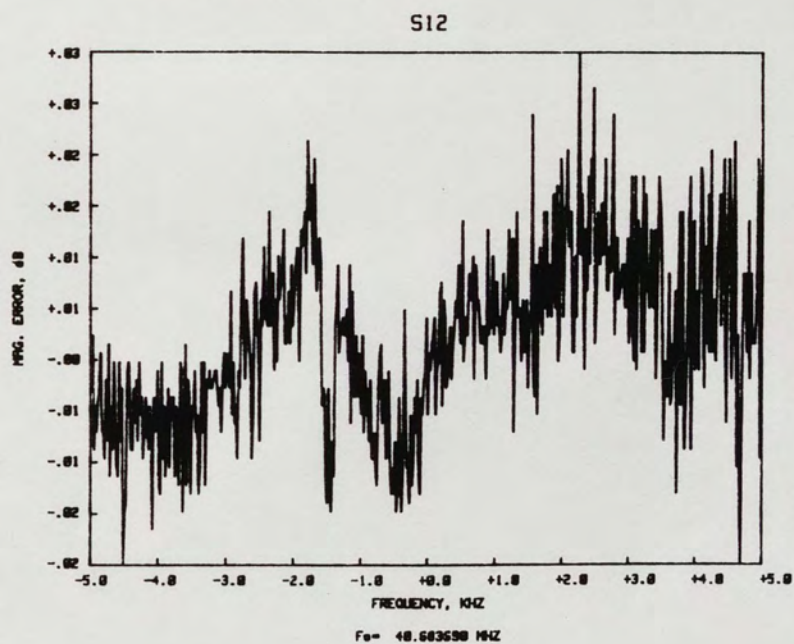


Figure 46.  $S_{12}$  Magnitude Error Plot of Device F83;  
Second Run

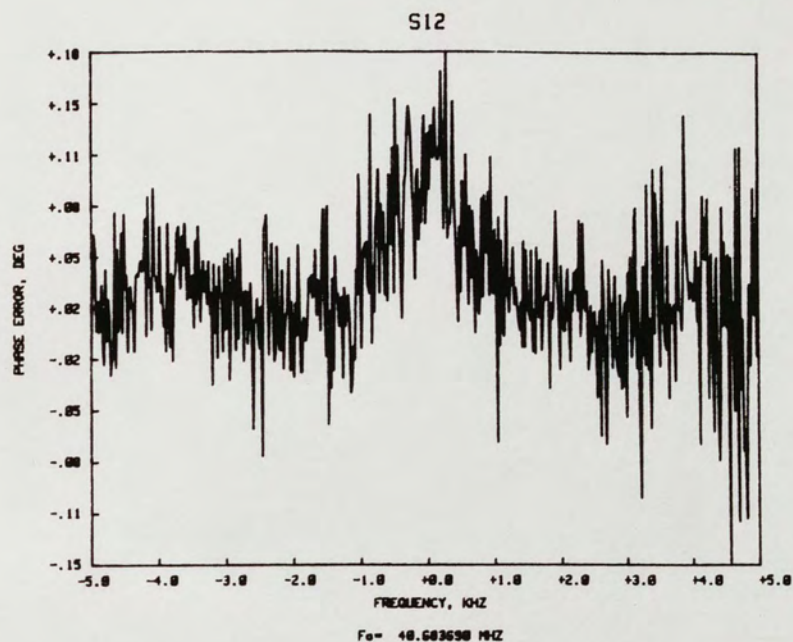


Figure 47.  $S_{12}$  Phase Error Plot of Device F83; First Run

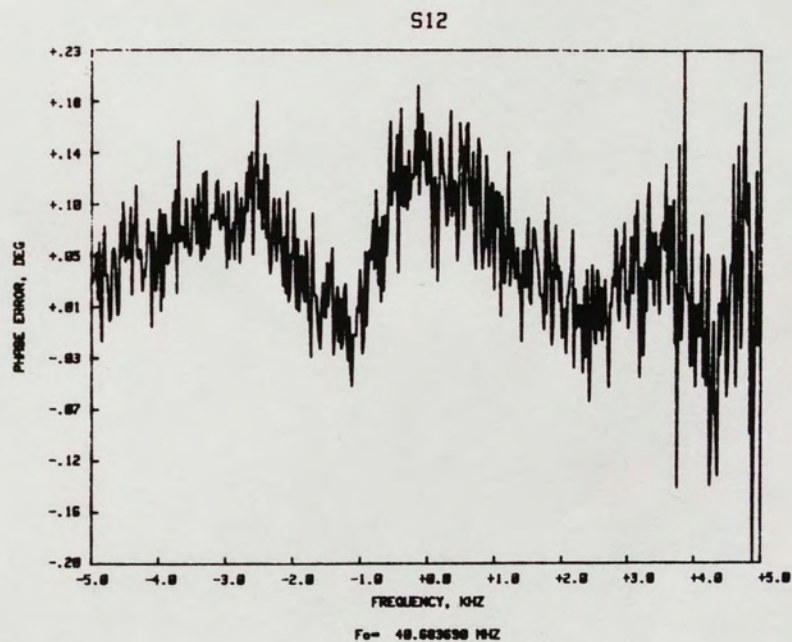


Figure 48.  $S_{12}$  Phase Error Plot of Device F83; Second Run



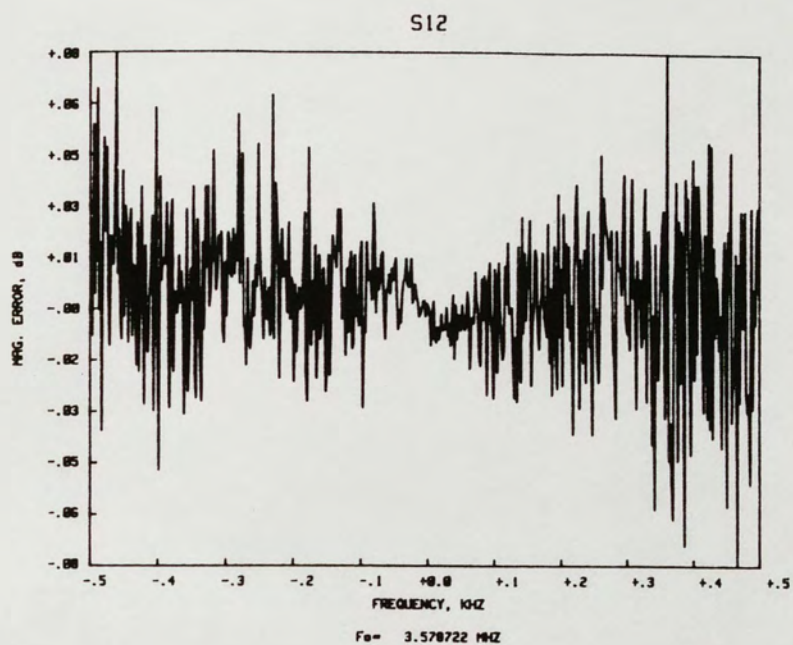


Figure 49.  $S_{12}$  Magnitude Error Plot of Device J69;  
First Run

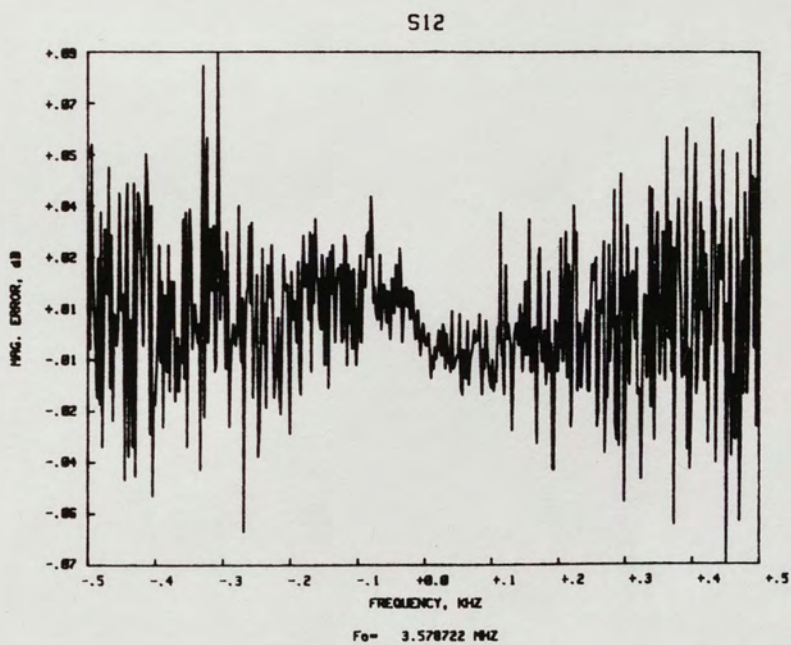


Figure 50.  $S_{12}$  Magnitude Error Plot of Device J69;  
Second Run

The increased errors for both of these runs are noted at lower and higher frequencies where the  $S_{12}$  magnitude is lower (see figures 14 and 16). Figures 51 and 52 show the  $S_{12}$  phase error plots of device J69 for the first and second run. The error ranges from  $-0.62$  degrees to  $+0.37$  degrees for the first run and from  $-0.63$  degrees to  $+0.45$  degrees for the second run. Increased errors for both runs occur as the  $S_{12}$  phase approaches  $\pm 90$  degrees at lower and higher frequencies (see figures 15 and 17).

Figures 53 and 54 show the  $S_{11}$  magnitude error plots of device F83 for the first and second run. The first run error ranges from  $-0.09$  dB to  $+0.05$  dB and the second run error ranges from  $-0.03$  dB to  $+0.05$  dB. The increased errors for both runs are noted slightly before and after the resonant frequency where the  $S_{11}$  magnitude changes are sharp over a small frequency span (see figures 19 and 21). Figures 55 and 56 show the phase error plots of device F83 for the first and second run. The error ranges from  $-0.54$  degrees to  $+0.24$  degrees on the first run and from  $-0.37$  degrees to  $+0.28$  degrees on the second run. The increased errors for both runs occur slightly before and after the resonant frequency where the  $S_{11}$  phase changes are sharp over a small frequency span (see figures 20 and 22). Figures 57 and 58 show the  $S_{11}$  magnitude error plots of device J69 for the two runs.



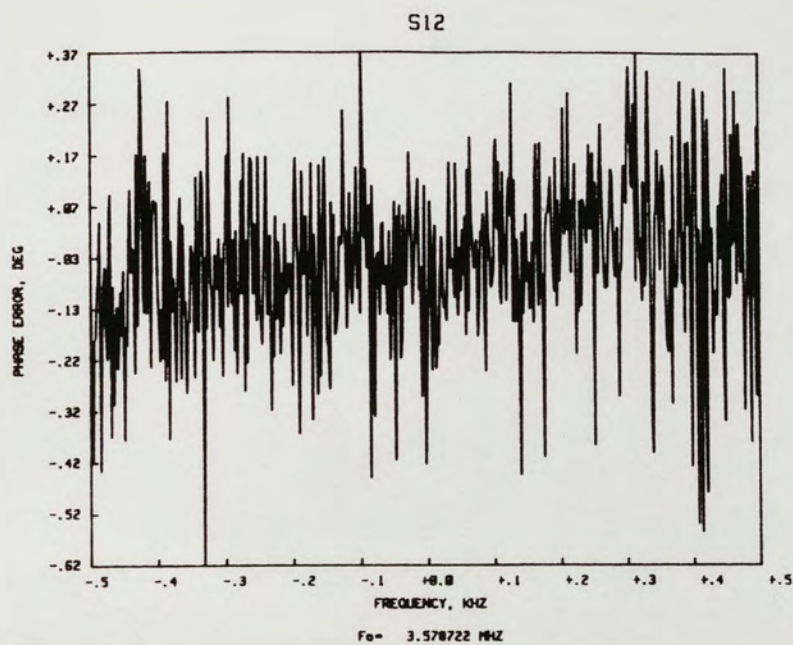


Figure 51.  $S_{12}$  Phase Error Plot of Device J69; First Run

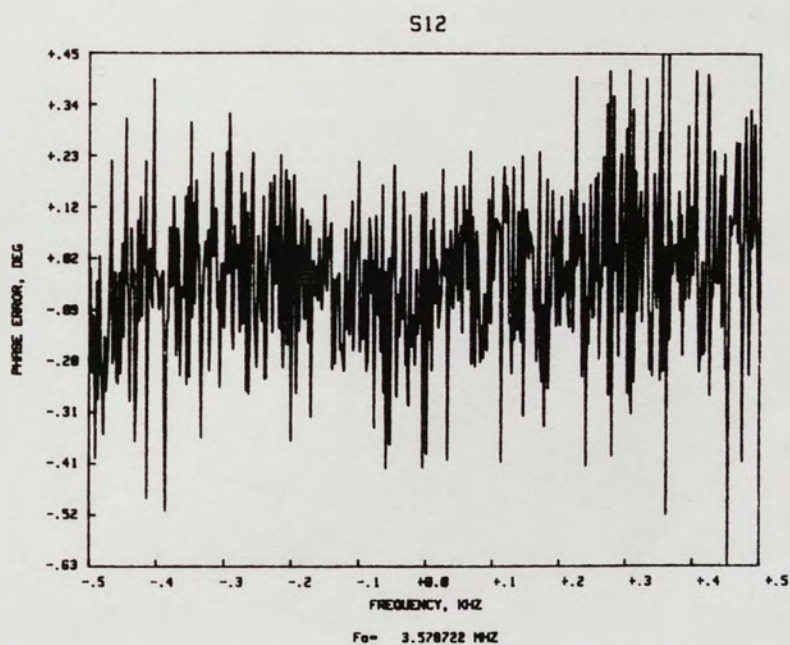


Figure 52.  $S_{12}$  Phase Error Plot of Device J69; Second Run

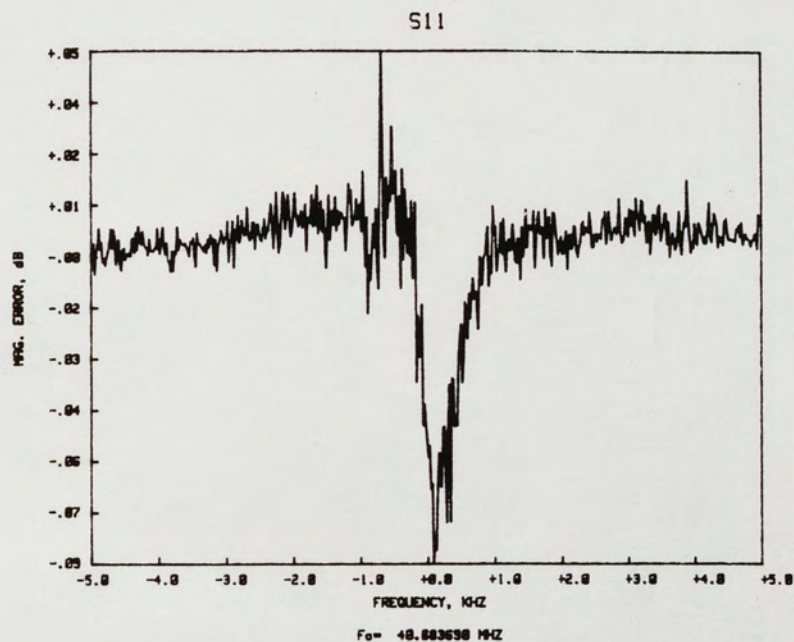


Figure 53. S<sub>11</sub> Magnitude Error Plot of Device F83;  
First Run

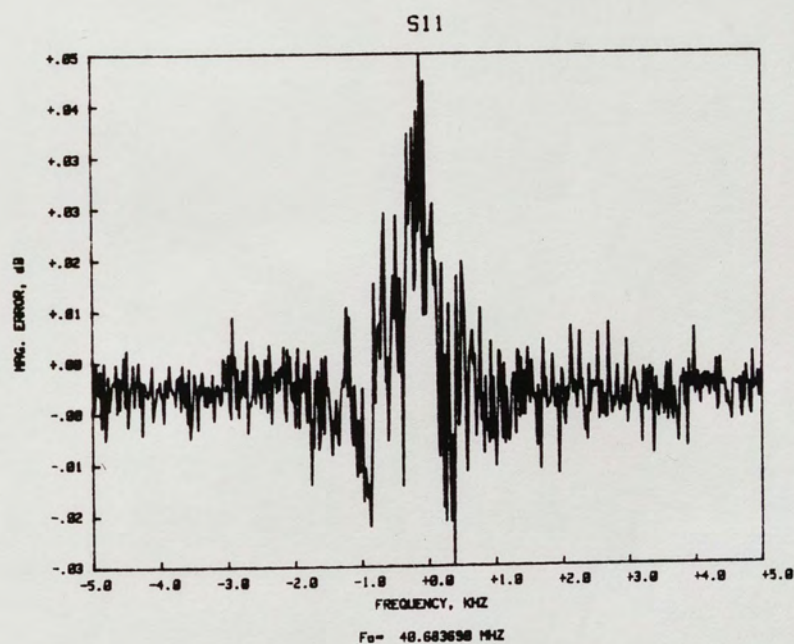


Figure 54. S<sub>11</sub> Magnitude Error Plot of Device F83;  
Second Run



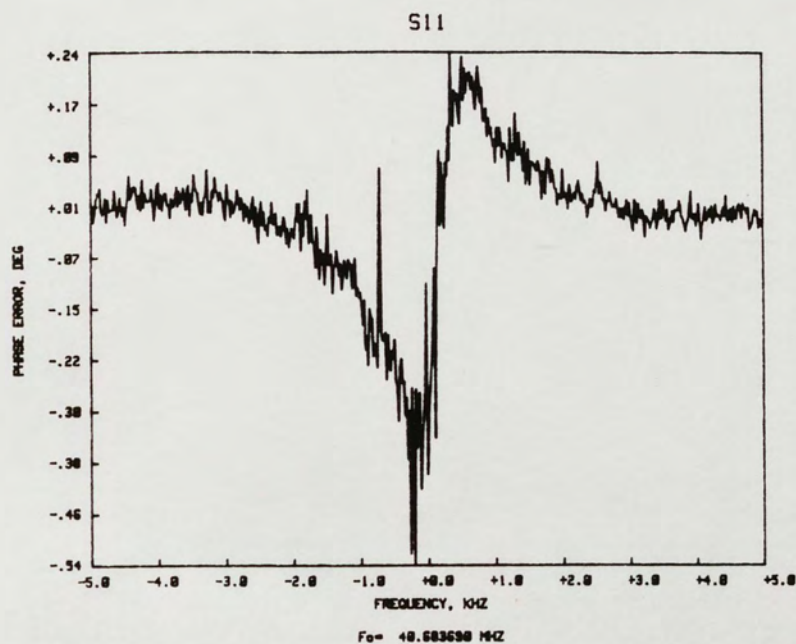


Figure 55. S<sub>11</sub> Phase Error Plot of Device F83; First Run

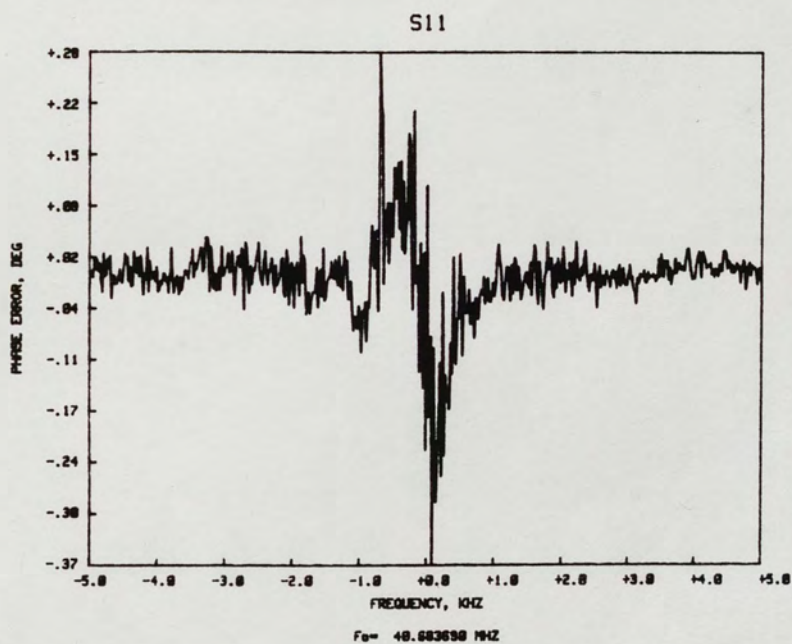


Figure 56. S<sub>11</sub> Phase Error Plot of Device F83; Second Run

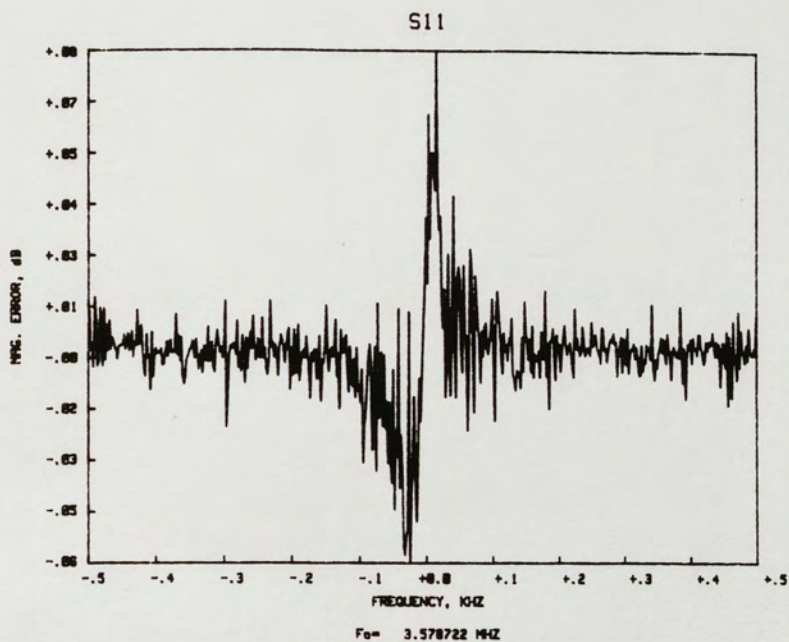


Figure 57. S<sub>11</sub> Magnitude Error Plot of Device J69;  
First Run

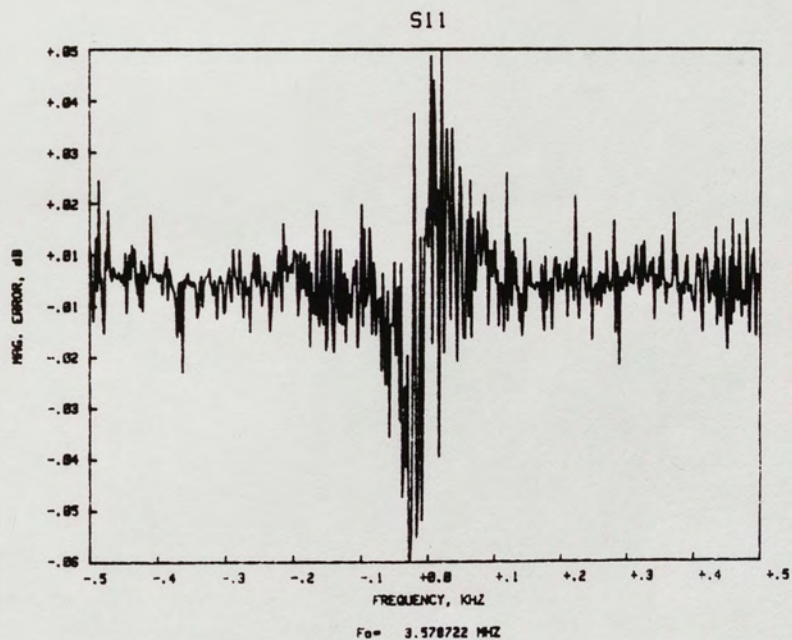


Figure 58. S<sub>11</sub> Magnitude Error Plot of Device J69;  
Second Run



The first run error ranges from  $-0.06$  dB to  $+0.08$  dB and the second run error ranges from  $-0.06$  dB to  $+0.05$  dB. As before, error increases are noted where the change in  $S_{11}$  magnitude is greatest over a small frequency span slightly before and after resonant frequency (see figures 24 and 26). Figures 59 and 60 show the  $S_{11}$  phase error plots of device J69 for the two runs. The first run error ranges from  $-0.41$  degrees to  $+0.80$  degrees with the maximum occurring at the resonant frequency where changes in phase is sharp over a small frequency span (see Figure 25). The second run error ranges from  $-0.24$  degrees to  $+0.77$  degrees with error increases slightly before and after resonant frequency (see Figure 27).

Figures 61 and 62 show the  $S_{22}$  magnitude error plots for different values of  $N$ , the number of data points. For  $N=401$  the error range in Figure 61 is from  $-0.06$  dB to  $+0.09$  dB. For  $N=1024$  the error range in Figure 62 is from  $-0.09$  dB to  $+0.06$  dB. The error increases for both plots occur slightly before and after resonance where the change in  $S_{22}$  magnitude is sharp over a small range of frequencies (see figures 29 and 31). Figures 63 and 64 show the  $S_{22}$  phase error plots for  $N=401$  and  $N=1024$ , respectively. For  $N=401$  the error range in Figure 63 is from  $-0.34$  degrees to  $+0.78$  degrees

with increased error slightly before and after resonant frequency where the change in  $S_{22}$  phase is sharp over a small frequency range (see Figure 30).



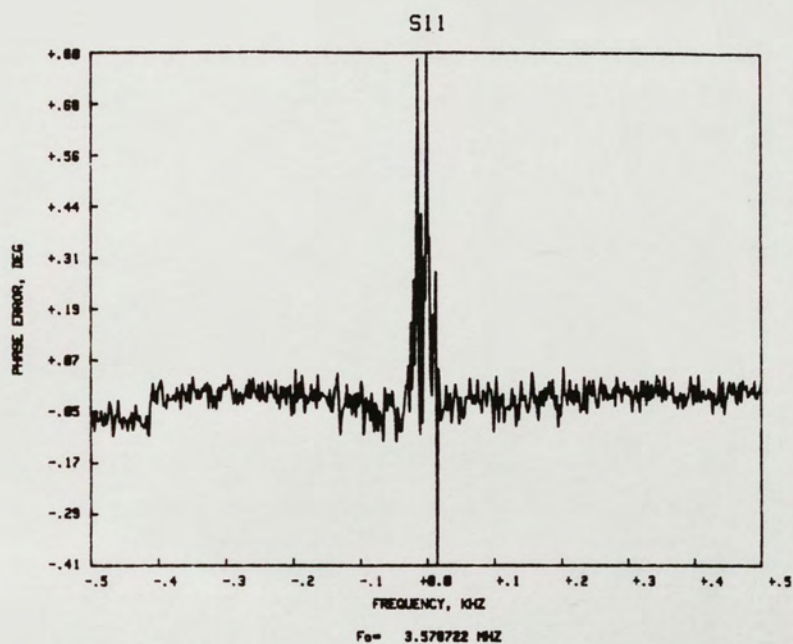


Figure 59. S<sub>11</sub> Phase Error Plot of Device J69; First Run

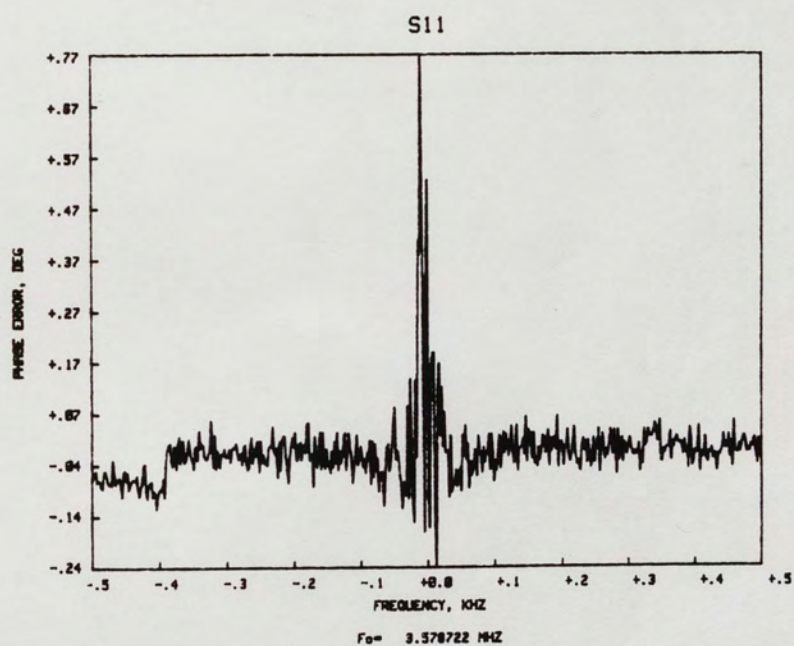


Figure 60. S<sub>11</sub> Phase Error Plot of Device J69; Second Run

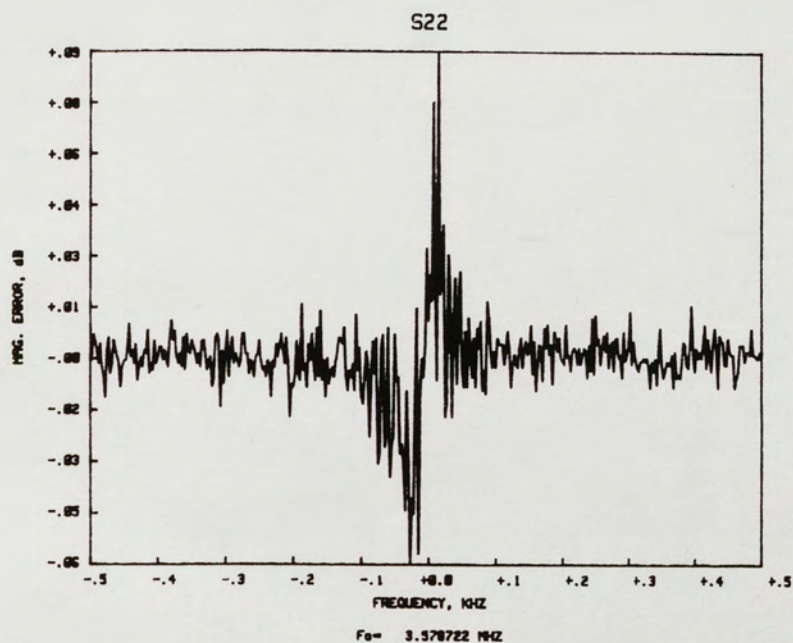


Figure 61.  $S_{22}$  Magnitude Error Plot of Device J69 with N=401

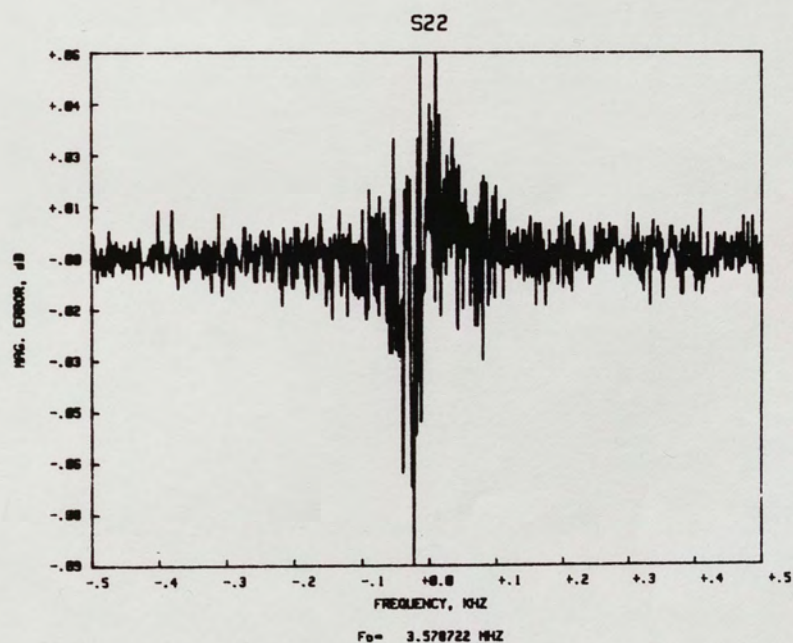


Figure 62.  $S_{22}$  Magnitude Error Plot of Device J69 with N=1024



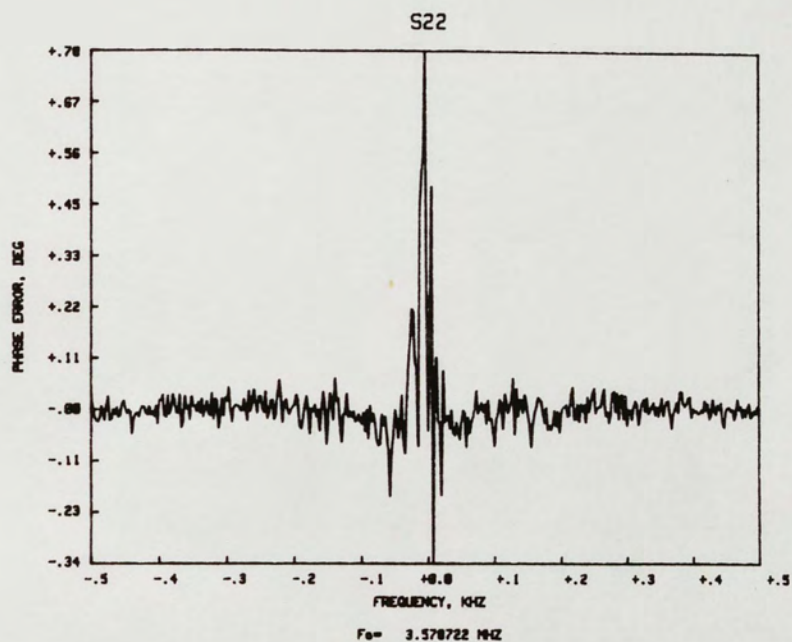


Figure 63. S<sub>22</sub> Phase Error Plot of Device J69 with N=401

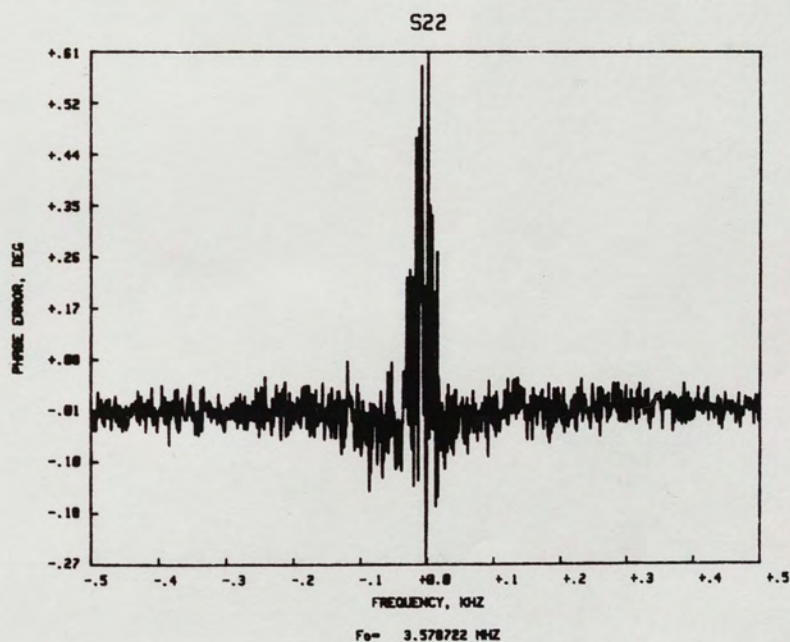


Figure 64. S<sub>22</sub> Phase Error Plot of Device J69 with N=1024

For  $N=1024$ , the error range in Figure 64 is from  $-0.27$  degrees to  $+0.61$  degrees, again with error increases slightly before and after resonant frequency (see Figure 32).

Table 3 shows the maximum errors and their locations as previously discussed for each measurement.



TABLE 3  
MAXIMUM ERRORS

Device	Parameter	Method	N	Maximum	Occurrence
1. F83	S <sub>21</sub> - Magnitude	Dump the Screen	401	+0.04 dB	Higher Freq., Mag. decr.
2. F83	S <sub>21</sub> - Phase	Dump the Screen	401	+0.19 deg	Sl. Above Res., Hi Phase Slope
3. F83	S <sub>21</sub> - Magnitude	Define N	401	+0.03 dB	Higher Freq., Mag. decr.
4. F83	S <sub>21</sub> - Phase	Define N	401	+0.30 deg	Higher Freq., Phase -> -90°
5. F83	S <sub>21</sub> - Magnitude	Define Df	512	-0.05 dB	Higher Freq., Mag. decr.
6. F83	S <sub>21</sub> - Phase	Define Df	512	+0.20 deg	Higher Freq., Phase -> -90°
7. F83	S <sub>12</sub> - Magnitude	Define Df	512	-0.03 dB	Higher Freq., Mag. decr.
8. F83	S <sub>12</sub> - Phase	Define Df	512	+0.18 deg	Sl. Above Res., Hi Phase Slope
9. F83	S <sub>12</sub> - Magnitude	Define Df	512	+0.03 dB	Higher Freq., Mag. decr.
10. F83	S <sub>12</sub> - Phase	Define Df	512	+0.23 deg	Higher Freq., Phase -> -90°
11. J69	S <sub>12</sub> - Magnitude	Define Df	512	+/-0.08 dB	Lo&Hi Freq., Mag. decr.
12. J69	S <sub>12</sub> - Phase	Define Df	512	-0.62 deg	Lower Freq., Phase -> 90°
13. J69	S <sub>12</sub> - Magnitude	Define Df	512	+0.09 dB	Higher Freq., Mag. decr.
14. J69	S <sub>12</sub> - Phase	Define Df	512	-0.63 deg	Higher Freq., Phase -> -90°
15. F83	S <sub>11</sub> - Magnitude	Define Df	512	-0.09 dB	Sl. Below Res., Hi Mag. Slope
16. F83	S <sub>11</sub> - Phase	Define Df	512	-0.54 deg	Sl. Below Res., Hi Phase Slope
17. F83	S <sub>11</sub> - Magnitude	Define Df	512	+0.05 dB	Sl. Below Res., Hi Mag. Slope
18. F83	S <sub>11</sub> - Phase	Define Df	512	-0.37 deg	Sl. Above Res., Hi Phase Slope
19. J69	S <sub>11</sub> - Magnitude	Define Df	512	+0.08 dB	Sl. Above Res., Hi Mag. Slope
20. J69	S <sub>11</sub> - Phase	Define Df	512	+0.80 deg	Res. Freq., Hi Phase Slope
21. J69	S <sub>11</sub> - Magnitude	Define Df	512	-0.06 dB	Sl. Below Res., Hi Mag. Slope
22. J69	S <sub>11</sub> - Phase	Define Df	512	+0.77 deg	Sl. Below Res., Hi Phase Slope
23. J69	S <sub>22</sub> - Magnitude	Define N	401	+0.09 dB	Sl. Above Res., Hi Mag. Slope
24. J69	S <sub>22</sub> - Phase	Define N	401	+0.78 deg	Sl. Below Res., Hi Phase Slope
25. J69	S <sub>22</sub> - Magnitude	Define N	1024	-0.09 dB	Sl. Below Res., Hi Mag. Slope
26. J69	S <sub>22</sub> - Phase	Define N	1024	+0.61 deg	Sl. Above Res., Hi Phase Slope

## DISCUSSION AND CONCLUSION

### Resonators

A resonator is a device which allows the greatest flow of current at a certain frequency. In a quartz crystal resonator, a thin flat piece of quartz is placed between two electrodes. If an alternating electric signal is applied to these electrodes, the piezoelectric properties of quartz will cause the quartz to vibrate. When the frequency of this electric signal is very near the mechanical resonance of the quartz slab, the amplitude of the vibrations become very large. The strain of these vibrations causes the quartz to produce a sinusoidal electric field which controls the effective impedance between the two electrodes. This impedance then possesses a very high  $Q$  [1].

The  $Q$ , or quality factor, is defined by the equation

$$Q = \frac{f_o}{B} ,$$

where  $f_o$  is the frequency of resonance and  $B$  is the bandwidth where the magnitude is  $1/\sqrt{2}$  times the resonant magnitude [7]. From Figure 9, the  $Q$  of device F83 is approximately 16,000 and from Figure 14, the  $Q$  of device J69 is approximately 36,000.



### Error Sources

When considering errors there are several possible sources. Systematic, random, drift, and operator errors can all cause deviations in magnitude and phase measurement results between sweeps [8]. These are discussed in the section to follow herein.

### Discussion of Results

As can be seen from Table 2, when comparing methods of data acquisition in items 1-8, the magnitude at resonance showed the same percent difference. When the magnitude ranges were compared, the "Define the Delta Frequency" method had a somewhat smaller percent difference when compared to the "Dump the Screen" method than did the "Define the Number of Data Points" method. The phase at resonance and phase range also had smaller percent differences when comparing the "Define the Delta Frequency" method to the "Dump the Screen" method. All error sources can combine to cause differences between measurements, however the most probable cause of discrepancy between methods of data acquisition is systematic error. The degree to which residual systematic errors remaining after calibration/normalization combine is affected by the measurement method [8].

From items 9-16 of Table 2 one can compare consecutive runs measuring  $S_{12}$ . The magnitude at resonance had the same percent difference for consecutive runs on the two devices while the magnitude and phase ranges had a smaller percent difference for device J69. The phase at resonance had a smaller percent difference between runs for device F83. From items 17-24 of Table 2 one can compare consecutive runs measuring  $S_{11}$ . The magnitude at resonance, magnitude range and phase range had smaller percent differences between consecutive runs for device J69 while the phase at resonance had a smaller percent difference between runs for device F83. Errors due to temperature drift can cause differences between measurement sweeps. Frequency drift is caused by the device under test while instrumentation drift is caused by the thermal expansion characteristics of the interconnecting cables within the test set [8].

From items 25-28 of Table 2, one can compare the results of runs made with a varying number of data points. The percent differences between runs made defining  $N$  to be 401 and then 1024 were approximately a fourth of one percent with exception of the phase at resonance which did not differ at all. Accuracy and smoothness of the trace are dependent upon sweep resolution.



One would expect discrepancies between measurements utilizing sweep resolutions of different sizes, especially one being over two and a half times larger than the other.

In Table 3 the maximum errors are summarized. From items 1-6 one can compare the  $S_{21}$  errors of different data acquisition methods. The "Define the Number of Data Points" method had the smallest magnitude error while the "Dump the Screen" method had the smallest phase error. Most of the  $S_{21}$  errors occurred when the magnitude was small and as the phase approached  $-90^\circ$ . None of the errors, however, are outside the network analyzer specifications (see Appendix A) of  $\pm 0.15$  decibels and  $\pm 2.0$  degrees. From items 7-14 of Table 3 one can compare the errors of the two devices when measuring  $S_{12}$ . The magnitude and phase errors were smaller for device F83. Again, most of the  $S_{12}$  errors occurred when the magnitude was small and as the phase approached  $-90^\circ$ . While errors are within specifications, all errors can combine and it is sometimes difficult to single out one specific source. Residual systematic errors remaining after calibration/normalization result from the imperfections in the calibration standards, the connector interface, the interconnecting cables and the instrumentation [8]. It may be noted that the default resolution bandwidth is the maximum at 1 kHz and thus the pre-sweep settling time is minimum at 22 ms. Reduction in bandwidth



would lower the noise floor and result in an increase in settling time. This however would necessitate a longer sweep or sample time for more accurate results [4].

When measuring  $S_{11}$  (items 15-22) the magnitude errors were comparably the same for both devices while the phase errors were smaller for device F83. All of the  $S_{11}$  errors occurred at or near resonance where the change in magnitude and phase was great over a small frequency range. Again, all errors were within specifications. It appears that a frequency drift has taken place. If a drift to the left occurred in device F83 between measurement sweeps the magnitude errors would be positive during pre-resonance and negative during post-resonance. The phase errors would be positive before resonance, become negative immediately before and after resonance and then become positive again. This can be observed in figures 53 to 56. If a frequency drift to the right occurred in device J69 the magnitude errors would be negative during pre-resonance and positive during post-resonance. The phase errors would be positive during pre-resonance and negative during post-resonance. This can be observed in figures 57 to 60.

From items 23 to 26 of Table 3, one can compare the errors when runs are made with different values for  $N$ , the number of data points. The magnitude errors were the same for  $N$  equaling 401 and 1024. The phase error was somewhat



smaller for  $N=1024$ . All of the  $S_{22}$  errors occurred near resonance where the change in magnitude and phase was great over a small range of frequency. All errors were within specifications, however as with the  $S_{11}$  measurements, the second measurement sweep of device J69 appears to have drifted to the right.

Observe from Table 3 that the maximum magnitude error ranged from  $-0.09$  dB to  $+0.09$  dB and the maximum phase error ranged from  $-0.63$  degrees to  $+0.78$  degrees. These results are more than 50% better than the specifications given for the network analyzer, however these errors still bound the accuracy of measurement results and must be taken into consideration.

As noted from figures 34 to 38, measurements of the SAW device were taken in the frequency domain and successfully transformed via a separate computer program into the time domain thus giving greater dynamic range and accuracy.

Problems encountered during the development of the computer program stemmed mainly from its size. The author would have liked to calibrate all of the scattering parameters rather than calibrating one and normalizing the remaining three. The author would also have liked to make corrections for the errors incurred in the measurements.

In summary, a program was written which offers the advantages of a choice of data acquisition method, option of a greater number of sample frequencies, permanent record of results, error analysis, and storage of data for future manipulation. With these advantages the program overcomes many of the limitations encountered using only the analyzer instrumentation for device testing.



## APPENDICES

APPENDIX A

SPECIFICATIONS FOR THE HP 3577A AND THE HP 35677A

See reference 4



HP 3577A

## Magnitude Characteristics

Range: Maximum Input Level to Sensitivity.

Resolution: 0.001 dB (log); 5 digits (linear).

Accuracy (at 100 kHz, 25°C, and Maximum Input Level):  
+/- 0.15 dB (50 Ohms)

Accuracy and frequency response errors, and effects of different input attenuation can be calibrated out with normalization.

## Dynamic Accuracy:

Input Level Relative to Maximum Allowable	Error
0 dB to -10 dB	+/- 0.04 dB
-10 dB to -50 dB	+/- 0.02 dB
-50 dB to -60 dB	+/- 0.05 dB
-60 dB to -80 dB	+/- 0.15 dB
-80 dB to -90 dB	+/- 0.75 dB
-90 dB to -100 dB	+/- 0.75 dB

Frequency Response: Specifications apply when inputs are driven from a 50 Ohm source impedance

Frequency	Error
20 Hz to 20 MHz	0.3 dBpp
5 Hz to 200 MHz	0.4 dBpp
5 Hz to 200 MHz	-----

## Phase Characteristics

Range: +/- 180 degrees.

Resolution: 0.005 deg (0.0001 rad).

Accuracy (at 100 kHz, 25°C, and Maximum Input Level):  
+/- 2.0 deg.

Accuracy and frequency response errors, and effects of different input attenuation can be calibrated out with normalization.

Dynamic Accuracy:

Input Level Relative to Maximum Allowable	Error
0 dB to -10 dB	+/- 0.4 deg
-10 dB to -50 dB	+/- 0.2 deg
-50 dB to -60 dB	+/- 0.5 deg
-60 dB to -80 dB	+/- 1.5 deg
-80 dB to -90 dB	+/- 7.5 deg
-90 dB to -100 dB	+/- .75 deg

Frequency Response: Specifications apply when inputs are driven from a 50 Ohm source impedance

Frequency	Error
20 Hz to 20 MHz	2 deg pp
5 Hz to 200 MHz	10 deg pp
5 Hz to 200 MHz	-----

HP 35677A

Frequency Range: 100 kHz to 200 MHz

Test Port Impedance: 50 Ohms

Frequency Response:

Transmission ( $S_{21}$ ,  $S_{12}$ ): +/- 1 dB, +/- 5 deg.

Reflection ( $S_{11}$ ,  $S_{22}$ ): +/- 1 dB, +/- 5 deg.



## APPENDIX B

### DERIVATION OF $S_{11}$ CALIBRATION EQUATION

See references 3 and 9

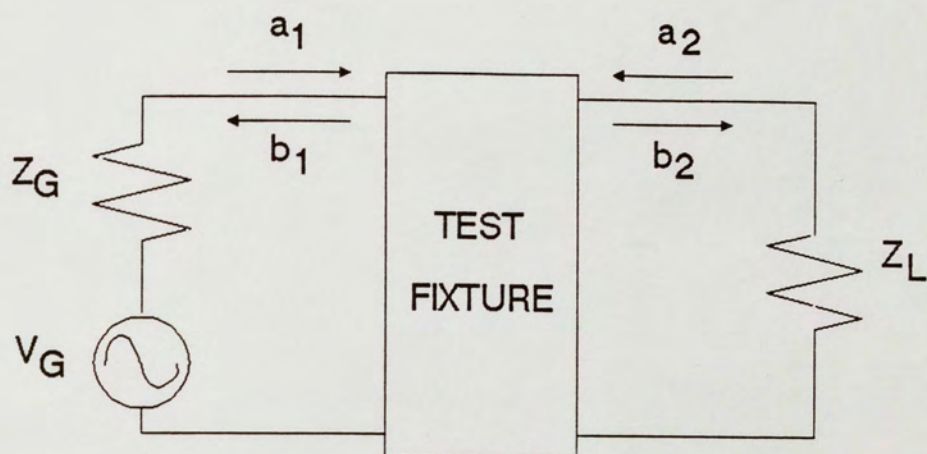


Figure 65. Diagram of a Two Port Network

The scattering parameters of the one-port network of Figure 65 are defined by the following equations:

$$b_1 = S_{11}a_1 + S_{12}a_2 \quad (1)$$

$$b_2 = S_{21}a_1 + S_{22}a_2 \quad (2)$$

To find the equation for the corrected value of the input reflection,  $S_{11}$ , first solve equation (2) for  $a_2/a_1$ .

$$\frac{b_2}{a_2} = S_{21} \frac{a_1}{a_2} + S_{22}$$

$$\frac{\frac{b_2}{a_2} - S_{22}}{S_{21}} = \frac{a_1}{a_2}$$



or

$$\frac{a_2}{a_1} = \frac{S_{21}}{\frac{b_2}{a_2} - S_{22}} \quad (3)$$

Now solve equation (1) for  $b_1/a_1$  then substitute the value of  $a_2/a_1$  from equation (3)

$$\frac{b_1}{a_1} = S_{11} + S_{12} \frac{a_2}{a_1} \quad (4)$$

$$\frac{b_1}{a_1} = S_{11} + \frac{S_{12} S_{21}}{\frac{b_2}{a_2} - S_{22}} \quad (5)$$

For calibration, let  $Z_L$  of Figure 65 be equal to a known impedance. Then, since all the power is absorbed and there is no reflection,  $a_2$  will equal zero and so equation (4) becomes

$$\frac{b_1}{a_1} = S_{11}$$

For this case, let

$$\frac{b_1}{a_1} = \Gamma_t = e_{00}$$

where  $\Gamma_t$  is measured with the load in place. Next, let  $Z_L=0$  as when replaced by a short. Then  $a_2/b_2=-1$  due to a 180 degree phase shift. Substituting, equation (5) becomes

$$\frac{b_1}{a_1} = S_{11} + \frac{S_{12} S_{21}}{-1 - S_{22}}$$

or

$$\frac{b_1}{a_1} = S_{11} - \frac{S_{12}S_{21}}{1 + S_{22}} \quad (6)$$

Let two additional error terms be defined as  $e_{01}=S_{12}S_{21}$  and  $e_{11}=S_{22}$ . Then let  $\Gamma_s=b_1/a_1$  for the measured value when the short is in place. Equation (6) then becomes

$$\Gamma_s = e_{00} - \frac{e_{01}}{1 + e_{11}} \quad (7)$$

Finally, replace the short with an open. Then, with no phase shift,  $a_2/b_2=1$  and substituting, equation (5) becomes

$$\frac{b_1}{a_1} = S_{11} + \frac{S_{12}S_{21}}{1 - S_{22}} \quad (8)$$

Using the error terms and defining  $\Gamma_o=b_1/a_1$  as the measured value when the open is in place, equation (8) becomes

$$\Gamma_o = e_{00} + \frac{e_{01}}{1 - e_{11}} \quad (9)$$

The error terms can be found from equations (7) and (9). Remembering that  $\Gamma_i = e_{00}$ , from equation (7)

$$\Gamma_i - \Gamma_s = \frac{e_{01}}{1 + e_{11}}$$

$$e_{01} = (\Gamma_i - \Gamma_s)(1 + e_{11}) \quad (10)$$



Substitute this value for  $e_{01}$  into equation (9)

$$\Gamma_o - \Gamma_t = \frac{(\Gamma_t - \Gamma_s)(1 + e_{11})}{(1 - e_{11})}$$

$$(\Gamma_o - \Gamma_t)(1 - e_{11}) = (\Gamma_t - \Gamma_s)(1 + e_{11})$$

$$\Gamma_o - \Gamma_t - e_{11}\Gamma_o + e_{11}\Gamma_t = \Gamma_t - \Gamma_s + e_{11}\Gamma_t - e_{11}\Gamma_s$$

$$e_{11}(\Gamma_s - \Gamma_o) = 2\Gamma_t - \Gamma_s - \Gamma_o$$

$$e_{11} = \frac{2\Gamma_t - \Gamma_s - \Gamma_o}{\Gamma_s - \Gamma_o} \quad (11)$$

Replace  $e_{11}$  in equation (10) with equation (11)

$$e_{01} = (\Gamma_t - \Gamma_s) \left( 1 + \frac{2\Gamma_t - \Gamma_s - \Gamma_o}{\Gamma_s - \Gamma_o} \right)$$

$$e_{01} = (\Gamma_t - \Gamma_s) \left( \frac{\Gamma_s - \Gamma_o + 2\Gamma_t - \Gamma_s - \Gamma_o}{\Gamma_s - \Gamma_o} \right)$$

$$e_{01} = \frac{(\Gamma_t - \Gamma_s)(2\Gamma_t - 2\Gamma_o)}{\Gamma_s - \Gamma_o} \quad (12)$$

With the test device in place  $a_2/b_2 = S_{11}$  and equation (5) becomes

$$\frac{b_1}{a_1} = e_{00} + \frac{e_{01}}{\frac{1}{S_{11}} - e_{11}}$$

$$\frac{b_1}{a_1} = e_{00} + \frac{S_{11}e_{01}}{1 - S_{11}e_{11}} \quad (13)$$

Here let  $b_1/a_1 = M_{meas}$  then solve equation (13) for  $S_{11}$

$$M_{meas}(1 - S_{11}e_{11}) = e_{00}(1 - S_{11}e_{11}) + S_{11}e_{01}$$

$$M_{meas}S_{11}e_{11} - S_{11}e_{11}e_{00} + S_{11}e_{01} = M_{meas} - e_{00}$$

$$S_{11} = \frac{M_{meas} - e_{00}}{M_{meas}e_{11} - e_{11}e_{00} + e_{01}} \quad (14)$$

Substitute the values for the error terms

$$S_{11} = \frac{M_{meas} - \Gamma_t}{M_{meas}\left(\frac{2\Gamma_t - \Gamma_s - \Gamma_o}{\Gamma_s - \Gamma_o}\right) - \left(\frac{2\Gamma_t - \Gamma_s - \Gamma_o}{\Gamma_s - \Gamma_o}\right)\Gamma_t + \frac{(\Gamma_t - \Gamma_s)(2\Gamma_t - 2\Gamma_o)}{\Gamma_s - \Gamma_o}}$$

$$S_{11} = \frac{M_{meas} - \Gamma_t}{M_{meas}\left(\frac{2\Gamma_t - \Gamma_s - \Gamma_o}{\Gamma_s - \Gamma_o}\right) + \left(\frac{-2\Gamma_t^2 + \Gamma_s\Gamma_t + \Gamma_o\Gamma_t + 2\Gamma_t^2 - 2\Gamma_o\Gamma_t - 2\Gamma_s\Gamma_t + 2\Gamma_s\Gamma_o}{\Gamma_s - \Gamma_o}\right)}$$

$$S_{11} = \frac{M_{meas} - \Gamma_t}{M_{meas}\left(\frac{2\Gamma_t - \Gamma_s - \Gamma_o}{\Gamma_s - \Gamma_o}\right) + \left(\frac{2\Gamma_s\Gamma_o - \Gamma_t(\Gamma_s + \Gamma_o)}{\Gamma_s - \Gamma_o}\right)} \quad (15)$$

Letting the factor for source match be



$$S_f = \frac{2\Gamma_t - \Gamma_s - \Gamma_o}{\Gamma_s - \Gamma_o}$$

the correction factor for directivity be

$$D = \Gamma_t$$

and the correction factor for transmission be

$$T_f = \frac{2\Gamma_s\Gamma_o - \Gamma_t(\Gamma_s + \Gamma_o)}{\Gamma_s - \Gamma_o}$$

Then equation (15) can be written more simply as

$$S_{11} = \frac{M_{meas} - D}{M_{meas} S_f + T_f} \quad (16)$$

APPENDIX C

COMPUTER LISTING FOR "SCAT"



```

10 ! UNIVERSITY OF CENTRAL FLORIDA
20 ! DEPARTMENT OF ELECTRICAL ENGINEERING AND COMMUNICATION SCIENCES
30 ! SPRING, SUMMER, AND FALL TERMS, 1987
40 ! SALLIE LAYTON DOUGLAS
50 !
60 ! REMOTE DATA ACQUISITION AND SYSTEMATIC ERROR ANALYSIS
70 !
80 ! MEASUREMENT SETUP
90 OPTION BASE 1
100 !SETS LOWER BOUND FOR DIMENSIONING
110 ! ARRAYS AT 1 RATHER THAN 0
120 INPUT "Hardkey=SPCL FCTN, Softkey=TALKONLY OFF. Press CONT.",Y
130 ! THE HP 3577A MUST BE ABLE TO TALK AND LISTEN TO BE OPERATED REMOTELY.
140 REMOTE 711 !SWITCHES CONTROL OF THE HP 3577A
150 ! FROM LOCAL TO REMOTE
160 DIM A(1024),B(1024),C(1024),D(1024),E(1024),Dn(1024),En(1024),F(1024)
170 DIM G(1024),H(1024),M(1024),N(1024),O(1024),P(1024),Q(1024),R(1024)
180 OUTPUT 711;"IPR;" !INSTRUMENT PRESET
190 INPUT "Start frequency = ? Enter in MHz then press CONT.",Afreq
200 OUTPUT 711;"FRA;"Afreq,"MHZ;" !START FREQUENCY
210 Y=(Afreq=0) !CHECK START FREQUENCY
220 IF Y THEN GOTO 250 !IF ZERO, THEN GO TO FILL THE
230 ! FIRST VALUES OF THE ARRAYS USED
240 GOTO 310 ! WITH S21 FOR FFT ON SAW DEVICE
250 Dn(1)=0 !ELSE, CONTINUE
260 En(1)=0
270 B(1)=-100
280 C(1)=0
290 Ii=2
300 GOTO 320 !SET ARRAY START VARIABLE AT 2
310 Ii=1 !CONTINUE
320 INPUT "Stop frequency = ? Enter in MHz then press CONT.",Bfreq
330 OUTPUT 711;"FRB;"Bfreq,"MHZ;" !STOP FREQUENCY
340 INPUT "Source output signal level = ? Enter in dBm then press CONT.",Amp
350 OUTPUT 711;"AMP;"Amp,"DBM;" !AMPLITUDE
360 OUTPUT 711;"DSF;"TR2;DF5;" !DISPLAY TRACE 2, DEFINE AS PHASE
370 OUTPUT 711;"TR1;" !TURN TRACE 1 BACK ON (DEFAULT
380 GOSUB 7120 ! FUNCTION FOR TR 1 IS LOG. MAG.)
390 REDIM A(N),B(N),C(N),D(N),E(N),Dn(N),En(N),F(N) !GOTO DATA ACQUISITION METHOD SUBR.
400 REDIM G(N),H(N),M(N),N(N),O(N),P(N),Q(N),R(N)
410 E=0
420 INPUT "Do you want dual sweeps for system error checks?"X$
430 IF X$="N" THEN GOTO 460
440 IF X$="Y" THEN GOTO 450
450 E=1
460 ! MEASUREMENT SETUP COMPLETE
470 INPUT "Setup complete. Press CONT.",Y
480 INPUT "Do you want to measure S21?"X$
490 IF X$="N" THEN GOTO 570
500 IF X$="Y" THEN GOTO 510
510 ! MEASUREMENT OF S21; FORWARD GAIN AND PHASE
520 S=1
530 GOSUB 8040 !SET S PARAMETER FLAG TO 1
540 !GO TO CALIBRATION SUBROUTINE
550 GOSUB 950 ! TO NORMALIZE WITH THE "THRU"
560 INPUT "Measurement of S21 complete. Press CONT for S12.",Y
570 INPUT "Do you want to measure S12 ?"X$
580 IF X$="N" THEN GOTO 670
590 IF X$="Y" THEN GOTO 600
600 ! MEASUREMENT OF S12; REVERSE LOSS AND REVERSE PHASE ANGLE
610 S=2
620 OUTPUT 711;"I12;TR2;I12;TR1;" !INPUT = S12 FOR BOTH TRACES
630 GOSUB 8040 !GO TO CALIBRATION SUBROUTINE
640 ! TO NORMALIZE WITH THE "THRU"
650 GOSUB 950 !GO TO TAKE DATA FROM THE DUT
660 INPUT "Measurement of S12 complete. Press CONT for S11.",Y
670 INPUT "Do you want to measure S11 ?"X$
680 IF X$="N" THEN GOTO 810
690 IF X$="Y" THEN GOTO 700
700 ! MEASUREMENT OF S11; INPUT RETURN LOSS AND CORRESPONDING PHASE
710 S=3 !SET S PARAMETER FLAG TO 3

```



[illegible]



```

1440      ! NOW CALIBRATED
1450      MAT C=R      !THE PHASE ARRAY, C, IS
1460      ! NOW CALIBRATED
1470      PRINT "MAGNITUDE,dB:"
1480      MAT PRINT B      !PRINT MAGNITUDE ARRAY
1490      PRINT "PHASE,deg:"
1500      MAT PRINT C      !PRINT PHASE ARRAY
1510      INPUT "Do you want a print-out of these ?",X$
1520      IF X$="N" THEN GOTO 1800
1530      IF X$="Y" THEN GOTO 1540
1540      PRINTER IS O      !RE-DEFINES THE PRINTER AS THE
1550      ! 9834B PAPER PRINTER
1560      ! CHECK THE S PARAMETER FLAGS
1570      Y=(S=1)
1580      IF Y THEN PRINT "S21"
1590      Y=(S=2)
1600      IF Y THEN PRINT "S12"
1610      Y=(S=3)
1620      IF Y THEN PRINT "S21"
1630      Y=(S=4)
1640      IF Y THEN PRINT "S22"
1650      Y=(Rp=1)      !CHECK THE ERROR RUN
1660      ! "PRINT/PLOT" FLAG
1670      IF Y THEN PRINT "DUAL SWEEP ERROR"
1680      PRINT "MAGNITUDE,dB:"
1690      PRINT " "
1700      MAT PRINT B
1710      PRINT " "
1720      Y=(Rp=1)      !CHECK THE ERROR RUN
1730      ! "PRINT/PLOT" FLAG
1740      IF Y THEN PRINT "DUAL SWEEP ERROR"
1750      PRINT "PHASE,deg.:"
1760      PRINT " "
1770      MAT PRINT C
1780      PRINT IS 16      !REDEFINES THE PRINTER TO
1790      ! BE THE 9845B SCREEN
1800      INPUT "Do you want a normalized plot of these? Y or N then CONT.",X$
1810      IF X$="Y" THEN GOTO 1920
1820      IF X$="N" THEN GOTO 1830
1830      Y=(Rp=1)      !CHECK THE ERROR RUN
1840      ! "PRINT/PLOT" FLAG
1850      IF Y THEN RETURN      !IF SET, RETURN TO CONTINUE WITH
1860      ! NEXT S PARAMETER
1870      Y=(E=0)      !CHECK THE ERROR RUN FLAG
1880      IF Y THEN RETURN      !IF NOT SET, RETURN TO CONTINUE
1890      ! WITH NEXT S PARAMETER
1900      GOTO 2130      !ELSE, GO TO FIND ERROR BETWEEN
1910      ! THE TWO SWEEPS
1920      ! NOW PREPARE TO GO TO PLOTTING SUBROUTINE
1930      MAT A=B      !ENTER MAGNITUDE ARRAY, B, INTO
1940      ! PLOT ARRAY, A
1950      R=0      !PRESET PLOT "ONCE THROUGH" FLAG
1960      Xmin=Afreq      !DEFINES MINIMUM FREQUENCY FOR THE
1970      ! LOWER END OF THE HORIZONTAL AXIS
1980      Xmax=Bfreq      !DEFINES MAXIMUM FREQUENCY FOR THE
1990      ! UPPER END OF THE HORIZONTAL AXIS
2000      Imin=1      !DEFINES MINIMUM AMPLITUDE FOR THE
2010      ! LOWER END OF THE VERTICAL AXIS
2020      Imax=N      !DEFINES MAXIMUM AMPLITUDE FOR THE
2030      ! UPPER END OF THE VERTICAL AXIS
2040      GOSUB Max_min      !GO TO THE Max_min SUBROUTINE
2050      ! WHICH FINDS Imax AND Imin
2060      GOSUB Plot      !GO TO THE Plot SUBROUTINE
2070      Y=(R=1)      !CHECK THE PLOT "ONCE THROUGH" FLAG
2080      IF Y THEN GOTO 2100      !IF SET, CONTINUE
2090      GOTO 2300      !ELSE, GOTO PLOT ARRAY C
2100      Y=(E=1)      !CHECK ERROR RUN FLAG
2110      IF Y THEN GOTO 2130      !IF SET, CONTINUE
2120      RETURN      !ELSE, RETURN
2130      Y=(Rp=1)      !CHECK ERROR RUN "PRINT/PLOT" FLAG
2140      IF Y THEN GOTO 2120      !IF SET, GO TO RETURN COMMAND
2150      MAT B=M-B      !ELSE, SUBTRACT (dB) THE SECOND

```

```

2160
2170 MAT C=N-C
2180
2190 MAT E=C
2200 GOSUB 12480
2210 MAT C=E
2220
2230 PRINT "DUAL SWEEP MAGNITUDE ERROR, dB"
2240 WAIT 2000
2250 MAT PRINT B
2260 PRINT "DUAL SWEEP PHASE ERROR, DEGREES"
2270 MAT PRINT C
2280 Rp=1
2290 GOTO 1510
2300 MAT A=C
2310
2320 R=1
2330 GOTO 1960
2340 !
2350 ! THIS SECTION (FROM "DEFINE N") MEASURES THE HP 3577A SCREEN VALUE
2360 ! FOR EACH DATA POINT
2370 Re=0
2380
2390 Rp=0
2400
2410 DISP "Please wait. Measurements are being taken."
2420 OUTPUT 711;"ST5;"
2430 Xmin=Afreq
2440
2450
2460 FOR I=1 TO N
2470     OUTPUT 711 USING 2480;Afreq
2480     IMAGE "SFR;","DDD.DDDDD","MHZ;"
2490
2500
2510     OUTPUT 711;"TKM;FM1;DM1;"
2520
2530
2540     ENTER 711;B(I)
2550     OUTPUT 711;"TKM;FM1;DM2;"
2560
2570
2580     ENTER 711;C(I)
2590     Afreq=Afreq+Df
2600
2610
2620 NEXT I
2630 Afreq=Xmin
2640 MAT D=B
2650
2660 MAT E=C
2670 Y=(S=3)
2680 IF Y THEN GOTO 2730
2690
2700 MAT Q=D-Dn
2710 MAT R=E-En
2720 GOTO 2760
2730 GOSUB 11900
2740
2750
2760 MAT E=R
2770
2780 GOSUB 12480
2790
2800 MAT R=E
2810
2820 Y=(E=1)
2830 IF Y THEN GOTO 2850
2840 GOTO 2920
2850 Y=(Re=0)
2860 IF Y THEN GOTO 2880
2870 GOTO 2920

! SWEEP FROM THE FIRST; MAGNITUDE
! SUBTRACT (DEGREES) THE SECOND
! SWEEP FROM THE FIRST; PHASE
! LOAD PHASE ERROR ARRAY, C
! GO TO CHECK FOR 360 DEGREE SHIFT
! RELOAD PHASE ERROR ARRAY, C, WITH
! CORRECTED PHASE ARRAY,E

! SET ERROR RUN "PRINT/PLOT" FLAG
! GOTO OFFER PRINT-OUT OF THE ERRORS
! ELSE, ENTER PHASE ARRAY, C, INTO
! PLOT ARRAY, A
! SET PLOT "ONCE THROUGH" FLAG
! GO TO PLOT AGAIN

! PRESET ERROR RUN "ONCE
! THROUGH" FLAG
! PRESET ERROR RUN "PRINT/PLOT"
! FLAG

! SET SWEEP TYPE TO CONTINUOUS WAVE
! DEFINES MINIMUM FREQUENCY FOR THE
! LOWER END OF THE HORIZONTAL AXIS
! (AND SAVES ORIGINAL VALUE)

! SOURCE FREQUENCY STARTS AT
! DEFINED START FREQUENCY AND
! IS ACCURATE TO THE HERTZ
! TAKE MEASUREMENT, PUT IN ASCII
! FORM, AND DUMP THE MARKER FROM
! TRACE 1 (MAGNITUDE)
! ENTER DATA INTO MAGNITUDE ARRAY, B
! TAKE MEASUREMENT, PUT IN ASCII
! FORM AND DUMP THE MARKER FROM
! TRACE 2 (PHASE)
! ENTER DATA INTO PHASE ARRAY, C
! INCREMENT FREQUENCY BY THE DELTA
! FREQUENCY.THIS WAS CALCULATED
! WHEN THE VALUE OF N WAS DEFINED
! ELSE, CONTINUE
! RESET START FREQUENCY
! IN PREPARATION FOR MATH, LOAD
! MAGNITUDE ARRAY, B, INTO ARRAY D
! AND PHASE ARRAY, C, INTO ARRAY E
! CHECK THE S11 FLAG
! IF SET, SKIP THE FOLLOWING TWO
! LINES OF MATH
! SUBTRACT (dB) CALIBRATION ARRAY
! SUBTRACT (PHASE) CALIBRATION ARRAY
! GO TO CHECK FOR PHASE SHIFT
! GO TO THE END OF ONE PART FULL
! CALIBRATION SUBROUTINE TO FIND
! THE CALIBRATED MEASUREMENT
! LOAD CALIBRATED PHASE ARRAY, R
! INTO ARRAY E
! GO TO CHECK FOR 360 DEGREE
! PHASE SHIFT
! RELOAD ARRAY R WITH CORRECTED
! PHASE ARRAY
! CHECK ERROR RUN FLAG
! IF SET, CONTINUE
! ELSE, GO TO LOAD ARRAYS B AND C
! CHECK ERROR RUN "ONCE THROUGH" FLAG
! IF NOT SET GO TO STORE FIRST SWEEP
! IF SET, CONTINUE

```



```

2880 MAT M=Q
2890 MAT N=R
2900 Re=1
2910 GOTO 2410
2920 MAT B=Q
2930
2940 MAT C=R
2950 PRINT "MAGNITUDE,dB:"
2960 MAT PRINT B
2970 PRINT "PHASE,deg:"
2980 MAT PRINT C
2990 INPUT "Do you want a print-out of these? ",X$
3000 IF X$="N" THEN GOTO 3280
3010 IF X$="Y" THEN GOTO 3020
3020 PRINTER IS 0
3030
3040 ! CHECK THE S PARAMETER FLAGS
3050 Y=(S=1)
3060 IF Y THEN PRINT "S21"
3070 Y=(S=2)
3080 IF Y THEN PRINT "S12"
3090 Y=(S=3)
3100 IF Y THEN PRINT "S11"
3110 Y=(S=4)
3120 IF Y THEN PRINT "S22"
3130 Y=(Rp=1)
3140
3150 IF Y THEN PRINT "DUAL SWEEP ERROR"
3160 PRINT "MAGNITUDE,dB:"
3170 PRINT " "
3180 MAT PRINT B
3190 PRINT " "
3200 Y=(Rp=1)
3210
3220 IF Y THEN PRINT "DUAL SWEEP ERROR"
3230 PRINT "PHASE,deg:"
3240 PRINT " "
3250 MAT PRINT C
3260 PRINTER IS 16
3270
3280 INPUT "Do you want a normalized plot of these? Y or N then CONT.",X$
3290 IF X$="Y" THEN GOTO 3390
3300 IF X$="N" THEN GOTO 3310
3310 Y=(Rp=1)
3320 IF Y THEN RETURN
3330
3340 Y=(E=0)
3350 IF Y THEN RETURN
3360
3370 GOTO 3610
3380
3390 ! PREPARE TO GO TO PLOTTING SUBROUTINE
3400 R=0
3410 MAT A=B
3420
3430 Xmin=Afreq
3440
3450 Xmax=Bfreq
3460
3470 Imin=1
3480
3490 Imax=N
3500
3510 GOSUB Max_min
3520
3530 GOSUB Plot
3540 Y=(R=1)
3550 IF Y THEN GOTO 3570
3560 GOTO 3780
3570 Y=(E=1)
3580 IF Y THEN GOTO 3610
3590 RETURN

!STORE FIRST MAGNITUDE SWEEP
!STORE FIRST PHASE SWEEP
!SET ERROR RUN "ONCE THROUGH" FLAG
!GO TO TAKE SECOND SWEEP
!MAGNITUDE ARRAY, B, IS NOW
! CALIBRATED
!PHASE ARRAY, C, IS NOW CALIBRATED

!PRINT THE MAGNITUDE ARRAY

!PRINT THE PHASE ARRAY

!REDEFINE THE PRINTER TO
! PRINT ON THE 9845B PAPER

!CHECK THE ERROR RUN
! "PRINT/PLOT" FLAG

!PRINT MAGNITUDE ARRAY

!CHECK THE ERROR RUN
! "PRINT/PLOT" FLAG

!PRINT PHASE ARRAY
!REDEFINE THE PRINTER TO BE
! THE 9845B SCREEN

!CHECK ERROR RUN "PRINT/PLOT" FLAG
!IF SET, RETURN TO CONTINUE WITH
! THE NEXT S PARAMETER
!CHECK THE ERROR RUN FLAG
!IF NOT SET, RETURN TO CONTINUE
! WITH THE NEXT S PARAMETER
!ELSE GO TO FIND THE ERROR
! IN THE TWO SWEEPS

!PRESET PLOT "ONCE THROUGH" FLAG
!ENTER MAGNITUDE ARRAY, B, INTO
! PLOT ARRAY, A
!DEFINES MINIMUM FREQUENCY FOR THE
! LOWER END OF HORIZONTAL AXIS
!DEFINES MAXIMUM FREQUENCY FOR THE
! UPPER END OF THE HORIZONTAL AXIS
!DEFINES MINIMUM AMPLITUDE FOR THE
! LOWER END OF THE VERTICAL AXIS
!DEFINES MAXIMUM AMPLITUDE FOR THE
!UPPER END OF THE VERTICAL AXIS
!GO TO THE Max_min SUBROUTINE
! TO FIND Imax AND Imin
!GO TO THE Plot SUBROUTINE
!CHECK THE PLOT "ONCE THROUGH" FLAG
!IF SET, CONTINUE
!ELSE, GO TO PLOT PHASE ARRAY, C
!CHECK ERROR RUN FLAG
!IF SET, CONTINUE
!ELSE, RETURN TO CONTINUE WITH

```

```

3600                                     ! THE NEXT S PARAMETER
3610      Y=(Rp=1)                       !CHECK ERROR RUN "PRINT/PLOT" FLAG
3620      IF Y THEN GOTO 3590            !IF SET, GO TO RETURN COMMAND
3630      MAT B=M-B                      !SUBTRACT (dB) THE SECOND MAGNITUDE
3640                                     ! SWEEP FROM THE FIRST
3650      MAT C=N-C                     !SUBTRACT (DEGREES) THE SECOND
3660                                     ! PHASE SWEEP FROM THE FIRST
3670      MAT E=C                       !LOAD PHASE ERROR ARRAY, C
3680      GOSUB 12480                   !GO TO CHECK FOR 360 DEGREE SHIFT
3690      MAT C=E                       !RELOAD PHASE ERROR ARRAY, C, WITH
3700                                     ! CORRECTED PHASE ARRAY, E
3710      PRINT "DUAL SWEEP MAGNITUDE ERROR, dB"
3720      WAIT 2000
3730      MAT PRINT B
3740      PRINT "DUAL SWEEP PHASE ERROR, DEGREES"
3750      MAT PRINT C
3760      Rp=1
3770      GOTO 2990
3780      MAT A=C
3790
3800      R=1
3810      GOTO 3430
3820      !
3830      ! THIS SECTION (FROM"DEFINE Df") MEASURES THE HP3577A VALUE FOR EACH
3840      ! DATA POINT (THE NUMBER OF DATA POINTS HAS BEEN CALCULATED FROM THE
3850      ! DEFINED DELTA FREQUENCY)
3860      Re=0
3870
3880      Rp=0
3890
3900      DISP "Please wait. Measurements are being taken."
3910      OUTPUT 711;"ST5;"
3920      Xmin=Cfreq
3930
3940
3950
3960      FOR I=Ii TO N
3970
3980          Cfreq=(I-1)*Df+Xmin
3990
4000          OUTPUT 711 USING 4010;Cfreq
4010          IMAGE "SFR;" ,DDD.DDDDDD,"MHz;"
4020
4030
4040          OUTPUT 711;"TKM;FM1;DM1;"
4050
4060
4070          ENTER 711;B(I)
4080          OUTPUT 711;"TKM;FM1;DM2"
4090
4100
4110          ENTER 711;C(I)
4120      NEXT I
4130      Cfreq=Xmin
4140
4150      MAT D=B
4160
4170      MAT E=C
4180      Y=(S=3)
4190      IF Y THEN GOTO 4240
4200
4210      MAT Q=D-Dn
4220      MAT R=E-En
4230      GOTO 4270
4240      GOSUB 11900
4250
4260
4270      MAT E=R
4280      GOSUB 12480
4290      MAT R=E
4300
4310      Y=(E=1)

```

```

! SET ERROR RUN "PRINT/PLOT" FLAG
! GO TO OFFER PRINT-OUT OF ERRORS
! ELSE, ENTER MAGNITUDE ARRAY, C,
! INTO PLOT ARRAY, A
! SET PLOT "ONCE THROUGH" FLAG
! GO TO PLOT AGAIN

! PRESET ERROR RUN "ONCE
! THROUGH" FLAG
! PRESET ERROR RUN "PRINT/PLOT"
! FLAG

! SWEEP TYPE SET TO CONTINUOUS WAVE
! DEFINES MINIMUM FREQUENCY FOR THE
! LOWER END F THE HORIZONTAL AXIS
! (AND SAVES THE VALUE FOR THE
! START OF THE BANDWIDTH)
! IF SAW DEVICE, LOOP BEGINS WITH
! 2. OTHERWISE, LOOP BEGINS WITH 1
! INCREMENT FREQUENCY BY THE
! DELTA FREQUENCY

! SOURCE FREQUENCY STARTS AT MINIMUM
! VALUE OF THE BAND AND IS
! ACCURATE TO ONE HERTZ
! TAKE MEASUREMENT, PUT IN ASCII
! FORM, AND DUMP THE MAGNITUDE
! MARKER FROM TRACE1
! ENTER DATA INTO MAGNITUDE ARRAY, B
! TAKE MEASUREMENT, PUT IN ASCII
! FORM, AND DUMP THE PHASE
! MARKER FROM TRACE 2
! ENTER DATA INTO THE PHASE ARRAY, C

! RESTORE Cfreq TO IT'S
! DEFINED VALUE
! IN PREPARATION FOR MATH, LOAD
! MAGNITUDE ARRAY, B, INTO ARRAY D
! AND PHASE ARRAY, C, INTO ARRAY E
! CHECK THE S11 FLAG
! IF SET, THE FOLLOWING MATH IS
! NOT NECESSARY
! SUBTRACT (dB) CALIBRATION ARRAY
! SUBTRACT (PHASE) CALIBRATION ARRAY
! GO TO CHECK FOR PHASE SHIFT
! GO TO THE END OF ONE PORT FULL
! CALIBRATION SUBROUTINE TO FIND
! THE CALIBRATED VALUES
! LOAD PHASE ARRAY, R, INTO ARRAY E
! GO TO CHECK FOR 360 DEGREE SHIFT
! RELOAD PHASE ARRAY, R, WITH
! CORRECTED VALUES
! CHECK ERROR RUN FLAG

```



```

4320 IF Y THEN GOTO 4340
4330 GOTO 4420
4340 Y=(Re=0)
4350 IF Y THEN GOTO 4380
4360
4370 GOTO 4420
4380 MAT M=Q
4390 MAT N=R
4400 Re=1
4410 GOTO 3900
4420 MAT B=Q
4430
4440 MAT C=R
4450 PRINT "MAGNITUDE,db:"
4460 MAT PRINT B
4470 PRINT " "
4480 PRINT "PHASE,deg:"
4490 MAT PRINT C
4500 INPUT "Do you want a print-out of these?",X$
4510 IF X$="N" THEN GOTO 4790
4520 IF X$="Y" THEN GOTO 4530
4530 PRINTER IS 0
4540
4550 ! CHECK THE S PARAMETER FLAGS
4560 Y=(S=1)
4570 IF Y THEN PRINT "S21"
4580 Y=(S=2)
4590 IF Y THEN PRINT "S12"
4600 Y=(S=3)
4610 IF Y THEN PRINT "S11"
4620 Y=(S=4)
4630 IF Y THEN PRINT "S22"
4640 Y=(Rp=1)
4650
4660 IF Y THEN PRINT "DUAL SWEEP ERROR"
4670 PRINT "MAGNITUDE,db:"
4680 PRINT " "
4690 MAT PRINT B
4700 PRINT " "
4710 Y=(Rp=1)
4720
4730 IF Y THEN PRINT "DUAL SWEEP ERROR"
4740 PRINT "PHASE,deg:"
4750 PRINT " "
4760 MAT PRINT C
4770 PRINTER IS 16
4780
4790 GOSUB 12610
4800 INPUT "Do you want a normalized plot of these? Y or N then CONT.",X$
4810 IF X$="Y" THEN GOTO 4910
4820 IF X$="N" THEN GOTO 4830
4830 Y=(Rp=1)
4840
4850 IF Y THEN RETURN
4860
4870 Y=(E=0)
4880 IF Y THEN RETURN
4890
4900 GOTO 5120
4910 ! PREPARE TO GO TO PLOTTING SUBROUTINE
4920 R=0
4930
4940 MAT A=B
4950
4960 Xmax=Dfreq
4970
4980 Imin=1
4990
!IF SET, CONTINUE
!ELSE, GO TO LOAD ARRAYS B AND C
!CHECK ERROR RUN "ONCE THROUGH" FLAG
!IF NOT SET, GO TO STORE FIRST
! ERROR SWEEP
!IF SET, CONTINUE
!STORE FIRST MAGNITUDE SWEEP
!STORE FIRST PHASE SWEEP
!SET ERROR RUN "ONCE THROUGH" FLAG
!GO TO TAKE SECOND SWEEP
!MAGNITUDE ARRAY , B, IS NOW
! CALIBRATED
!PHASE ARRAY, C, IS NOW CALIBRATED

!PRINT THE MAGNITUDE ARRAY

!PRINT THE PHASE ARRAY

!REDEFINE THE PRINTER TO PRINT
! OUT ON 9845B PAPER

!CHECK THE ERROR RUN
! "PRINT/PLOT" FLAG

!PRINT MAGNITUDE ARRAY

!CHECK THE ERROR RUN
! "PRINT/PLOT" FLAG

!PRINT PHASE ARRAY
!REDEFINE THE PRINTER TO BE
! THE 9845B SCREEN
!GO TO OFFER TO SAVE RESULTS

!CHECK THE ERROR RUN
! "PRINT/PLOT" FLAG
!IF SET, THEN RETURN TO CONTINUE
! WITH THE NEXT S PARAMETER
!CHECK THE ERROR RUN FLAG
!IF NOT SET, RETURN TO CONTINUE
! WITH THE NEXT S PARAMETER
!ELSE, GO TO FIND ERROR

!PRESET THE PLOT "ONCE
! THROUGH" FLAG TO ZERO
!ENTER MAGNITUDE ARRAY, B,
! INTO PLOT ARRAY, A
!DEFINES MAXIMUM FREQUENCY FOR THE
! UPPER END OF THE HORIZONTAL AXIS
!DEFINES MINIMUM AMPLITUDE FOR THE
! LOWER END OF THE VERTICAL AXIS

```

```

5000   Imax=X                                !DEFINES MAXIMUM AMPLITUDE FOR THE
5010                                     ! UPPER END OF THE VERTICAL AXIS
5020   GOSUB Max_min                         !GO TO Max_min SUBROUTINE TO
5030                                     ! FIND Imax AND Imin
5040   GOSUB Plot                             !GO TO THE Plot SUBROUTINE
5050   Y=(R=1)                               !CHECK THE PLOT "ONCE THROUGH" FLAG
5060   IF Y THEN GOTO 5080                   !IF SET, CONTINUE
5070   GOTO 5300                             !ELSE, GO TO PLOT PHASE ARRAY, C
5080   Y=(E=1)                               !CHECK ERROR RUN FLAG
5090   IF Y THEN GOTO 5120                   !IF SET, GO TO FIND ERROR
5100   RETURN                               !ELSE, RETURN TO CONTINUE WITH
5110                                     ! THE NEXT S PARAMETER
5120   Y=(Rp=1)                             !CHECK ERROR RUN "PRINT/PLOT" FLAG
5130   IF Y THEN GOTO 5100                   !IF SET, THEN RETURN TO CONTINUE
5140                                     ! WITH THE NEXT S PARAMETER
5150   MAT B=M-B                             !SUBTRACT (dB) THE SECOND MAGNITUDE
5160                                     ! SWEEP FROM THE FIRST
5170   MAT C=N-C                             !SUBTRACT (DEGREES) THE SECOND
5180                                     ! PHASE SWEEP FROM THE FIRST
5190   MAT E=C                               !LOAD PHASE ERROR ARRAY, C
5200   GOSUB 12480                           !GO TO CHECK FOR 360 SHIFT
5210   MAT C=E                               !RELOAD PHASE ERROR ARRAY, C, WITH
5220                                     ! CORRECTED PHASE ARRAY,E
5230   PRINT "DUAL SWEEP MAGNITUDE ERROR, dB"
5240   WAIT 2000
5250   MAT PRINT B
5260   PRINT "DUAL SWEEP PHASE ERROR, DEGREES"
5270   MAT PRINT C
5280   Rp=1
5290   GOTO 4500
5300   MAT A=C
5310
5320   R=1
5330   GOTO 4960
5340   RETURN
5350
5360   !
5370   ! CARL BISHOP'S PLOTTING SUBROUTINE ADDED HERE
5380   !
5390   ! BASIC SUBROUTINE PACKAGE, REV. A, 6/16/83
5400   ! UNIVERSITY OF CENTRAL FLORIDA
5410   ! COLLEGE OF ENGINEERING, ELECTRICAL ENGINEERING DEPARTMENT
5420   ! CARLTON BISHOP
5430 Plot: !
5440   X1=(Xmin-Xmax)/2
5450   X$="FREQUENCY, MHZ"
5460   IF ABS(X1)>10 THEN GOTO 5490
5470   X1=X1*1000
5480   X$="FREQUENCY, KHZ"
5490   X2=ABS(X1/5)
5500   Xtic=(Xmax-Xmin)/10
5510   Ytic=(Ymax-Ymin)/10
5520   Delta_x=(Xmax-Xmin)/(Imax-1)
5530   SETGU                                     !Use graphics units to label plot
5540   ! HERE SLD HAS ADDED AN OPTION TO PLOT ON THE 9845B SCREEN OR
5550   ! PLOT ON THE 7475A PLOTTER. CARL'S PROGRAM DEFINES PLOTTER
5560   ! AS "GRAPHICS"
5570   Sa=0                                     !PRESET THE "BOTH FLAG TO ZERO
5580   T=0                                     !PRESET "ONCE THROUGH" FLAG TO ZERO
5590   INPUT "Plot on this screen S, plotter, P, or both, B?",P$
5600   DISP "Press CONT. when each plot is finished."
5610   WAIT 4000
5620   IF P$="S" THEN GOTO 5660
5630   IF P$="P" THEN GOTO 5680
5640   IF P$="B" THEN GOTO 5650
5650   Sa=1
5660   PLOTTER IS "GRAPHICS"
5670   GOTO 5700
5680   PLOTTER IS "9872A"
5690   INPUT "Is there paper in the plotter? Press CONT.",Y
5700   GRAPHICS
5710   LINE TYPE 1

```

!SET THE "BOTH" FLAG  
!Define 9845B as plotting device  
!DEFINE 7475A AS PLOTTING DEVICE  
!Use solid line for plotting



```

5720 LOCATE 18,121.9,14.3,92.7
5730 CLIP 18,121.9,14.3,92.7
5740 PEN 1
5750 FRAME
5760 CSIZE 2.5,.5
5770 MOVE 12.1,11.3
5780 FOR I=1 TO 11
5790 Ti=X2*(I-1)+X1
5800 LABEL USING "SDDDD.D";Ti
5810 IPLOT 10.6,2.5,2
5820 NEXT I
5830 MOVE 6.6,13.9
5840 FOR I=1 TO 11
5850 Ti=Ytic*(I-1)+Ymin
5860 LABEL USING "SDDDD.DD";Ti
5870 IPLOT 0,10.29,2
5880 NEXT I
5890 LDIR 0
5900 LORG 4
5910 MOVE 70.1,7.8
5920 LABEL USING "#,K";X$
5930 MOVE 70.1,2.8
5940 LABEL USING "#,K,DDD.DDDDDD,K";Fo= "(Xmax+Xmin)/2," MHZ"
5950 MOVE 7.5,53.5
5960 LDIR PI/2
5970 Y=(E=1)
5980 IF Y THEN GOTO 6000
5990 GOTO 6090
6000 Y=(Rp=0)
6010 IF Y THEN GOTO 6090
6020 Y=(R=0)
6030 IF Y THEN GOTO 6050
6040 GOTO 6070
6050 Y$="MAG. ERROR, dB"
6060 GOTO 6150
6070 Y$="PHASE ERROR, DEG"
6080 GOTO 6150
6090 Y=(R=0)
6100 IF Y THEN GOTO 6120
6110 GOTO 6140
6120 Y$="MAGNITUDE, dB"
6130 GOTO 6150
6140 Y$="PHASE, DEGREES"
6150 LABEL USING "#,K";Y$
6160 CSIZE 4,.5
6170 MOVE 70.1,96.2
6180 LDIR 0
6190 Y=(S=1)
6200 IF Y THEN H$="S21"
6210 Y=(S=2)
6220 IF Y THEN H$="S12"
6230 Y=(S=3)
6240 IF Y THEN H$="S11"
6250 Y=(S=4)
6260 IF Y THEN H$="S22"
6270 LABEL USING "#,K";H$
6280 SCALE Xmin,Xmax,Ymin,Ymax
6290 SETUU
6300 AXES Xtic,Ytic,Xmin,Ymin
6310 MOVE Xmin,Ymin
6320 FOR I=Imin TO Imax
6330 DRAW Xmin+(I-1)*Delta_x,A(I)
6340 NEXT I
6350 PEN 0
6360 PAUSE
6370 EXIT GRAPHICS
6380 Y=(Sa*T)=1)
6390
6400 IF Y THEN GOTO 6450
6410
6420 T=1
6430 Y=(Sa=1)

```

!Position graph on the paper  
!Use left pen for plotting  
!Draw border of graph  
!Set the size of the characters  
!Pen in position to scale X axis  
  
!Calculate value of tic mark  
!Put it on the graph  
!Position for next tic mark  
  
!Pen in position to scale Y axis  
  
!Calculate value of tic mark  
!Put it on the graph  
!Position for next tic mark  
  
  
!Put pen position to label X axis  
!Label X axis  
  
!Pen in position to label Y axis  
!Label bottom to top  
!CHECK ERROR RUN FLAG  
!IF SET, GO TO CHECK ANOTHER FLAG  
!ELSE, CONTINUE  
  
  
!CHECK PLOT "ONCE THROUGH" FLAG  
  
  
!GO TO LABEL Y AXIS  
!CHECK PLOT "ONCE THROUGH" FLAG  
  
  
  
!Make Heading of the graph larger  
!Position at top to print heading  
!Print it left to right  
!CHECK S21 FLAG  
!IF SET, HEADING = S21  
!CHECK S12 FLAG  
!IF SET, HEADING = S12  
!CHECK S11 FLAG  
!IF SET, HEADING = S11  
!CHECK S22 FLAG  
!IF SET, HEADING = S22  
  
!Set user scale according to data  
!Return to user defined units  
  
!Start plot at first point  
  
  
!CHECK TO SEE IF "BOTH" FLAG AND  
! "ONCE THROUGH" FLAG ARE SET  
!IF SO, RETURN TO MAIN PLOT/PRINT  
! SUBROUTINE  
!SET THE "ONCE THROUGH" FLAG  
!CHECK TO SEE IF "BOTH" FLAG IS SET

```

6440 IF Y THEN GOTO 5680
6450 RETURN
6460 Max_min:
6470 Ymin=1E99
6480 Ymax=-1E99
6490 FOR I=Imin TO Imax
6500 IF A(I)>Ymax THEN Ymax=A(I)
6510 IF A(I)<Ymin THEN Ymin=A(I)
6520 NEXT I
6530 RETURN
6540 !
6550 ! POLAR-TO-REAL-AND-IMAGINARY SUBROUTINE (DEGREES)
6560 ! THIS SUBROUTINE CHANGES POLAR VALUES TO REAL AND IMAGINARY
6570 ! VALUES IN PREPARATION FOR LINEAR MATHEMATICAL OPERATIONS. THE
6580 ! MAGNITUDE COMING IN IS LINEAR. THE PHASE COMING IN IS IN DEGREES.
6590 FOR Z=1 TO N
6600 A=D(Z)
6610 C=E(Z)*PI/180
6620 RAD
6630 F=A*COS(C)
6640
6650 P(Z)=F
6660 G=A*SIN(C)
6670
6680 O(Z)=G
6690 NEXT Z
6700 RETURN
6710 !
6720 ! POLAR-TO-REAL-AND-IMAGINARY SUBROUTINE (RADIAN)
6730 ! THIS SUBROUTINE CHANGES POLAR VALUES TO REAL AND IMAGINARY
6740 ! VALUES IN PREPARATION FOR LINEAR MATHEMATICAL OPERATION. THE
6750 ! MAGNITUDE COMING IN IS IN LOG FORM. THE PHASE COMING IN IS IN RADIAN.
6760 FOR Z=1 TO N
6770 A=10^D(Z)
6780 C=E(Z)
6790 RAD
6800 F=A*COS(C)
6810
6820 P(Z)=F
6830 G=A*SIN(C)
6840
6850 O(Z)=G
6860 NEXT Z
6870 RETURN
6880 !
6890 ! REAL-AND-IMAGINARY-TO-POLAR SUBROUTINE
6900 ! THIS SUBROUTINE CHANGES REAL AND IMAGINARY VALUES TO POLAR (LOG
6910 ! MAGNITUDE VALUES)
6920 FOR Z=1 TO N
6930 A=SQR(P(Z)^2+O(Z)^2)
6940 B=LGT(A)
6950 D(Z)=B
6960 RAD
6970 Y=(O(Z)>=0)
6980 IF Y THEN GOTO 7020
6990 Y=(P(Z)<0)
7000 IF Y THEN GOTO 7060
7010 GOTO 7040
7020 Y=(P(Z)<0)
7030 IF Y THEN GOTO 7060
7040 C=0
7050 GOTO 7070
7060 C=PI
7070 C=C+ATN(O(Z)/P(Z))
7080 E(Z)=C
7090 NEXT Z
7100 RETURN
7110 !
7120 ! DATA ACQUISITION METHOD SUBROUTINE
7130 ! THIS SUBROUTINE ALLOWS THE USER TO CHOOSE WHICH METHOD OF
7140 ! DATA ACQUISITION HE WOULD LIKE
7150 Du=0

```







```

7870                                     ! DATA POINTS
7880 Y=(X>N)                           ! IS THE NEW NUMBER OF DATA
7890                                     ! GREATER THAN OR EQUAL TO THE
7900                                     ! MINIMUM NUMBER OF DATA POINTS?
7910 IF Y THEN 7950                     ! IF SO, CONTINUE
7920 A=A+1                             ! IF NOT, INCREMENT VARIABLE A AND
7930 GOTO 7860                         ! RETURN TO RE-CALCULATE A NEW
7940                                     ! NUMBER OF DATA POINTS
7950 Df=Bw/X                           ! CALCULATE THE NEW (AND SMALLER)
7960                                     ! DELTA FREQUENCY
7970 PRINT "Better yet, you may have a";X,"point file with Df=";Df,"MHz."
7990 DISP "Oh, happy day!!"
8000 WAIT 5000
8010 N=X                               ! REDEFINE N
8020 RETURN
8030 !
8040 ! NORMALIZING SWEEP WITH THRU/OPEN
8050 Y=(S=4)                           ! CHECK FOR S22 FLAG
8060 IF Y THEN GOTO 8100                ! IF SET, CALIBRATE WITH AN "OPEN"
8070 INPUT "Replace DUT with the THRU then press CONT.",Y
8080 DISP "Please wait. Measurements are being taken."
8090 GOTO 8120                         ! SKIP THE NEXT STATEMENTS
8100 INPUT "Replace DUT with the OPEN. Press CONT.",Y
8110 DISP "Please wait. Measurements are being taken."
8120 Y=(Du=1)                          ! CHECK THE "DUMP THE SCREEN" FLAG
8130 IF Y THEN GOTO 8210               ! IF SET, GO TO TAKE CALIBRATION
8140                                     ! MEASUREMENTS
8150 Y=(Nu=1)                          ! ELSE, CHECK "DEFINE N" FLAG
8160 IF Y THEN GOTO 8360               ! IF SET, GO TO TAKE CALIBRATION
8170                                     ! MEASUREMENTS
8180 Y=(Fr=1)                          ! ELSE, CHECK "DEFINE dF" FLAG
8190 IF Y THEN GOTO 8680               ! IF SET, GO TO TAKE CALIBRATION
8200                                     ! MEASUREMENTS
8210 OUTPUT 711;"SM2;TKM;FM1;DT1;"    ! SINGLE SWEEP, TAKE MEASUREMENTS,
8220                                     ! PUT IN ASCII FORM, DUMP TRACE 1
8230 ENTER 711 USING "#,F";Dn(*)      ! ENTER DATA INTO THE CALIBRATION
8240                                     ! MAGNITUDE ARRAY, Dn
8250 OUTPUT 711;"SM2;TKM;FM1;DT2;"    ! SINGLE SWEEP, TAKE MEASUREMENTS,
8260                                     ! PUT IN ASCII FORM, DUMP TRACE 2
8270 ENTER 711 USING "#,F";En(*)      ! ENTER DATA INTO THE CALIBRATION
8280                                     ! PHASE ARRAY, En
8290 Y=(S=4)                           ! IF SET, SKIP THE NEXT STATEMENT
8300 IF Y THEN GOTO 8330
8310 INPUT "Replace the THRU with the DUT. Press CONT.",Y
8320 GOTO 8340
8330 INPUT "Replace the OPEN with the DUT. Press CONT.",Y
8340 RETURN
8350 !
8360 OUTPUT 711;"ST5;"                ! SET SWEEP TYPE TO CONTINUOUS WAVE
8370 Xmin=Afreq                        ! DEFINES MINIMUM FREQUENCY FOR THE
8380                                     ! LOWER END OF THE HORIZONTAL AXIS
8390                                     ! (SAVES THE VALUE OF THE START
8400                                     ! FREQUENCY)
8410 FOR I=1 TO N
8420   OUTPUT 711 USING 8430;Afreq
8430   IMAGE "SFR;","DDD.DDDDDD","MHZ;" ! SOURCE FREQUENCY STARTS AT
8440                                     ! DEFINED START FREQUENCY AND
8450                                     ! IS ACCURATE TO ONE HERTZ
8460   OUTPUT 711;"TKM;FM1;DM1;"      ! TAKE MEASUREMENT, PUT IN ASCII
8470                                     ! FORM, AND DUMP THE MAGNITUDE
8480                                     ! MARKER FROM TRACE 1
8490   ENTER 711;Dn(I)                ! ENTER DATA INTO CALIBRATION
8500                                     ! MAGNITUDE ARRAY, Dn
8510   OUTPUT 711;"TKM;FM1;DM2;"      ! TAKE MEASUREMENT, PUT IN ASCII
8520                                     ! FORM, AND DUMP CALIBRATION PHASE
8530                                     ! MARKER FROM TRACE 2
8540   ENTER 711;En(I)                ! ENTER DATA INTO CALIBRATION
8550                                     ! PHASE ARRAY, En
8560   Afreq=Afreq+Df                  ! INCREMENT FREQUENCY BY THE
8570                                     ! CALCULATED DELTA FREQUENCY
8580 NEXT I
8590 Afreq=Xmin                        ! RESET START FREQUENCY

```



```

8600 Y=(S=4) !CHECK FOR THE S22 FLAG
8610 IF Y THEN GOTO 8640 !IF SET, SKIP THE NEXT STATEMENT
8620 INPUT "Replace the THRU with the DUT. Press CONT.",Y
8630 GOTO 8650 !GO TO RETURN COMMAND
8640 INPUT "Replace the OPEN with the DUT. Press CONT.",Y
8650 RETURN !RETURN TO TAKE MEASUREMENTS
8660 ! FROM THE DEVICE UNDER TEST
8670 !
8680 OUTPUT 711;"ST5;" !SET SWEEP TYPE TO CONTINUOUS WAVE
8690 Xmin=Cfreq !DEFINES MINIMUM FREQUENCY FOR THE
8700 ! LOWER END OF THE HORIZONTAL AXIS
8710 ! (AND SAVES THE VALUE FOR START
8720 ! FREQUENCY OF THE BANDWIDTH)
8730 FOR I=Ii TO N !IF SAW DEVICE, LOOP BEGINS WITH
8740 ! 2. OTHERWISE, LOOP BEGINS WITH 1
8750 Cfreq=(I-1)*Df+Xmin !INCREMENT FREQUENCY BY THE
8760 ! DELTA FREQUENCY
8770 OUTPUT 711 USING 8780;Cfreq
8780 IMAGE "SFR";,DDD.DDDDDD,"MHz;" !SOURCE FREQUENCY STARTS AT MINIMUM
8790 ! VALUE OF THE BANDWIDTH AND IS
8800 ! ACCURATE TO ONE HERTZ
8810 OUTPUT 711;"TKM;FM1;DM1;" !TAKE MEASUREMENT, PUT IN ASCII
8820 ! FORM, AND DUMP THE MAGNITUDE
8830 ! MARKER FOR TRACE 1
8840 ENTER 711;Dn(I) !ENTER DATA INTO CALIBRATION
8850 ! MAGNITUDE ARRAY, Dn
8860 OUTPUT 711;"TKM;FM1;DM2;" !TAKE MEASUREMENT, PUT IN ASCII
8870 ! FORM, AND DUMP THE CALIBRATION
8880 ! PHASE MARKER FOR TRACE 2
8890 ENTER 711;En(I) !ENTER DATA INTO THE CALIBRATION
8900 ! PHASE ARRAY, En
8910 NEXT I
8920 Cfreq=Xmin !RELOAD THE VALUE FOR THE START
8930 ! FREQUENCY INTO Cfreq
8940 Y=(S=4) !CHECK FOR THE S22 FLAG
8950 IF Y THEN GOTO 8980 !IF SET, SKIP THE NEXT STATEMENT
8960 INPUT "Replace the THRU with the DUT. Press CONT.",Y
8970 GOTO 8990
8980 INPUT "Replace the OPEN with the DUT. Press CONT.",Y
8990 RETURN !RETURN TO TAKE MEASUREMENTS FROM
9000 ! THE DEVICE UNDER TEST
9010 !
9020 ! ONE PORT FULL CALIBRATION
9030 INPUT "Replace the DUT with the OPEN. Press CONT.",Y
9040 DISP "Please wait. Measurements are being taken."
9050 Y=(Du=1) !CHECK THE "DUMP THE SCREEN" FLAG
9060 IF Y THEN GOTO 9150 !IF SET, GOTO TAKE CALIBRATION
9070 ! MEASUREMENTS
9080 Y=(Nu=1) !CHECK THE "DEFINE N" FLAG
9090 IF Y THEN GOTO 9560 !IF SET, GOTO TAKE CALIBRATION
9100 ! MEASUREMENTS
9110 Y=(Fr=1) !CHECK THE "DEFINE dF" FLAG
9120 IF Y THEN GOTO 10250 !IF SET, GOTO TAKE CALIBRATION
9130 ! MEASUREMENTS
9140 !
9150 OUTPUT 711;"SM2;TKM;FM1;DT1;" !SINGLE SWEEP, TAKE MEASUREMENT,
9160 ! PUT INTO ASCII FORM, AND DUMP
9170 ! TRACE 1
9180 ENTER 711 USING "#,F";D(*) !ENTER DATA INTO THE MATH
9190 ! MAGNITUDE ARRAY, D
9200 OUTPUT 711;"SM2;TKM;FM1;DT2;" !SINGLE SWEEP, TAKE MEASUREMENT,
9210 ! PUT INTO ASCII FORM, AND DUMP
9220 ! TRACE 2
9230 ENTER 711 USING "#,F";E(*) !ENTER DATA INTO MATH PHASE
9240 ! ARRAY, E
9250 GOSUB 6550 !GOT TO CHANGE TO REAL AND IMAG.
9260 MAT A=P !STORE ARRAY P INTO ARRAY
9270 ! GAMMA(OPEN,REAL)=A
9280 MAT B=O !STORE ARRAY O INTO ARRAY
9290 ! GAMMA(OPEN,IMAGINARY)=B
9300 INPUT "Replace the OPEN with the SHORT. Press CONT.",Y
9310 DISP "Measuring again. . ."

```

```

9320 OUTPUT 711;"SM2;TKM;FM1;DT1;"
9330 ENTER 711 USING "#,F";D(*)
9340 OUTPUT 711;"SM2;TKM;FM1;DT2;"
9350 ENTER 711 USING "#,F";E(*)
9360 GOSUB 6550
9370 MAT C=P
9380
9390 MAT F=0
9400
9410 INPUT "Replace the SHORT with the reference LOAD (50 ohms). Press CONT.",Y
9420 DISP ". . .and again."
9430 OUTPUT 711;"SM2;TKM;FM1;DT1;"
9440 ENTER 711 USING "#,F";D(*)
9450 OUTPUT 711;"SM2;TKM;FM1;DT2;"
9460 ENTER 711 USING "#,F";E(*)
9470 GOSUB 6550
9480 MAT G=P
9490
9500 MAT H=0
9510
9520 GOSUB 10880
9530 RETURN
9540
9550 !
9560 OUTPUT 711;"ST5;"
9570 Xmin=Afreq
9580
9590
9600
9610 FOR I=1 TO N
9620 OUTPUT 711 USING 8430;Afreq
9630 IMAGE "SFR;","DDD.DDDDDD","MHZ;"
9640
9650 OUTPUT 711;"TKM;FM1;DM1;"
9660
9670
9680 ENTER 711;D(I)
9690
9700 OUTPUT 711;"TKM;FM1;DM2;"
9710
9720
9730 ENTER 711;En(I)
9740
9750 Afreq=Afreq+Df
9760
9770 NEXT I
9780 Afreq=Xmin
9790 GOSUB 6550
9790 MAT A=P
9810
9820 MAT B=0
9830
9840 INPUT "Replace the OPEN with the SHORT. Press CONT.",Y
9850 DISP "Measuring again . . ."
9860 Xmin=Afreq
9870 FOR I=1 TO N
9880 OUTPUT 711 USING 9890;Afreq
9890 IMAGE "SFR;","DDD.DDDDDD","MHZ;"
9900 OUTPUT 711;"TKM;FM1;DM1;"
9910 ENTER 711;D(I)
9920 OUTPUT 711;"TKM;FM1;DM2;"
9930 ENTER 711;E(I)
9940 Afreq=Afreq+Df
9950 NEXT I
9960 Afreq=Xmin
9970 GOSUB 6550
9980 MAT C=P
9990

```

!GOTO CHANGE TO REAL AND IMAG.  
!LOAD ARRAY P INTO ARRAY  
! GAMMA(SHORT,REAL)=C  
!LOAD ARRAY O INTO ARRAY  
! GAMMA(SHORT,IMAGINARY)=F  
  
!GOTO CHANGE TO REAL AND IMAG.  
!LOAD ARRAY P INTO ARRAY  
! GAMMA(t,REAL)=G  
!LOAD ARRAY O INTO ARRAY  
! GAMMA(t,IMAGINARY)=H  
!GO TO PERFORM CALCULATIONS  
!RETURN TO TAKE MEASUREMENTS  
! FROM THE DEVICE UNDER TEST  
  
!SET SWEEP TYPE TO CONTINUOUS WAVE  
!DEFINES MINIMUM FREQUENCY FOR THE  
! LOWER END OF THE HORIZONTAL AXIS  
! (SAVES THE VALUE OF THE START  
! FREQUENCY)  
  
!SOURCE FREQUENCY STARTS AT THE  
! DEFINED START FREQUENCY  
!TAKE MEASUREMENTS, PUT INTO ASCII  
! FORM, AND DUMP MAGNITUDE MARKER  
! FROM TRACE 1  
!ENTER DATA INTO MATH MAGNITUDE  
! ARRAY, D  
!TAKE MEASUREMENT, PUT IN ASCII  
! FORM, AND DUMP PHASE MARKER  
! FROM TRACE 2  
!ENTER DATA INTO MATH  
! PHASE ARRAY, E  
!INCREMENT FREQUENCY BY THE  
! CALCULATED DELTA FREQUENCY  
  
!RELOAD START FREQUENCY INTO Afreq  
!GOTO CHANGE TO REAL AND IMAG.  
!STORE ARRAY P INTO ARRAY  
! GAMMA(OPEN,REAL)=A  
!STORE ARRAY O INTO ARRAY  
! GAMMA(OPEN,IMAGINARY)=B  
  
!RELOAD START FREQUENCY INTO Afreq  
!GOTO CHANGE TO REAL AND IMAG.  
!LOAD ARRAY P INTO ARRAY  
! GAMMA(SHORT,REAL)=C



```

10000 MAT F=0
10010 !LOAD ARRAY O INTO ARRAY
10020 ! GAMMA(SHORT,IMAGINARY)=F
10020 INPUT "Replace the SHORT with the reference LOAD (50 ohms). Press CONT.",Y
10030 DISP ". . .and again."
10040 Xmin=Afreq
10050 FOR I=1 TO N
10060 OUTPUT 711 USING 10070;Afreq
10070 IMAGE "SFR;","DDD.DDDDDD","MHZ;"
10080 OUTPUT 711;"TKM;FM1;DM1;"
10090 ENTER 711;D(I)
10100 OUTPUT 711;"TKM;FM1;DM2;"
10110 ENTER 711;E(I)
10120 Afreq=Afreq+Df
10130 !INCREMENT FREQUENCY BY THE
10130 ! CALCULATED DELTA FREQUENCY
10140 NEXT I
10150 Afreq=Xmin
10160 GOSUB 6550
10170 MAT G=P
10180 ! GAMMA(t,REAL)=G
10190 MAT H=O
10200 !LOAD ARRAY O INTO ARRAY
10210 ! GAMMA(t,IMAGINARY)=H
10210 GOSUB 10800
10220 !GO TO PERFORM CALCULATIONS
10220 RETURN
10230 !RETURN TO TAKE MEASUREMENTS FROM
10240 ! THE DEVICE UNDER TEST
10250 OUTPUT 711;"ST5;"
10260 Xmin=Cfreq
10270 !SET SWEEP TYPE TO CONTINUOUS WAVE
10280 !DEFINES MINIMUM FREQUENCY FOR THE
10290 ! LOWER END OF THE HORIZONTAL AXIS
10300 ! (AND SAVES THE VALUE FOR THE
10310 FOR I=1 TO N
10320 OUTPUT 711 USING 10310;Cfreq
10330 IMAGE "SFR;","DDD.DDDDDD","MHZ;"
10340 OUTPUT 711;"TKM;FM1;DM1;"
10350 !SOURCE FREQUENCY STARTS AT MINIMUM
10360 !TAKE MEASUREMENT, PUT INTO ASCII
10370 ! FORM, DUMP THE MAGNITUDE MARKER
10380 ! FROM TRACE 1
10390 ENTER 711;D(I)
10400 !ENTER DATA INTO MATH MAGNITUDE
10410 ! ARRAY, D
10420 OUTPUT 711;"TKM;FM1;DM2;"
10430 !TAKE MEASUREMENT, PUT INTO ASCII
10440 ! FORM, DUMP PHASE MARKER FROM
10450 ! TRACE 2
10460 ENTER 711;E(I)
10470 !ENTER DATA INTO THE MATH PHASE
10480 ! ARRAY, E
10490 Cfreq=Cfreq+Df
10500 !INCREMENT THE FREQUENCY BY THE
10510 ! DEFINED DELTA FREQUENCY
10520 NEXT I
10530 Cfreq=Xmin
10540 GOSUB 6550
10550 MAT A=P
10560 !RELOAD START FREQUENCY INTO Cfreq
10570 !GO TO CHANGE TO REAL AND IMAG.
10580 MAT B=O
10590 !STORE ARRAY P INTO ARRAY
10600 ! GAMMA(OPEN,REAL)=A
10610 !STORE ARRAY O INTO ARRAY
10620 ! GAMMA(OPEN,IMAGINARY)=B
10630 INPUT "Replace the OPEN with the SHORT. Press CONT.",Y
10640 DISP "Measuring again."
10650 Xmin=Cfreq
10660 FOR I=1 TO N
10670 OUTPUT 711 USING 10560;Cfreq
10680 IMAGE "SFR;","DDD.DDDDDD","MHZ;"
10690 OUTPUT 711;"TKM;FM1;DM1;"
10700 ENTER 711;D(I)
10710 OUTPUT 711;"TKM;FM1;DM2;"
10720 ENTER 711;E(I)
10730 Cfreq=Cfreq+Df
10740 NEXT I
10750 Cfreq=Xmin
10760 GOSUB 6550
10770 MAT C=P
10780 !RELOAD START OF BAND INTO Cfreq
10790 !GO TO CHANGE TO REAL AND IMAG.
10800 MAT F=O
10810 !LOAD ARRAY P INTO ARRAY
10820 ! GAMMA(SHORT,REAL)=C
10830 !LOAD ARRAY O INTO ARRAY
10840 ! GAMMA(SHORT,IMAGINARY)=F
10850 INPUT "Replace the SHORT with the reference LOAD (50 ohms). Press CONT.",Y
10860 DISP ". . .and again."
10870 Xmin=Cfreq

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10720 FOR I=1 TO N
10730   OUTPUT 711 USING 10740;Cfreq
10740   IMAGE "SFR;","DDD.DDDDDD","MHz;"
10750   OUTPUT 711;"TKM;FM1;DM1;"
10760   ENTER 711;D(I)
10770   OUTPUT 711;"TKM;FM1;DM2;"
10780   ENTER 711;E(I)
10790   Cfreq=Cfreq+Df
10800 NEXT I
10810 Cfreq=Xmin
10820 GOSUB 6550
10830 MAT G=P
10840
10850 MAT H=O
10860
10870 !
10880 ! FIND Tf (THE CORRECTION FACTOR FOR TRANSMISSION.) IT IS GIVEN
10890 ! BY:  $Tf = (2GsGo - Gt(Gs+Go)) / (Gs - Go)$ 
10900 DISP "Calculating the correction factor for transmission. . ."
10910 !
10920 MAT Dn=C+A
10930 MAT En=F+B
10940 MAT P=G
10950 MAT O=H
10960 GOSUB 6890
10970 MAT G=D
10980 MAT H=E
10990 MAT P=Dn
11000 MAT O=En
11010 GOSUB 6890
11020 MAT Dn=D
11030 MAT En=E
11040 MAT Dn=Dn+G
11050 MAT En=En+H
11060 MAT P=C
11070 MAT O=F
11080 GOSUB 6890
11090 MAT C=D
11100 MAT F=E
11110 MAT P=A
11120 MAT O=B
11130 GOSUB 6890
11140 MAT A=D
11150 MAT B=E
11160 FOR I=1 TO N
11170   P(I)=2
11180   O(I)=0
11190 NEXT I
11200 GOSUB 6890
11210 MAT D=D+C
11220 MAT D=D+A
11230 MAT E=E+F
11240 MAT E=E+B
11250 GOSUB 6720
11260 MAT M=P
11270 MAT N=O
11280 MAT D=Dn
11290 MAT E=En
11300 GOSUB 6720
11310 MAT P=M-P
11320 MAT O=N-O
11330 GOSUB 6890
11340 MAT M=D
11350 MAT N=E
11360 MAT D=A
11370 MAT E=B
11380 GOSUB 6720
11390 MAT A=P
11400 MAT B=O
11410 MAT D=C
11420 MAT E=F
11430 GOSUB 6720

!RELOAD BAND START FREQUENCY
!GOTO CHANGE TO REAL AND IMAG.
!LOAD ARRAY P INTO ARRAY
! GAMMA(t,REAL)=G
!LOAD ARRAY O INTO ARRAY
! GAMMA(t,IMAGINARY)=H

!Gsr+Gor
!Gsi+Goi
!PREPARE Gtr FOR CONVERSION
!PREPARE Gti FOR CONVERSION
!GOTO RECTANGULAR-TO-POLAR SUBR.
!Gt MAG
!Gt PHASE
!PREPARE FOR CONVERSION
!PREPARE FOR CONVERSION
!GOTO RECTANGULAR-TO-POLAR SUBR.
!(Gs+Go) MAG
!(Gs+Go) PHASE
!2ND TERM OF NUMERATOR;LOG. MAG.
!2ND TERM OF NUM.;POLAR PHASE, RAD.
!PREPARE Gsr FOR CONVERSION
!PREPARE Gsi FOR CONVERSION
!GOTO RECTANGULAR-TO-POLAR SUBR.
!Gs MAG.
!Gs PHASE
!PREPARE Gor FOR CONVERSION
!PREPARE Goi FOR CONVERSION
!GOTO RECTANGULAR-TO-POLAR SUBR.
!Go MAG.
!Go PHASE

!DEFINE P ARRAY TO BE 2, RECT.,REAL
!DEFINE O ARRAY TO BE 0, RECT.,IMAG

!GOTO RECTANGULAR-TO-POLAR SUBR.
!2*Gs,LOG. MAG.
!2*Gs*Go,LOG. MAG.
!2*Gs,PHASE,RAD.
!2*Gs*Go,PHASE,RAD.
!GOTO POLAR-TO-RECTANGULAR SUBR.
!FIRST TERM OF NUMERATOR;RECT.REAL
!FIRST TERM OF NUMERATOR;RECT.IMAG.
!PREPARE 2ND TERM OF NUMERATOR
!FOR CONVERSION
!GOTO POLAR-TO-RECTANGULAR SUBR.
!NUMERATOR; RECT. REAL
!NUMERATOR; RECT. IMAG.
!GOTO RECTANGULAR-TO-POLAR SUBR.
!NUMERATOR; POLAR LOG. MAG.
!NUMERATOR; POLAR PHASE RADIANS
!PREPARE Go MAG. FOR CONVERSION
!PREPARE Go PHASE FOR CONVERSION
!GOTO POLAR-TO-RECTANGULAR SUBR.
!Gor
!Goi
!PREPARE Gs MAG. FOR CONVERSION
!PREPARE Gs PHASE FOR CONVERSION
!GOTO POLAR-TO-RECTANGULAR SUBR.

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11440 MAT C=P !Gsr
11450 MAT F=O !Gsi
11460 MAT P=C-A !DENOMINATOR; RECT. REAL
11470 MAT O=F-B !DENOMINATOR; RECT. IMAG.
11480 GOSUB 6890 !GOTO RECTANGULAR-TO-POLAR SUBR.
11490 MAT M=M-D !Tf IN POLAR FORM; LOG. MAGNITUDE
11500 MAT N=N-E !Tf IN POLAR FORM; PHASE (RADIAN)S
11510 !
11520 ! FIND Sf (FACTOR FOR SOURCE MATCH.) IT IS GIVEN
11530 ! BY: Sf=(2Gt-Gs-Go)/(Gs-Go)
11540 DISP "Calculating the factor for source match. . ."
11550 FOR I=1 TO M
11560 P(I)=2 !DEFINE P ARRAY = 2,RECT.REAL
11570 O(I)=0 !DEFINE O ARRAY = 0,RECT.IMAG.
11580 NEXT I
11590 GOSUB 6890 !GOTO RECTANGULAR-TO-POLAR SUBR.
11600 MAT D=D+G !PREPARE 2*Gt MAG FOR CONVERSION
11610 MAT E=E+H !PREPARE 2*Gi PHASE FOR CONVERSION
11620 GOSUB 6720 !GOTO POLAR-TO-RECTANGULAR SUBR.
11630 MAT G=P !2*Gtr
11640 MAT H=O !2*Gti
11650 MAT Q=C+A !Gs+Go;RECT.REAL
11660 MAT R=F+B !Gs+Go;RECT.IMAG.
11670 MAT Dn=G !2*Gtr
11680 MAT En=H !2*Gti
11690 MAT P=Dn-Q !NUMERATOR;RECT. REAL
11700 MAT O=En-R !NUMERATOR;RECT. IMAG.
11710 GOSUB 6890 !GOTO RECTANGULAR-TO-POLAR
11720 MAT Dn=D !NUMERATOR;POLAR LOG. MAG.
11730 MAT En=E !NUMERATOR;POLAR PHASE,RADIANS
11740 MAT Q=C-A
11750 MAT R=F-B
11760 MAT P=Q !PREPARE DENOMINATOR FOR CONVERSION
11770 MAT O=R !PREPARE DENOMINATOR FOR CONVERSION
11780 GOSUB 6890 !GOTO RECTANGULAR-TO-POLAR SUBR.
11790 MAT Q=Dn-D !Sf;POLAR,LOG. MAGNITUDE
11800 MAT R=En-E !Sf;POLAR,PHASE,RADIANS
11810 MAT Dn=M !Tf;POLAR,LOG. MAGNITUDE
11820 MAT En=N !Tf;POLAR,PHASE,RADIANS
11830 !
11840 ! NOTE: THE CORRECTION FACTOR FOR DIRECTIVITY IS GIVEN BY Gt
11850 !
11860 INPUT "Now replace the DUT. Press CONT.",Y
11870 RETURN !RETURN TO TAKE MEASUREMENTS
11880 ! FROM THE DEVICE UNDER TEST
11890 !
11900 ! THE FOLLOWING SECTION FINDS THE CORRECTED MEASUREMENT. IT IS GIVEN
11910 ! BY S11=(Mmeas-D)/(Sf*Mmeas+Tf)
11920 DISP "Calculating the corrected measurement for S11. . ."
11930 Y=(Re=1) !CHECK ERROR RUN ONCE THROUGH FLAG
11940 IF Y THEN GOTO 11960 !IF SET, GOTO RELOAD Sf
11950 GOTO 11980 !ELSE, CONTINUE
11960 MAT Q=P !RELOAD Sf INTO ARRAYS
11970 MAT R=O !Q AND R
11980 ! Mmeas=D and E in polar form at this point
11990 GOSUB 6550 !GOTO POLAR-TO-RECTANGULAR SUBR.
12000 MAT A=P !Mmeas;RECT.,REAL
12010 MAT B=O !Mmeas;RECT.,IMAG.
12020 Y=(Re=1) !CHECK ERROR RUN ONCE THROUGH FLAG
12030 IF Y THEN GOTO 12080 !IF SET, SKIP NEXT MATH STEP
12040 FOR I=1 TO N
12050 G(I)=.5*G(I) !.5*2*Gtr = Gtr
12060 H(I)=.5*H(I) !.5*2*Gti = Gti
12070 NEXT I
12080 MAT P=A-G !NUMERATOR; RECT.REAL
12090 MAT O=B-H !NUMERATOR; RECT.IMAG.
12100 GOSUB 6890 !GOTO RECTANGULAR-TO-POLAR SUBR.
12110 MAT C=D !NUMERATOR; POLAR, LOG. MAG.
12120 MAT F=E !NUMERATOR; POLAR, PHASE, RADIAN)S
12130 MAT P=A !PREPARE Mmeas FOR CONVERSION
12140 MAT O=B !PREPARE Mmeas FOR CONVERSION
12150 GOSUB 6890 !GOTO RECTANGULAR-TO-POLAR SUBR.

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12160 MAT A=D
12170 MAT B=E
12180 MAT D=Q+A
12190 MAT E=R+B
12200 GOSUB 6720
12210 MAT A=P
12220 MAT B=O
12230 MAT D=Dn
12240 MAT E=En
12250 GOSUB 6720
12260 MAT P=P+A
12270 MAT O=O+B
12280 GOSUB 6890
12290 MAT C=C-D
12300 MAT F=F-E
12310 FOR Z=1 TO N
12320   A=180/PI
12330   F(Z)=F(Z)*A
12340   C(Z)=20*C(Z)
12350 NEXT Z
12360 Y=(E=1)
12370 IF Y THEN GOTO 12390
12380 GOTO 12440
12390 Y=(Re=0)
12400 IF Y THEN GOTO 12420
12410 GOTO 12440
12420 MAT P=Q
12430 MAT O=R
12440 MAT Q=C
12450 MAT R=F
12460 RETURN
12470 !
12480 ! CHECK FOR 360 DEGREE PHASE SHIFT AND CENTER
12490 FOR I=1 TO N
12500   Y=(E(I)<180)
12510   IF Y THEN GOTO 12540
12520   E(I)=E(I)-360
12530   GOTO 12500
12540   Y=(E(I)>180)
12550   IF Y THEN GOTO 12580
12560   E(I)=E(I)+360
12570   GOTO 12540
12580 NEXT I
12590 RETURN
12600 !
12610 ! THIS SUBROUTINE WRITES THE RESULTS TO THE HARD DISK
12620 ! FOR FUTURE FAST FOURIER TRANSFORM
12630 INPUT "Would you like to save these results?",X$
12640 IF X$="Y" THEN GOTO 12660
12650 IF X$="N" THEN GOTO 12840
12660 INPUT "Enter filename.",N$
12670 FOR I=1 TO N-1
12680   Offset=0
12690   IF C(I+1)>C(I) THEN Offset=360
12700   D(I)=-1*(C(I+1)-C(I)-Offset)/(Df*360)
12710 NEXT I
12720 Dmin=Df/2
12730 Dmax=(N-2)*Df+Dmin
12740 ASSIGN #1 TO N$&"F:A6",File
12750 IF File=0 THEN GOTO 12780
12760 CREATE N$&"F:A6",33,2048
12770 ASSIGN #1 TO N$&"F:A6"
12780 PRINT #1;N,B(*),C(*),Dfreq,1
12790
12800
12810 PRINT #1;D(*),Dmin,Dmax
12820
12830 ASSIGN #1 TO *
12840 RETURN

!Mmeas; POLAR, LOG. MAG.
!Mmeas; POLAR, PHASE, RADIANS
!Sf*Mmeas; POLAR, LOG. MAG.
!Sf*Mmeas; POLAR, PHASE, RADIANS
!GOTO POLAR-TO-RECTANGULAR SUBR.
!Sf*Mmeas;RECT.REAL
!Sf*Mmeas;RECT IMAG.
!PREPARE Tf FOR CONVERSION
!PREPARE Tf FOR CONVERSION
!GOTO POLAR-TO-RECTANGULAR
! +Tf (RECT.REAL)
! +Tf (RECT.IMAG.)
!GOTO RECTANGULAR-TO-POLAR SUBR.
!S11; POLAR, LOG. MAG.
!S11; POLAR, PHASE, RADIANS

!S11;POLAR,PHASE,DEGREES
!S11;POLAR,MAG.,dB

!CHECK THE ERROR RUN FLAG
!IF SET, GO TO CHECK ANOTHER FLAG
!ELSE, CONTINUE
!CHECK ERROR RUN ONCE THROUGH FLAG
!IF SET, GOTO STORE Sf
!ELSE, CONTINUE
!STORE Sf DURING SECOND SWEEP
!STORE Sf DURING SECOND SWEEP
!S11
!S11

!THIS SECTION CALCULATES THE
!GROUP DELAY

!MINIMUM GROUP DELAY
!MAXIMUM GROUP DELAY
!ATTEMPT TO OPEN FILE
!CHECK FOR FILE EXISTENCE
!CREATE FILE, IF NONEXISTENT
!OPEN, AFTER CREATING FILE
!PRINT NUMBER OF POINTS,MAGNITUDE,
! PHASE,HIGHEST FREQUENCY,
! AVERAGING FACTOR
!PRINT GROUP DELAY, MINIMUM AND
! MAXIMUM GROUP DELAY
!CLOSE THE FILE
!RETURN TO PROGRAM

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## VITA

Sallie Layton Douglas received her A.D.N. from Greenville Technical College, Greenville, S.C. in 1976 and her B.S.E. with an option in electrical engineering from the University of Central Florida in 1985.

She spent 1976-1982 as a Registered Nurse in surgery at Greenville General Hospital. While there she was promoted to Senior Nurse with a specialty in Neurosurgery.

In 1982, Ms. Douglas returned to her hometown of Orlando, Fl. to begin her studies in engineering. She has continued her nursing career on a part time basis in surgery at Orlando Regional Medical Center. She worked as a student assistant for the Mechanical Engineering Department in 1983-84 and was awarded the Florida Engineering Society scholarship for UCF in 1984. In 1985-86 she was employed by Martin Marietta Orlando Aerospace as a research and development technician in simulation. She is now on an Ed. L.O.A. from Martin Marietta.

Ms. Douglas began her thesis research in 1986. She completed her Masters Degree with an option in electrical engineering in 1987 and wishes to pursue a career in which she can use her medical background along with her engineering degree.

Ms. Douglas is a member of Tau Beta Pi (Service Award, '85), Eta Kappa Nu (Secr., '85-87), IEEE, Mensa, Cousteau Society, Rosalind Club, and Republican National Committee. She was listed in 1987's Who's Who Among Students and is an Usher, Youth Ministry Counselor, and Senior Minister Research Assistant at the First Presbyterian Church, Orlando, Fl.